RENESAS

Specifications in this document are tentative and subject to change.

RL78/G1A RENESAS MCU

R01DS0151EJ0230 Rev.2.30 Apr 26, 2024

Combines Multi-channel 12-Bit A/D Converter, True Low Power Platform (as low as 66 μ A/MHz, and 0.57 μ A for RTC + LVD), 1.6 V to 3.6 V operation, 16 to 64 Kbyte Flash, 41 DMIPS at 32 MHz

1. OUTLINE

1.1 Features

Ultra-Low Power Technology

- 1.6 V to 3.6 V operation from a single supply
- Stop (RAM retained): 0.23 μ A, (LVD enabled): 0.31 μ A
- Halt (RTC + LVD): 0.57 μA
- Snooze: 0.7 mA (UART), 0.6 mA (ADC)
- Operating: 66 µA/MHz

16-bit RL78 CPU Core

- Delivers 41 DMIPS at maximum operating frequency of 32 MHz
- Instruction Execution: 86% of instructions can be executed in 1 to 2 clock cycles
- CISC Architecture (Harvard) with 3-stage pipeline
- Multiply Signed & Unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

Code Flash Memory

- Density: 16 KB to 64 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing
- Self-programming with secure boot swap function and flash shield window function

Data Flash Memory

- Data Flash with background operation
- Data flash size: 4 KB
- Erase Cycles: 1 Million (typ.)
- Erase/programming voltage: 1.8 V to 3.6 V

RAM

- 2 KB to 4 KB size options
- Supports operands or instructions
- Back-up retention in all modes

High-speed On-chip Oscillator

- 32 MHz with +/- 1% accuracy over voltage (1.8 V to 3.6 V) and temperature (-20 °C to +85 °C)
- Pre-configured settings: 32 MHz, 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz, and 1 MHz

Reset and Supply Management

- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 12 setting options (Interrupt and/or reset function)

Data Memory Access (DMA) Controller

- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

Multiple Communication Interfaces

- Up to 6 x I²C master
- Up to 1 x I²C multi-master
- Up to 6 x Simplified SPI (CSINote)/SPI (7-, 8-bit)
- Up to 3 x UART (7-, 8-, 9-bit)
- Up to 1 x LIN

Extended-Function Timers

- Multi-function 16-bit timers: Up to 8 channels
- Real-time clock (RTC): 1 channel (full calendar and alarm function with watch correction function)
- Interval Timer: 12-bit, 1 channel
- 15 kHz watchdog timer: 1 channel (window function)

Rich Analog

- ADC: Up to 28 channels, 12-bit resolution, 3.375 $\mu \rm s$ conversion time
- Supports 1.6 V
- Internal voltage reference (1.45 V)
- On-chip temperature sensor

Safety Features (IEC or UL 60730 compliance)

- Flash memory CRC calculation
- RAM parity error check
- RAM write protection
- SFR write protection
- Illegal memory access detection
- Clock stop/ frequency detection
- ADC self-test

General Purpose I/O

- 3.6 V tolerant, high-current (up to 20 mA per pin)
- Open-Drain, Internal Pull-up support

Operating Ambient Temperature

- Standard: -40 °C to +85 °C
- Extended: -40 °C to +105 °C

Package Type and Pin Count

From 3 mm x 3 mm to 10 mm x 10 mm QFP: 48, 64 QFN: 32, 48 LGA: 25 BGA: 64

Note Although the CSI function is generally called SPI, it is also called CSI in this product, so it is referred to as such in this manual.



Datasheet

O ROM, RAM capacities

Flash ROM	Data flash	RAM	RL78/G1A				
			25 pins	32 pins	48 pins	64 pins	
64 KB	4 KB	4 KB ^{Note}	R5F10E8E	R5F10EBE	R5F10EGE	R5F10ELE	
48 KB	4 KB	3 KB	R5F10E8D	R5F10EBD	R5F10EGD	R5F10ELD	
32 KB	4 KB	2 KB	R5F10E8C	R5F10EBC	R5F10EGC	R5F10ELC	
16 KB	4 KB	2 KB	R5F10E8A	R5F10EBA	R5F10EGA	-	

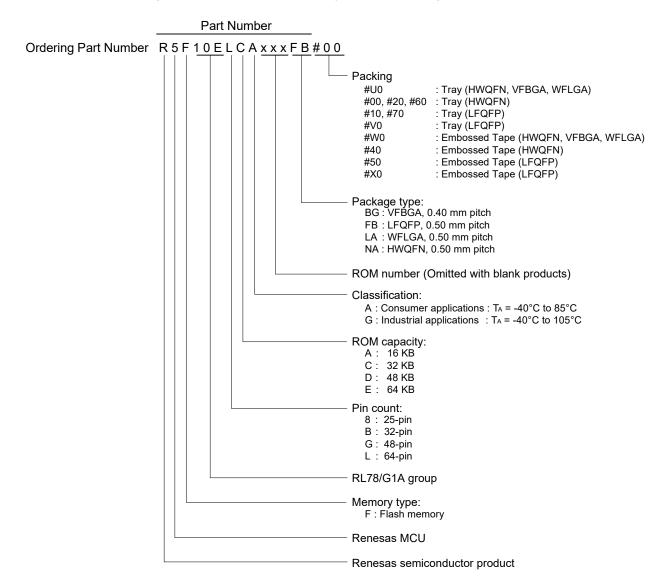
Note This is about 3 KB when the self-programming function and data flash function are used. (For details, see 3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS $T_A = -40$ to $+105^{\circ}$ C))



1.2 List of Part Numbers

<R>

Figure 1-1. Part Number, Memory Size, and Package of RL78/G1A



Caution The part number above is valid as of when this manual was issued. For the latest part number, see the web page of the target product on the Renesas Electronics website.



		Fields of	Ordering Part Number	er		
Pin count	Package	Application Note	Part Number	Packaging specification	RENESAS Code	
25 pins	25-pin plastic WFLGA $(3 \times 3 \text{ mm}, 0.5 \text{ mm} \text{ pitch})$	A	R5F10E8AALA, R5F10E8CALA, R5F10E8DALA, R5F10E8EALA	#U0, #W0	PWLG0025KA-A	
		G	R5F10E8AGLA, R5F10E8CGLA, R5F10E8DGLA, R5F10E8EGLA			
32 pins	32-pin plastic HWQFN (5 × 5 mm, 0.5 mm pitch)	A	R5F10EBAANA, R5F10EBCANA, R5F10EBDANA, R5F10EBEANA	#U0, #W0	PWQN0032KB-A	
				#00, #20, #40, #60	PWQN0032KE-A PWQN0032KG-A	
		G	R5F10EBAGNA, R5F10EBCGNA, R5F10EBDGNA, R5F10EBEGNA	#U0, #W0	PWQN0032KB-A	
				#00, #20, #40, #60	PWQN0032KE-A PWQN0032KG-A	
48 pins	48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)	A	R5F10EGAAFB, R5F10EGCAFB, R5F10EGDAFB, R5F10EGEAFB	#V0, #X0, #10, #50, #70	PLQP0048KF-A	
		G	R5F10EGAGFB, R5F10EGCGFB, R5F10EGDGFB, R5F10EGEGFB	#V0, #X0, #10, #50, #70	PLQP0048KF-A	
	48-pin plastic HWQFN $(7 \times 7 \text{ mm}, 0.5 \text{ mm} \text{ pitch})$	A	R5F10EGAANA, R5F10EGCANA, R5F10EGDANA, R5F10EGEANA	#U0, #W0	PWQN0048KB-A	
				#00, #20, #40, #60	PWQN0048KE-A PWQN0048KG-A	
		G	R5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNA	#U0, #W0	PWQN0048KB-A	
				#00, #20, #40, #60	PWQN0048KE-A PWQN0048KG-A	
64 pins	64-pin plastic LFQFP (10 \times 10 mm, 0.5 mm	A	R5F10ELCAFB, R5F10ELDAFB, R5F10ELEAFB	#V0, #X0, #10, #50, #70	PLQP0064KF-A	
	pitch)	G	R5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB	#V0, #X0, #10, #50, #70	PLQP0064KF-A	
	64-pin plastic VFBGA (4 × 4 mm, 0.4 mm pitch)	A	R5F10ELCABG, R5F10ELDABG, R5F10ELEABG	#U0, #W0	PVBG0064LA-A	
		G	R5F10ELCGBG, R5F10ELDGBG, R5F10ELEGBG			

Table 1-1.	List of Ordering Part Numbers
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Note For the fields of application, see Figure 1-1 Part Number, Memory Size, and Package of RL78/G1A.

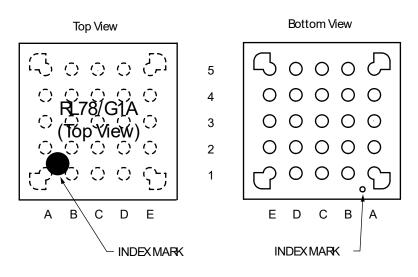
Caution The part number above is valid as of when this manual was issued. For the latest part number, see the web page of the target product on the Renesas Electronics website.



1.3 Pin Configuration (Top View)

1.3.1 25-pin products

• 25-pin plastic WFLGA (3 × 3 mm, 0.50 mm pitch)



	А	В	С	D	E	_
5	P40/TOOL0	RESET	P03/ANI16/ RxD1/TO00/ (KR1)	P23/ANI3/ (KR3)	AVss	5
4	P122/X2/ EXCLK	P137/INTP0	P02/ANI17/ TxD1/TI00/ (KR0)	P22/ANI2/ (KR2)	AVdd	4
3	P121/X1	Vdd	P21/ANI1/ AVrefm	P11/ANI20/ SI00/SDA00/ RxD0/ TOOLRxD	P10/ANI18/ SCK00/SCL00	3
2	REGC	Vss	P30/ANI27/ SCK11/SCL11/ INTP3	P51/ANI25/ SO11/INTP2	P50/ANI26/ SI11/SDA11 INTP1	2
1	P60/SCLA0	P61/SDAA0	P31/ANI29/TI03/ TO03/PCLBUZ0 /INTP4	P12/ANI21/ SO00/TxD0/ TOOLTxD	P20/ANI0/ AV _{REFP}	1
	А	В	С	D	E	•

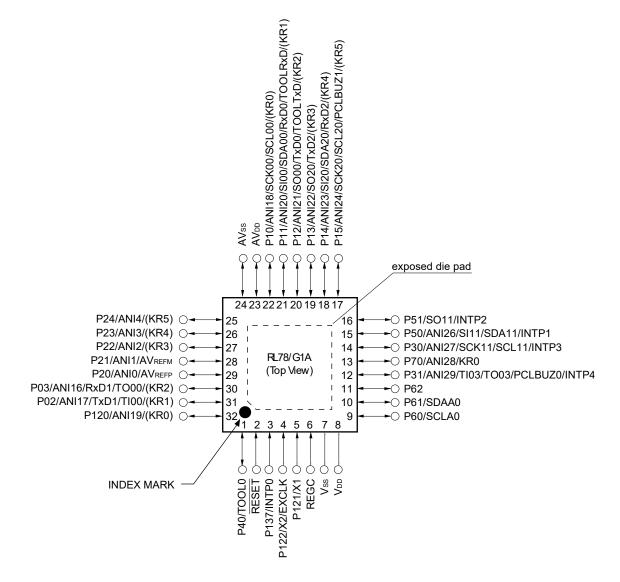
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

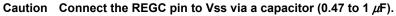
Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.3.2 32-pin products

• 32-pin plastic HWQFN (5 × 5 mm, 0.5 mm pitch)



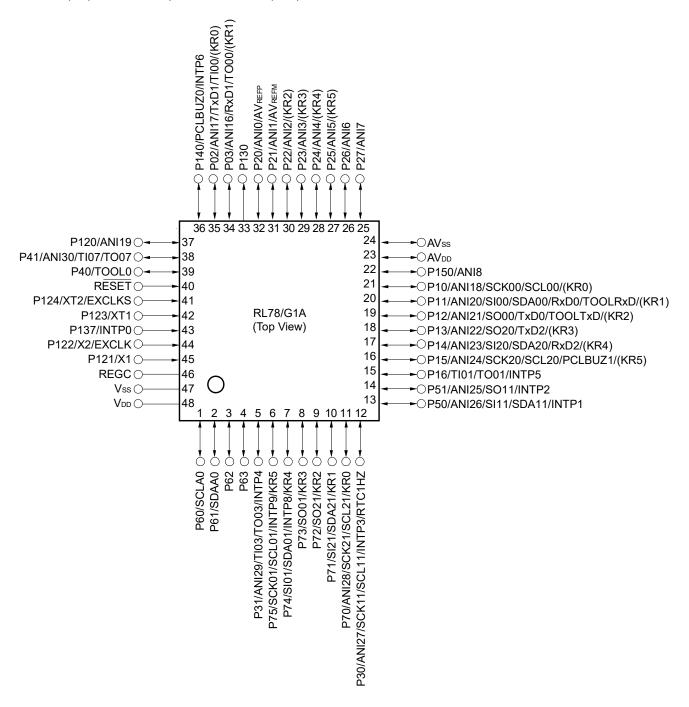


Remarks 1. For pin identification, see 1.4 Pin Identification.

- **2.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).
- 3. It is recommended to connect an exposed die pad to $V_{\text{ss.}}$

1.3.3 48-pin products

• 48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)



Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



P03/ANI16/RxD1/T000/(KR1 P02/ANI17/TxD1/TI00/(KR0) P140/PCLBUZ0/INTP6 P20/ANI0/AVREFF P21/ANI1/AVREFM P22/ANI2/(KR2) P23/ANI3/(KR3) P25/ANI5/(KR5) P24/ANI4/(KR4) P26/ANI6 P27/ANI7 P130 Ç ç ç Ç Ç Q Q 36 35 34 33 32 31 30 29 28 27 26 25 24 P120/ANI19 O-37 -OAVss 23 P41/ANI30/TI07/TO07 O-38 22 P40/TOOL0 O-39 -OP150/ANI8 21 RESET 40 -OP10/ANI18/SCK00/SCL00/(KR0) 20 P124/XT2/EXCLKS 41 -OP11/ANI20/SI00/SDA00/RxD0/TOOLRxD/(KR1) **RL78/G1A** 19 P123/XT1 42 P12/ANI21/SO00/TxD0/TOOLTxD/(KR2) (Top View) 18 P137/INTP0 43 P13/ANI22/SO20/TxD2/(KR3) 17 P122/X2/EXCLK 44 P14/ANI23/SI20/SDA20/RxD2/(KR4) 16 P121/X1 ()-45 -OP15/ANI24/SCK20/SCL20/PCLBUZ1/(KR5) 15 REGC 46 -OP16/TI01/TO01/INTP5 14 47 Vss 🔿-OP51/ANI25/SO11/INTP2 13 VDD O-48 P50/ANI26/SI11/SDA11/INTP1 2 9 10 11 12 3 4 5 6 7 8 1 \diamond \bigcirc P60/SCLA0 --Ċ 6 6 P75/SCK01/SCL01/INTP9/KR5 Oç 0 6 6 P62 P63 P61/SDAA0 P31/ANI29/TI03/T003/INTP4 P74/SI01/SDA01/INTP8/KR4 P73/SO01/KR3 P72/S021/KR2 P70/ANI28/SCK21/SCL21/KR0 P71/SI21/SDA21/KR1 P30/ANI27/SCK11/SCL11/INTP3/RTC1HZ

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 $\mu\mathrm{F}).$

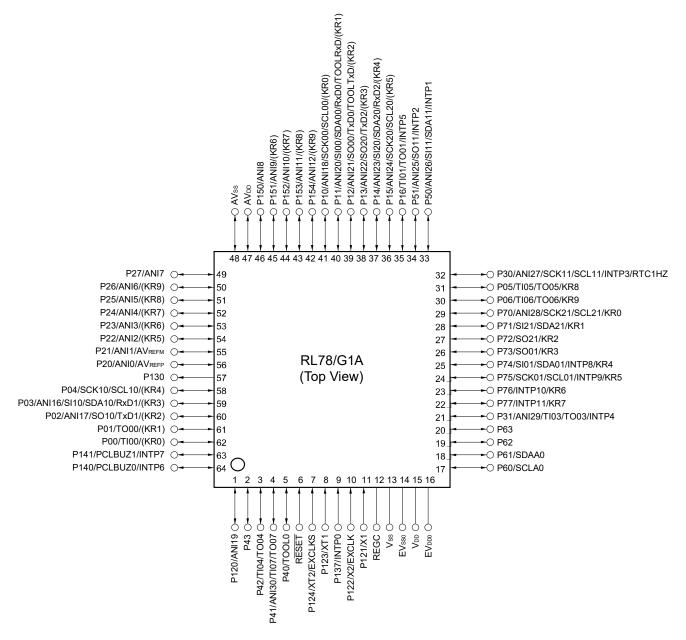
Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



1.3.4 64-pin products

• 64-pin plastic LFQFP (10×10 mm, 0.5 mm pitch)



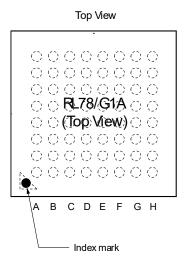
Cautions 1. Make EVsso pin the same potential as Vss pin.

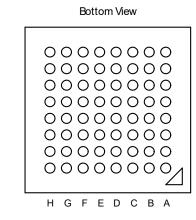
- 2. Make VDD pin the potential that is higher than EVDD0 pin.
- 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

- 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD0} pins and connect the Vss and EVss0pins to separate ground lines.
- **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

• 64-pin plastic VFBGA (4 × 4 mm, 0.4 mm pitch)





Pin No.	Name	Pin No.	Name	Pin No.	Name	Pin No.	Name
A1	P05/TI05/TO05/KR8	C1	P51/ANI25/SO11 /INTP2	E1	P153/ANI11/(KR8)	G1	AVdd
A2	P30/ANI27/SCK11 /SCL11/INTP3 /RTC1HZ	C2	P71/SI21/SDA21/KR1	E2	P154/ANI12/(KR9)	G2	P25/ANI5/(KR8)
A3	P70/ANI28/SCK21 /SCL21/KR0	C3	P74/SI01/SDA01 /INTP8/KR4	E3	P10/ANI18/SCK00 /SCL00/(KR0)	G3	P24/ANI4/(KR7)
A4	P75/SCK01/SCL01 /INTP9/KR5	C4	P16/TI01/TO01/INTP5	E4	P11/ANI20/SI00 /SDA00/RxD0 /TOOLRxD/(KR1)	G4	P22/ANI2/(KR5)
A5	P77/INTP11/KR7	C5	P15/ANI24/SCK20 /SCL20/(KR5)	E5	P03/ANI16/SI10 /SDA10/RxD1/(KR3)	G5	P130
A6	P61/SDAA0	C6	P63	E6	P41/ANI30/TI07/TO07	G6	P02/ANI17/SO10/TxD1 /(KR2)
A7	P60/SCLA0	C7	Vss	E7	RESET	G7	P00/TI00/(KR0)
A8	EVDD0	C8	P121/X1	E8	P137/INTP0	G8	P124/XT2/EXCLKS
B1	P50/ANI26 /SI11 /SDA11/INTP1	D1	P13/ANI22/SO20 /TxD2/(KR3)	F1	P150/ANI8	H1	AVss
B2	P72/SO21/KR2	D2	P06/TI06/TO06/KR9	F2	P151/ANI9/(KR6)	H2	P27/ANI7
B3	P73/SO01/KR3	D3	P12/ANI21/SO00 /TxD0/TOOLTxD/(KR2)	F3	P152/ANI10/(KR7)	H3	P26/ANI6/(KR9)
B4	P76/INTP10/KR6	D4	P14/ANI23/SI20/ SDA20/RxD2/(KR4)	F4	P21/ANI1/AVREFM	H4	P23/ANI3/(KR6)
B5	P31/ANI29/TI03/TO03 /INTP4	D5	P42/TI04/TO04	F5	P04/SCK10/SCL10 /(KR4)	H5	P20/ANI0/AVREFP
B6	P62	D6	P40/TOOL0	F6	P43	H6	P141/PCLBUZ1/INTP7
B7	Vdd	D7	REGC	F7	P01/TO00/(KR1)	H7	P140/PCLBUZ0/INTP6
B8	EVsso	D8	P122/X2/EXCLK	F8	P123/XT1	H8	P120/ANI19

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Cautions 1. Make EVsso pin the same potential as Vss pin.

- 2. Make VDD pin the potential that is higher than EVDD0 pin.
- 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

- 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD0} pins and connect the Vss and EV_{ss0} pins to separate ground lines.
- **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

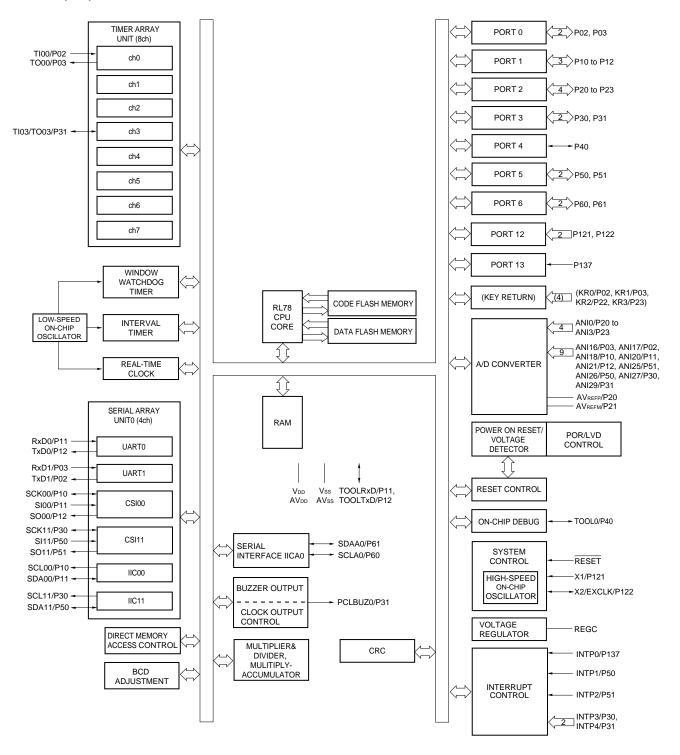
1.4 Pin Identification

ANI0 to ANI12,		PCLBUZ0, PCLBUZ1:	Programmable clock output/buzzer
ANI16 to ANI30:	Analog input		output
AVDD:	Analog power supply	REGC:	Regulator capacitance
AVss:	Analog ground	RESET:	Reset
AVREFM:	A/D converter reference	RTC1HZ:	Real-time clock correction clock
	potential (– side) input		(1 Hz) output
AVREFP:	A/D converter reference	RxD0 to RxD2:	Receive data
	potential (+ side) input	SCK00, SCK01, SCK10,	
EVDD0:	Power supply for port	SCK11, SCK20, SCK21:	Serial clock input/output
EVsso:	Ground for port	SCLA0, SCL00, SCL01,	
EXCLK:	External clock input (main	SCL10, SCL11, SCL20,	
	system clock)	SCL21:	Serial clock output
EXCLKS:	External clock input	SDAA0, SDA00, SDA01,	
	(subsystem clock)	SDA10, SDA11, SDA20,	
INTP0 to INTP11:	Interrupt Request from	SDA21:	Serial data input/output
	External	SI00, SI01, SI10, SI11,	
KR0 to KR9:	Key return	SI20, SI21:	Serial data input
P00 to P06:	Port 0	SO00, SO01, SO10,	
P10 to P16:	Port 1	SO11, SO20, SO21:	Serial data output
P20 to P27:	Port 2	TI00, TI01, TI03 to TI07:	Timer input
P30, P31:	Port 3	TO00, TO01,	
P40 to P43:	Port 4	TO03 to TO07:	Timer output
P50, P51:	Port 5	TOOL0:	Data input/output for tool
P60 to P63:	Port 6	TOOLRxD, TOOLTxD:	Data input/output for external device
P70 to P77:	Port 7	TxD0 to TxD2:	Transmit data
P120 to P124:	Port 12	Vdd:	Power supply
P130, P137:	Port 13	Vss:	Ground
P140, P141:	Port 14	X1, X2:	Crystal oscillator (main system clock)
P150 to P154:	Port 15	XT1, XT2:	Crystal oscillator (subsystem clock)



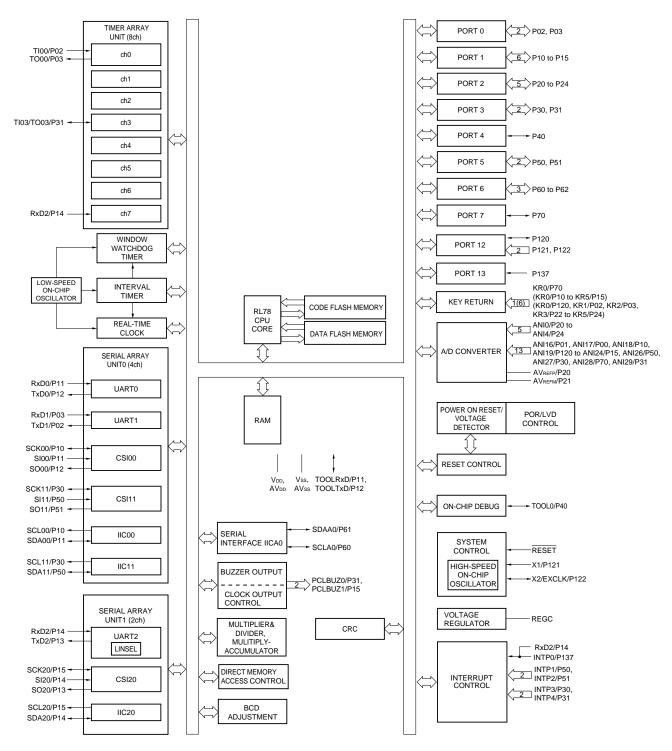
1.5 Block Diagram

1.5.1 25-pin products



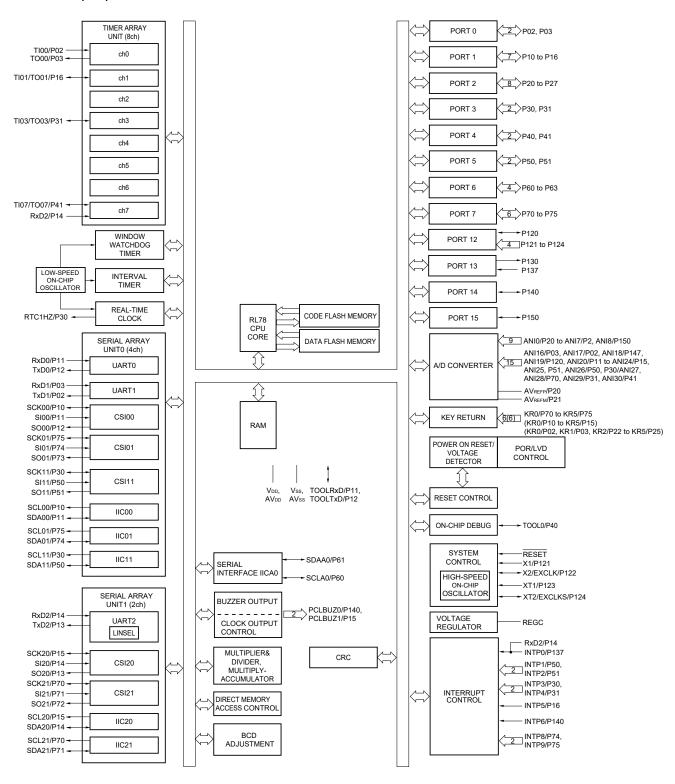
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.2 32-pin products



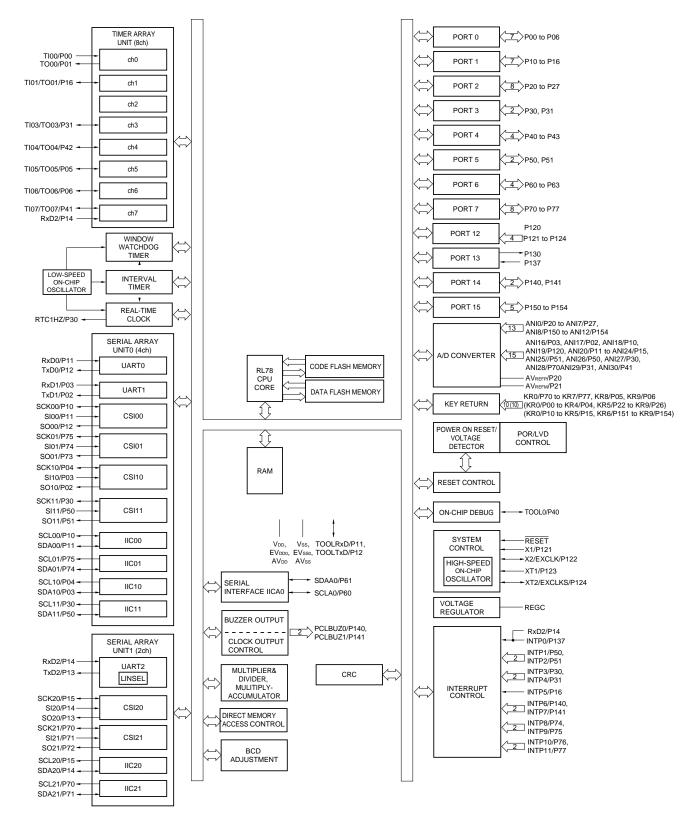
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.3 48-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.4 64-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.6 Outline of Functions

					(1/2)				
	Item	25-pin	32-pin	48-pin	64-pin				
		R5F10E8x	R5F10EBx	R5F10EGx	R5F10ELx				
Code flash memory (KB)		16 to 64	16 to 64	16 to 64	32 to 64				
Data flash me	emory (KB)	4	4	4	4				
RAM (KB)		2 to 4 ^{Note1}	2 to 4 ^{Note1}	2 to 4 ^{Note1}	2 to 4 ^{Note1}				
Address space	e	1 MB		•					
Main system clock	High-speed system clock High-speed on-chip oscillator	HS (High-speed main) n HS (High-speed main) n LS (Low-speed main) m LV (Low-voltage main) n	node: 1 to 20 MHz (V_{DD} = node: 1 to 16 MHz (V_{DD} = ode: 1 to 8 MHz (V_{DD} = 1 node: 1 to 4 MHz (V_{DD} = node: 1 to 32 MHz (V_{DD}	2.4 to 3.6 V), .8 to 3.6 V), 1.6 to 3.6 V) D = 2.7 to 3.6 V),					
		LS (Low-speed main) m	ode : 1 to 8 MHz (VDD	= 1.8 to 3.6 V),					
		LV (Low-voltage main) r	node : 1 to 4 MHz (VDD	= 1.6 to 3.6 V)					
Subsystem cl	ock		_	XT1 (crystal) oscillation, clock input (EXCLKS)	-				
Low-speed or	n-chip oscillator	15 kHz (TYP.)							
General-purp	ose register	$(8-bit register \times 8) \times 4$ bank							
Minimum inst	ruction execution time	0.03125 μ s (High-speed on-chip oscillator: f _{IH} = 32 MHz operation)							
		0.05 μ s (High-speed system clock: f _{MX} = 20 MHz operation)							
		- $30.5 \ \mu s$ (Subsystem clock: $f_{SUB} = 32.768 \ kHz$ operation)							
Instruction se	t	 Data transfer (8/16 bits) Adder and subtractor/logical operation (8/16 bits) Multiplication (8 bits × 8 bits) Rotate, barrel shift, and bit manipulation (Set, reset, test, and Boolean operation), etc. 							
I/O port	Total	19	26	42	56				
·	CMOS I/O	14 (N-ch O.D. I/O [Vɒɒ withstand voltage]: 6)	20 (N-ch O.D. I/O [Vɒɒ withstand voltage]: 9)	32 (N-ch O.D. I/O [Vɒɒ withstand voltage]: 11)	46 (N-ch O.D. I/O [Vɒɒ withstand voltage]: 12)				
	CMOS input	3	3	5	5				
	CMOS output	_	_	1	1				
	N-ch open-drain I/O (6 V tolerance)	2	3	4	4				
Timer	16-bit timer		8 cha	innels					
	Watchdog timer		1 ch	annel					
	Real-time clock (RTC)	1 chan	nel ^{Note 2}	1 cha	annel				
	12-bit interval timer (IT)		1 ch	annel					
	Timer output	2 channels (PWM output	s: 1 ^{Note 3})	4 channels (PWM outputs: 3 ^{Note 3})	7 channels (PWM outputs: 6 ^{Note 3})				
	RTC output		_	1 • 1 Hz (subsystem clock: fsuB = 32.768 kHz)					

- Notes 1. In the case of the 4 KB, this is about 3 KB when the self-programming function and data flash function are used. (For details, see CHAPTER 3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS TA = -40 to +105°C))
 - 2. Only the constant-period interrupt function when the low-speed on-chip oscillator clock (fi∟) is selected.
 - **3.** The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves). (**6.9.3 Operation as multiple PWM output function**).



		[T	(2/2)			
Ite	m	25-pin R5F10E8x	32-pin R5F10EBx	48-pin R5F10EGx	64-pin R5F10ELx			
Clock output/buzzer output								
οιοςκ σαιμανδάζετει σάιραι		1 • 2.44 kHz, 4.88 kHz, 9.7 2.5 MHz, 5 MHz, 10 M (Main system clock: fw		 2.44 kHz, 4.88 kHz, 2.5 MHz, 5 MHz, 10 (Main system clock: 256 Hz, 512 Hz, 1.0 	2 2 • 2.44 kHz, 4.88 kHz, 9.76 kHz, 1.25 MHz, 2.5 MHz, 5 MHz, 10 MHz (Main system clock: fMain = 20 MHz operation) • 256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.096 kHz, 8.192 kHz, 16.384 kHz, 32.768 kHz			
8/12-bit resolution	A/D converter	13 channels	18 channels	24 channels	28 channels			
Serial interface		[25-pin products]	-					
		 Simplified SPI (CSI): Simplified SPI (CSI): [32-pin products] 	 1 channel/simplified l²C: 1 channel/simplified l²C: 1 channel/simplified l²C: 	1 channel/UART: 1 cha	annel			
		Simplified SPI (CSI):	1 channel/simplified I ² C:	1 channel/UART: 1 cha				
		 Simplified SPI (CSI): Simplified SPI (CSI): channel [64-pin products] Simplified SPI (CSI): Simplified SPI (CSI): 	2 channels/simplified I ² C 2 channels/simplified I ² C	1 channel/UART: 1 cha 2: 2 channels/UART (U/ 2: 2 channels/UART: 1 d 2: 2 channels/UART: 1 d 2: 2 channels/UART: 1 d	annel ART supporting LIN-bus): 1 channel			
	I ² C bus	1 channel	1 channel	1 channel	1 channel			
Multiplier and divider/multiply-ac	cumulator	 16 bits × 16 bits = 32 bits (Unsigned or signed) 32 bits ÷ 32 bits = 32 bits (Unsigned) 16 bits × 16 bits + 32 bits = 32 bits (Unsigned or signed) 						
DMA controller		2 channels						
Vectored interrupt	Internal	24	27	27	27			
sources	External	6	6	10	13			
Key interrupt		0 ch (4 ch) ^{Note 1}	1 ch (6 ch) ^{Note 1}	6 ch	10 ch			
Reset		 Reset by RESET pin Internal reset by watchdog timer Internal reset by power-on-reset Internal reset by voltage detector Internal reset by illegal instruction execution^{Note 2} Internal reset by RAM parity error Internal reset by illegal-memory access 						
Power-on-reset ci	rcuit	Power-on-reset: 1.4 Power-down-reset: 1.4	51 V (TYP.) 50 V (TYP.)					
Voltage detector			.67 V to 3.14 V (12 stage .63 V to 3.06 V (12 stage					
On-chip debug fu	nction	Provided						
Power supply volt	age	V _{DD} = 1.6 to 3.6 V						
Operating ambien	t temperature	TA = -40 to +85°C (A: C	onsumer application), TA	= -40 to +105°C (G: In	ndustrial application)			

Notes 1. Can be used by the Peripheral I/O redirection register (PIOR).

2. The illegal instruction is generated when instruction code FFH is executed.

Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

2. ELECTRICAL SPECIFICATIONS ($T_A = -40$ to $+85^{\circ}C$)

This chapter describes the following electrical specifications.

- Target productsA:Consumer applicationsTA = -40 to +85°CR5F10E8AALA, R5F10E8CALA, R5F10E8DALA, R5F10E8EALAR5F10EBAANA, R5F10EBCANA, R5F10EBDANA, R5F10EBEANAR5F10EGAAFB, R5F10EGCAFB, R5F10EGDAFB, R5F10EGEAFBR5F10EGAANA, R5F10EGCANA, R5F10EGDANA, R5F10EGEANAR5F10ELCAFB, R5F10ELDAFB, R5F10ELEAFBR5F10ELCABG, R5F10ELDABG, R5F10ELEABG
 - G: Industrial applications When T_A = -40 to +105°C products is used in the range of T_A = -40 to +85°C
 R5F10EBAGNA, R5F10EBCGNA, R5F10EBDGNA, R5F10EBEGNA
 R5F10EGAGFB, R5F10EGCGFB, R5F10EGDGFB, R5F10EGEGFB
 R5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNA
 R5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB
- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EV_{DD0} or EV_{SS0} pin, replace EV_{DD0} with V_{DD}, or replace EV_{SS0} with V_{SS}.



2.1 Absolute Maximum Ratings

Absolute Maximum Ratings (T_A = 25°C) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	Vdd		-0.5 to +6.5	V
	EVDD0		-0.5 to +6.5	V
	AVDD		-0.5 to +4.6	V
	AVREFP		-0.3 to AV _{DD} +0.3 ^{Note 3}	V
	EVss0		-0.5 to +0.3	V
	AVss		-0.5 to +0.3	V
	AVREFM		–0.3 to AV _{DD} +0.3 ^{Note 3} and AV _{REFM} ≤ AV _{REFP}	V
REGC pin input voltage	Viregc	REGC	-0.3 to +2.8 and -0.3 to V _{DD} +0.3 ^{Note 1}	V
Input voltage	Vi1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	-0.3 to EV _{DD0} +0.3 and -0.3 to V _{DD} +0.3 ^{Note 2}	V
	V ₁₂	P60 to P63 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} +0.3 ^{Note 2}	V
	V14	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Output voltage	V ₀₁	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	-0.3 to EV _{DD0} +0.3 ^{Note 2}	V
	V ₀₂	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Analog input voltage	Val1	ANI16 to ANI30	-0.3 to EV_DD0 +0.3 and -0.3 to AV_{REF(+)} +0.3^{Notes 2, 4}	V
	Vai2	ANI0 to ANI12	-0.3 to AV_DD +0.3 and -0.3 to AV_{\text{REF}(+)} +0.3 $^{\text{Notes 2, 4}}$	V

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

- 2. Must be 6.5 V or lower.
- **3.** Must be 4.6 V or lower.
- 4. Do not exceed AV_{REF(+)} + 0.3 V in case of A/D conversion target pin.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - 2. AV_{REF(+)}: + side reference voltage of the A/D converter.
 - 3. Vss: Reference voltage



Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Der pin P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141		-40	mA
		Total of all pins –170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	-70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P70 to P77,	-100	mA
	Іон2	Per pin	P20 to P27, P150 to P154	-0.1	mA
		Total of all pins		-1.3	mA
Output current, low	lol1	Per pin	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	40	mA
		Total of all pins 170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P60 to P63, P70 to P77	100	mA
	IOL2	Per pin	P20 to P27, P150 to P154	0.4	mA
		Total of all pins		6.4	mA
Operating ambient	TA	In normal operation	on mode	-40 to +85	°C
temperature		In flash memory p	programming mode		
Storage temperature	Tstg			–65 to +150	°C

Absolute Maximum Ratings (T_A = 25°C) (2/2)

- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



2.2 Oscillator Characteristics

2.2.1 X1, XT1 oscillator characteristics

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/crystal resonator	$2.7~V \leq V_{\text{DD}} \leq 3.6~V$	1.0		20.0 M	
frequency (fx) ^{Note}		$2.4~V \leq V_{\text{DD}} < 2.7~V$	1.0		16.0	MHz
		$1.8~V \leq V_{\text{DD}} < 2.4~V$	1.0		8.0	MHz
		$1.6~V \leq V_{\text{DD}} < 1.8~V$	1.0		4.0	MHz
XT1 clock oscillation frequency (fx) ^{Note}	Crystal resonator		32	32.768	35	kHz

$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

- **Note** Indicates only permissible oscillator frequency ranges. See AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.
- Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

2.2.2 On-chip oscillator characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Oscillators	Parameters		Conditions			MAX.	Unit
High-speed on-chip oscillator clock frequency ^{Notes 1, 2}	fін			1		32	MHz
High-speed on-chip oscillator clock frequency accuracy		–20 to +85 °C	$1.8~V \leq V_{\text{DD}} \leq 3.6~V$	-1.0		+1.0	%
			$1.6~V \leq V_{\text{DD}} < 1.8~V$	-5.0		+5.0	%
		–40 to –20 °C	$1.8~V \leq V_{\text{DD}} \leq 3.6~V$	-1.5		+1.5	%
			$1.6~V \leq V_{\text{DD}} < 1.8~V$	-5.5		+5.5	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

- **Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H/010C2H) and bits 0 to 2 of HOCODIV register.
 - 2. This indicates the oscillator characteristics only. See AC Characteristics for instruction execution time.

2.3 DC Characteristics

2.3.1 Pin characteristics

(T _A = -40 to +85°	C, 1.6 V ≤ A	$V_{DD} \leq V_{DD} \leq 3.6 \text{ V}, 1.6 \text{ V} \leq \text{EV}_{DD0} \leq \text{V}$	DD \leq 3.6 V, Vss = EVs	sso = 0 V)		(1/5)
Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high ^{Note 1}	Іон1	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	$1.6~V \leq EV_{DD0} \leq 3.6~V$			-10.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			-10.0	mA
		P130, P140, P141	$1.8~V \leq EV_{\text{DD0}} < 2.7~V$			-5.0	mA
		(When duty ≤ 70% ^{Note 3})	$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V}$			-2.5	mA
		Total of P05, P06, P10 to P16, P30, P31, P50, P51, P70 to P77, (When duty $\leq 70\%^{\text{Note 3}}$)	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			-19.0	mA
			$1.8~V \leq EV_{\text{DD0}} < 2.7~V$			-10.0	mA
			$1.6~V \leq EV_{\text{DD0}} < 1.8~V$			-5.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$1.6~V \leq EV_{DD0} \leq 3.6~V$			-29.0	mA
	Іон2	Per pin for P20 to P27, P150 to P154	$1.6 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			-0.1 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$1.6 \text{ V} \le AV_{DD} \le 3.6 \text{ V}$			-1.3	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the EV_{DD0}, V_{DD} pins to an output pin.

- 2. However, do not exceed the total current value.
- 3. Specification under conditions where the duty factor ≤ 70%. The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).
 - Total output current of pins = (I_{OH} × 0.7)/(n × 0.01) <Example> Where n = 80% and I_{OH} = -10.0 mA

Total output current of pins = $(-10.0 \times 0.7)/(80 \times 0.01) \cong -8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

- Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low ^{Note 1}	Iol1	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141				20.0 ^{Note 2}	mA
		Per pin for P60 to P63				15.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			15.0	mA
		P130, P140, P141 (When duty ≤ 70% ^{Note 3})	$1.8~V \leq EV_{\text{DD0}} < 2.7~V$			9.0	mA
			$1.6~V \leq EV_{\text{DD0}} < 1.8~V$			4.5	mA
		P31, P50, P51, P60 to P63,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			35.0	mA
			$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			20.0	mA
			$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V}$			10.0	mA
lol2						50.0	mA
	IOL2	Per pin for P20 to P27, P150 to P154				0.4 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$1.6 \text{ V} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			5.2	mA

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVsso and Vss pin.
 - **2.** However, do not exceed the total current value.
 - **3.** Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = $(I_{OL} \times 0.7)/(n \times 0.01)$ <Example> Where n = 80% and IoL = 10.0 mA Total output current of pins = $(10.0 \times 0.7)/(80 \times 0.01) \cong 8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	$\frac{\mathbf{AV}_{DD} \leq \mathbf{V}_{DD} \leq \mathbf{3.6 V}, \ \mathbf{1.6 V} \leq \mathbf{EV}_{DD}}{\text{Conditions}}$	$0 \leq \mathbf{V} D D \leq 3.0 \mathbf{V}, \mathbf{V} SS =$	MIN.	<u>v)</u> TYP.	MAX.	(3/5 Unit
Input voltage, high	ViH1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	Normal input buffer	0.8EVddo		EVDDO	V
	VIH2	P01, P03, P04, P10, P11, P13 to P16, P43	TTL input buffer $3.3 V \le EV_{DD0} \le 3.6 V$	2.0		EVDD0	V
			TTL input buffer 1.6 V \leq EV _{DD0} $<$ 3.3 V	1.5		EVDD0	V
	VIH3	P20 to P27, P150 to P154		0.7AVDD		AVDD	V
	VIH4	P60 to P63		0.7EVDD0		6.0	V
	VIH5	P121 to P124, P137, EXCLK, EXCL	0.8Vdd		Vdd	V	
Input voltage, low	VIL1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	Normal input buffer	0		0.2EVDD0	V
	VIL2	P01, P03, P04, P10, P11, P13 to P16, P43	TTL input buffer $3.3 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	0		0.5	V
			TTL input buffer 1.6 V \leq EV _{DD0} < 3.3 V	0		0.32	V
	VIL3	P20 to P27, P150 to P154		0		0.3AVDD	V
	VIL4	P60 to P63		0		0.3EVDD0	V
	VIL5	P121 to P124, P137, EXCLK, EXCL	(S, RESET	0		0.2VDD	V

 $(T_A = -40 \text{ to } +85^{\circ}\text{C} = 1.6 \text{ V} \le 4 \text{ Vpp} \le 3.6 \text{ V} = 1.6 \text{ V} \le F \text{ Vpp} \le 3.6 \text{ V} = 5 \text{ Vss} = 0.0 \text{ V}$

Caution The maximum value of VIH of pins P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 is EVDD0, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	$AV_{DD} \le V_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le \text{EV}_{DD}$ Conditions	v ⊇ v bb ⊇ 0.0 v, v35 −	MIN.	TYP.	MAX.	(4/ Unit
Output voltage, high	V _{OH1}	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ I_{OH1} = -2.0 mA	EV _{DD0} - 0.6			V
		P120, P130, P140, P141	$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OH1}} = -1.5 \text{ mA}$	EV _{DD0} – 0.5			V
			$1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ IOH1 = -1.0 mA	EV _{DD0} - 0.5			V
	V _{OH2}	P20 to P27, P150 to P154	$1.6 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V},$ IOH2 = -100 μ A	AV _{DD} – 0.5			V
Output voltage, Vol	V _{OL1}	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77,	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL1}} = 3.0 \text{ mA}$			0.6	V
		P120, P130, P140, P141	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL1}} = 1.5 \text{ mA}$			0.4	V
			$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL1}} = 0.6 \text{ mA}$			0.4	V
			$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $I_{\text{OL1}} = 0.3 \text{ mA}$			0.4	V
	Vol2	P20 to P27, P150 to P154	$1.6 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V},$ $I_{\text{OL2}} = 400 \ \mu\text{A}$			0.4	V
Vo	Vol3	P60 to P63	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL3}} = 3.0 \text{ mA}$			0.4	V
			$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL3}} = 2.0 \text{ mA}$			0.4	V
			$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $I_{\text{OL3}} = 1.0 \text{ mA}$			0.4	V

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Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	Conditio	ons		MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ішні	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P140, P141	VI = EVDDO	,			1	μA
	ILIH2	P137, RESET	VI = VDD				1	μA
	Іцнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = VDD	In input port or external clock input			1	μA
				In resonator connection			10	μA
	Ілн4	P20 to P27, P150 to P154	VI = AVDD				1	μA
Input leakage current, low	ILIL1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P67, P70 to P77, P120, P140, P141	Vi = EVsso	VI = EVSS0			-1	μA
	ILIL2	P137, RESET	VI = Vss				-1	μA
	ILIL3	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = Vss	In input port or external clock input			-1	μA
				In resonator connection			-10	μA
	ILIL4	P20 to P27, P150 to P154	VI = AVss				-1	μA
On-chip pull-up resistance	Ru	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	Vi = EVsso, In input port		10	20	100	kΩ

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Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



2.3.2 Supply current characteristics

Parameter	Symbol			<pre>/, Vss = EVsso = 0 V) Conditions</pre>			MIN.	TYP.	MAX.	Uni
Supply current ^{Note 1}	IDD1	Operating mode	HS (high-speed main) mode ^{Note 5}	fi⊢ = 32 MHz ^{Note 3}	Basic operation	V _{DD} = 3.0 V		2.1		mA
					Normal operation	V _{DD} = 3.0 V		4.6	7.0	mA
				f _{IH} = 24 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		3.7	5.5	mA
				f⊪ = 16 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		2.7	4.0	mA
			LS (low-speed main) mode ^{Note 5}	fi⊢ = 8 MHz ^{Note 3}	Normal	V _{DD} = 3.0 V		1.2	1.8	mA
					operation	V _{DD} = 2.0 V		1.2	1.8	
			LV (Low-voltage main) mode ^{Note 5}	f _{IH} = 4 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		1.2	1.7	m/
					operation	V _{DD} = 2.0 V		1.2	1.7	
			HS (high-speed main) mode ^{Note 5}	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$ $V_{DD} = 3.0 \text{ V}$	Normal operation	Square wave input		3.0	4.6	m/
						Resonator connection		3.2	4.8	
				f _{MX} = 10 MHz ^{Note 2} , V _{DD} = 3.0 V	Normal operation	Square wave input		1.9	2.7	m/
						Resonator connection		1.9	2.7	
			LS (low-speed main) mode ^{Note 5}	fмх = 8 MHz ^{Note 2} , V _{DD} = 3.0 V	Normal operation	Square wave input		1.1	1.7	m
					Resonator connection		1.1	1.7		
		,	Normal operation	Square wave input		1.1	1.7	m		
		Subsystem clock mode			Resonator connection		1.1	1.7		
					Normal operation	Square wave input		4.1	4.9	μŀ
						Resonator connection		4.2	5.0	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +25°C	Normal operation	Square wave input		4.2	4.9	μŀ
						Resonator connection		4.3	5.0	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +50°C	Normal operation	Square wave input		4.3	5.5	μŀ
					Resonator connection		4.4	5.6	1	
				f _{SUB} = 32.768 kHz ^{Note 4} T _A = +70°C	Normal operation	Square wave input		4.5	6.3	μF
					Resonator connection		4.6	6.4		
				fsub = 32.768 kHz ^{Note 4} T _A = +85°C	Normal operation	Square wave input		4.8	7.7	μŀ
						Resonator connection		4.9	7.8	

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{ V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

(Notes and Remarks are listed on the next page.)

- **Notes 1.** Total current flowing into V_{DD} and EV_{DD0}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD0} or Vss, EVsso. The following points apply in the HS (high-speed main), LS (low-speed main), and LV (low-voltage main) modes.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

- 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- 3. When high-speed system clock and subsystem clock are stopped.
- **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When setting ultra-low power consumption oscillation (AMPHS1 = 1)
- **5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}@1 \text{ MHz}$ to 32 MHz

- $2.4 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}@1 \text{ MHz to 16 MHz}$ LS (low-speed main) mode: $1.8 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}@1 \text{ MHz to 8 MHz}$
- LS (low-speed main) mode: $1.8 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}@1 \text{ MHz}$ to 8 MHzLV (Low-voltage main) mode: $1.6 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}@1 \text{ MHz}$ to 4 MHz
- **Remarks 1.** fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - **3.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C



Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	DD2Note 2	HALT	HS (high-speed	f⊮ = 32 MHz ^{Note 4}	V _{DD} = 3.0 V		0.54	1.63	mA
current ^{Note 1}		mode	main) mode ^{Note 7}	fı⊢ = 24 MHz ^{Note 4}	V _{DD} = 3.0 V		0.44	1.28	mA
				f⊮ = 16 MHz ^{Note 4}	V _{DD} = 3.0 V		0.40	1.00	mA
			LS (low-speed	fı⊢ = 8 MHz ^{Note 4}	V _{DD} = 3.0 V		270	530	μA
			main) mode ^{Note 7}		V _{DD} = 2.0 V		270	530	
			LV (Low-voltage	fı⊢ = 4 MHz ^{Note 4}	V _{DD} = 3.0 V		435	640	μA
			main) mode ^{Note 7}		V _{DD} = 2.0 V		435	640	
			HS (high-speed	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.00	mA
			main) mode ^{Note 7}	V _{DD} = 3.0 V	Resonator connection		0.45	1.17	
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	0.60	mA
				V _{DD} = 3.0 V	Resonator connection		0.26	0.67	
			LS (low-speed	f _{MX} = 8 MHz ^{Note 3} ,	Square wave input		95	330	μA
			main) mode ^{Note 7}	V _{DD} = 3.0 V	Resonator connection		145	380	
	$f_{MX} = 8 \text{ MHz}^{Note 3},$ $V_{DD} = 2.0 \text{ V}$	Square wave input		95	330	μA			
				V _{DD} = 2.0 V	Resonator connection		145	380	
			Subsystem clock	fsub = 32.768 kHz ^{Note 5}	Square wave input		0.25	0.57	μA
			mode	T _A = -40°C	Resonator connection		0.44	0.76	
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.30	0.57	μA
				T _A = +25°C	Resonator connection		0.49	0.76	
				fsue = 32.768 kHz ^{Note 5}	Square wave input		0.38	1.17	μA
				T _A = +50°C	Resonator connection		0.57	1.36	
				fsue = 32.768 kHz ^{Note 5}	Square wave input		0.52	1.97	μA
				T _A = +70°C	Resonator connection		0.71	2.16	
				fsue = 32.768 kHz ^{Note 5}	Square wave input		0.97	3.37	μA
				T _A = +85°C	Resonator connection		1.16	3.56	
	I_{DD3} Note 6 STOP $T_A = -40^{\circ}C$	$T_A = -40^{\circ}C$				0.16	0.50	μA	
		mode ^{Note 8}	T _A = +25°C				0.23	0.50	
			T _A = +50°C				0.34	1.10	
		T _A = +70°C				0.46	1.90		
			T₄ = +85°C				0.75	3.30]

$(T_A = -40 \text{ to } +85^{\circ}C)$	$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}, \text{ Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V}$

(Notes and $\ensuremath{\textit{Remarks}}$ are listed on the next page.)



- **Notes 1.** Total current flowing into VDD and EVDDO, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDDO or Vss, EVsso. The following points apply in the HS (high-speed main), LS (low-speed main), and LV (low-voltage main) modes.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-downresistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- 4. When high-speed system clock and subsystem clock are stopped.
- **5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1).
- 6. When subsystem clock is stopped.
- **7.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 \text{ V} \le V_{\text{DD}} \le 3.6 \text{ V} @1 \text{ MHz}$ to 32 MHz

- 2.4 V \leq V_{DD} \leq 3.6 V@1 MHz to 16 MHz
- LS (low-speed main) mode: $1.8~V \leq V_{\text{DD}}$ < 3.6 V@1 MHz to 8 MHz
- LV (low-voltage main) mode: 1.6 V \leq V_DD \leq 3.6 V@1 MHz to 4 MHz
- **8.** Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- **Remarks 1.** fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - **3.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is $T_A = 25^{\circ}C$



Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit	
Low-speed on-chip oscillator operating current	_{FIL} Note 1				0.20		μA	
RTC operating current	_{RTC} Notes 1, 2, 3				0.02		μA	
12-bit interval timer operating current	IIT ^{Notes 1, 2, 4}				0.02		μA	
Watchdog timer operating current	_{WDT} Notes 1, 2, 5	f⊾ = 15 kHz			0.22		μA	
A/D converter operating current	ADC ^{Notes 6, 7}	AV _{DD} = 3.0 V, W	hen conversion at maximum speed		420	720	μA	
AV _{REF(+)} current	AVREFNote 8	AV _{DD} = 3.0 V, AI	DREFP1 = 0, ADREFP0 = 0 ^{Note 7}		14.0	25.0	μA	
		AV _{REFP} = 3.0 V, /	ADREFP1 = 0, ADREFP0 = $1^{\text{Note 10}}$		14.0	25.0	μA	
		ADREFP1 = 1, A	DREFP0 = 0 ^{Note 1}		14.0	25.0	μA	
A/D converter reference voltage current	ADREF ^{Notes 1, 9}	V _{DD} = 3.0 V			75.0		μA	
Temperature sensor operating current	_{TMP} Note 1	V _{DD} = 3.0 V			75.0		μA	
LVD operating current	ILVD ^{Notes 1, 11}				0.08		μA	
BGO operating current	BGO ^{Notes 1, 12}				2.5	12.2	mA	
Self-programming operating current	FSP ^{Notes 1, 13}				2.5	12.2	mA	
SNOOZE operating	Isnoz	A/D converter	The mode is performed ^{Notes 1, 14}		0.50	0.60	mA	
current		operation		During A/D conversion ^{Note 1}		0.60	0.75	mA
		(AV _{DD} = 3.0 V)	During A/D conversion ^{Note 7}		420	720	μA	
		Simplified SPI (C	CSI)/UART operation ^{Note 1}		0.70	0.84	mA	

(T _A = -40 to +85°C	, 1.6 V ≤ EVDD	$0 \leq V$ DD $\leq 3.6 V$,	Vss = EVsso = 0 \

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Current flowing to VDD.
 - 2. When high-speed on-chip oscillator and high-speed system clock are stopped.
 - 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
 - 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
 - 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2, or IDD3 and IWDT when the watchdog timer is in operation.
 - 6. Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC, IAVREF, IADREF when the A/D converter operates in an operation mode or the HALT mode.
 - 7. Current flowing to the AVDD.
 - 8. Current flowing from the reference voltage source of A/D converter.
 - 9. Operation current flowing to the internal reference voltage.
 - **10.** Current flowing to the AVREFP.
 - **11.** Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
 - 12. Current flowing only during data flash rewrite.
 - **13.** Current flowing only during self programming.

Remarks 1. fil: Low-speed on-chip oscillator clock frequency

- 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- 3. fclk: CPU/peripheral hardware clock frequency
- 4. Temperature condition of the TYP. value is $T_A = 25^{\circ}C$



2.4 AC Characteristics

$(T_{\text{A}} = -40 \text{ to } +85^{\circ}\text{C}, \text{ AV}_{\text{DD}} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}, 1.6 \text{ V} \leq \text{EV}_{\text{DD}} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Items	Symbol		Condit	tions		MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсү	Main system	HS (high-sp		$2.7~V \leq V_{\text{DD}} \leq 3.6~V$	0.03125		1	μs
instruction execution time)		clock (fmain) operation	main) mode	9	$2.4 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V}$	0.0625		1	μs
		operation	LS (low-spe main) mode		$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}$	0.125		1	μs
			LV (low-volt main) mode	-	$1.6 \text{ V} \leq V_{\text{DD}} \leq 3.6 \text{ V}$	0.25		1	μs
		Subsystem clooperation	ock (fsuв)		$1.8 \text{ V} \leq V_{\text{DD}} \leq 3.6 \text{ V}$	28.5	30.5	31.3	μs
		In the self	HS (high-sp	beed	$2.7~V \leq V_{\text{DD}} \leq 3.6~V$	0.03125		1	μs
		programming mode	main) mode	9	$2.4~V \leq V_{\text{DD}} < 2.7~V$	0.0625		1	μs
		mode	LS (low-spe main) mode		$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	0.125		1	μs
			LV (low-volt main) mode	•	$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}$	0.25		1	μs
External system clock	f _{EX}	$2.7~V \leq V_{\text{DD}} \leq$	3.6 V			1.0		20.0	MHz
frequency		$2.4~V \leq V_{\text{DD}} <$	2.7 V			1.0		16.0	MHz
		$1.8 \text{ V} \leq \text{V}_{\text{DD}}$ <	2.4 V			1.0		8.0	MHz
		$1.6 V \le V_{DD} <$	1.8 V			1.0		4.0	MHz
	fexs					32		35	kHz
External system clock input	texh, texl	$2.7~V \leq V_{\text{DD}} \leq$	3.6 V			24			ns
high-level width, low-level width		$2.4 \text{ V} \leq V_{\text{DD}}$ <	2.7 V			30			ns
width		$1.8 \text{ V} \leq \text{V}_{\text{DD}}$ <	2.4 V			60			ns
Ļ		$1.6 \text{ V} \le \text{V}_{\text{DD}}$ <	1.8 V			120			ns
	texns, texls					13.7			μs
TI00, TI01, TI03 to TI07 input high-level width, low-level width	t⊤ıн, t⊤ı∟								ns ^{Note}
TO00, TO01, TO03 to	fто	HS (high-speed main) $2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6$		$\leq EV_{DD0} \leq 3.6 V$			8	MHz	
TO07 output frequency		mode		1.8 V	\leq EV _{DD0} < 2.7 V			4	MHz
				$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V}$				2	MHz
		LS (low-speed	d main)	$1.8 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$				4	MHz
		mode		1.6 V ≤ EV _{DD0} < 1.8 V				2	MHz
		LV (low-voltag mode	ge main)	1.6 V	$\leq EV_{DD0} \leq 3.6 V$			2	MHz
PCLBUZ0, PCLBUZ1	f PCL	HS (high-spee	ed main)	2.7 V	$\leq EV_{DD0} \leq 3.6 V$			8	MHz
output frequency		mode		1.8 V	\leq EV _{DD0} < 2.7 V			4	MHz
			•	1.6 V	\leq EV _{DD0} < 1.8 V			2	MHz
		LS (low-speed	d main)	1.8 V	$\leq EV_{DD0} \leq 3.6 V$			4	MHz
		mode		1.6 V	≤ EV _{DD0} < 1.8 V			2	MHz
		LV (low-voltag	ge main)	1.8 V	$\leq EV_{DD0} \leq 3.6 V$			4	MHz
		mode		1.6 V	≤ EV _{DD0} < 1.8 V			2	MHz
Interrupt input high-level	tinth, tintl	INTP0		1.6 V	$\leq V_{DD} \leq 3.6 \text{ V}$	1			μs
width, low-level width		INTP1 to INT	P11	1.6 V	$\leq EV_{DD0} \leq 3.6 V$	1			μs
Key interrupt input high-level width, low-level	tкr	KR0 to KR9			$\leq EV_{DD0} \leq 3.6 V,$ $\leq AV_{DD0} \leq 3.6 V$	250			ns
width					≤ EV _{DD0} < 1.8 V, ≤ AV _{DD0} < 1.8 V	1			μs
			1		=/				

(Note and Remark are listed on the next page.)

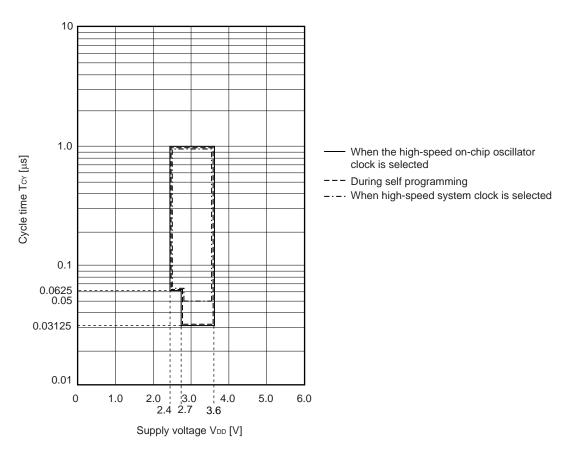


Note The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$. $1.8 V \le EV_{DD0} < 2.7 V : MIN. 125 ns$ $1.6 V \le EV_{DD0} < 1.8 V : MIN. 250 ns$

Remark fMCK: Timer array unit operation clock frequency (Operation clock to be set by the CKS0n bit of timer clock select register 0 (TPS0) and timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

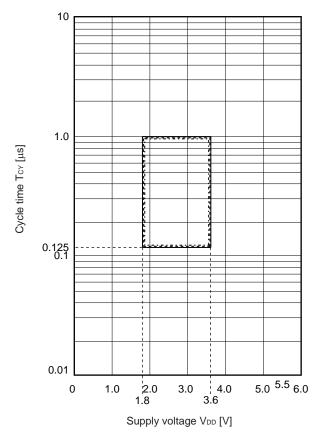
Minimum Instruction Execution Time during Main System Clock Operation

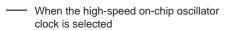
TCY VS VDD (HS (high-speed main) mode)





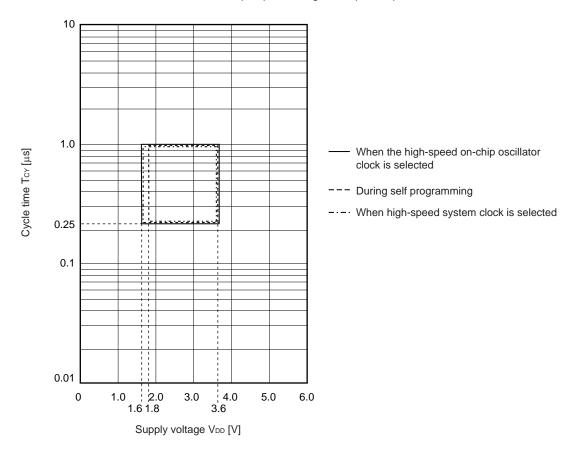
TCY VS VDD (LS (low-speed main) mode)





- --- During self programming
- ---- When high-speed system clock is selected

TCY vs VDD (LV (low-voltage main) mode)

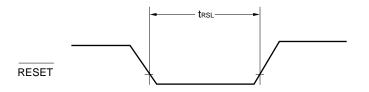




AC Timing Test Points Viн/Voн **Ин/**Vон Test points VIL/VOL VIL/VOL **External System Clock Timing** $1/f_{\text{EX}}$ $\mathbf{t}_{\mathsf{EXL}}$ **t**exh 0.7 VDD MIN. EXCLK 0.3 VDD MAX. **TI/TO Timing** t⊤ı∟ tтін TI00, TI01, TI03 to TI07 1/f⊤o -TO00, TO01, TO03 to TO07 Interrupt Request Input Timing **t**INTL tinth INTP0 to INTP11 Key Interrupt Input Timing tk₽ KR0 to KR9



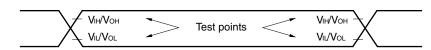
RESET Input Timing





2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit

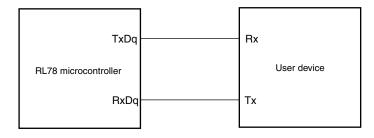
(1) During communication at same potential (UART mode) ($T_A = -40$ to +85°C, 1.6 V $\leq EV_{DD0} \leq V_{DD} \leq 3.6$ V, Vss = EVss0 = 0 V)

Parameter	Symbol	Conditions	HS	Note 1	LS	Note 2	L۷	lote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate ^{Note 4}		$2.4~V \leq EV_{\text{DD}} \leq 3.6~V$		fмск/6		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 6}$		5.3 ^{Note 5}		1.3		0.6	Mbps
		$1.8 \text{ V} \leq EV_{\text{DD}} \leq 3.6 \text{ V}$		fмск/6		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 6}$		5.3 ^{Note 5}		1.3		0.6	Mbps
		$1.7~V \le EV_{\text{DD}} \le 3.6~V$		fмск/6		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 6}$		5.3 ^{Note 5}		1.3 ^{Note 5}		0.6	Mbps
		$1.6 \text{ V} \leq EV_{\text{DD}} \leq 3.6 \text{ V}$		-		fмск/6		fмск/6	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 6}$		-		1.3 ^{Note 5}		0.6	Mbps

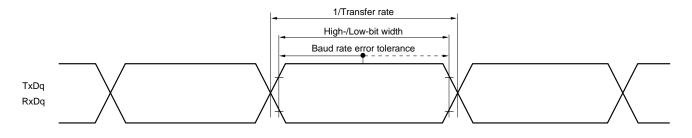
Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. Transfer rate in the SNOOZE mode is 4800 bps.
- 5. The following conditions are required for low-voltage interface when EVDD0 < VDD.
 - $2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$: MAX. 2.6 Mbps
 - $1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.4 \text{ V}$: MAX. 1.3 Mbps
 - $1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le 1.8 \text{ V}$: MAX. 0.6 Mbps
- **6.** fclk in each operating mode is as below.
 - HS (high-speed main) mode: fclk = 32 MHz
 - LS (low-speed main) mode: fclk = 8 MHz
 - LV (low-voltage main) mode: fcLK = 4 MHz
- Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Remarks 1. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

fmcκ: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
n: Channel number (mn = 00 to 03, 10, 11))



(2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

Parameter	Symbol	Conditions		HS ^{Note 1}		LS ^{Note 2}		LV ^{Note 3}		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	$2.7~V \leq EV_{\text{DD}} \leq 3.6~V$	tkcy1≥2/fcLk	83.3		250		500		ns
SCKp high-/low-level width	tкнı,	$2.7~V \leq EV_{\text{DD}} \leq 3.6~V$	$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 3.6 \text{ V}$ t			t ксү1/2		t ксү1/2		ns
	tĸ∟1			-10		-50		-50		
SIp setup time (to SCKp↑) ^{Note 4}	tsik1	$2.7~V \leq EV_{\text{DD}} \leq 3.6~V$	1	33		110		110		ns
SIp hold time (from SCKp↑) ^{Note 4}	tksi1	$2.7~V \leq EV_{\text{DD}} \leq 3.6~V$		10		10		10		ns
Delay time from SCKp↓ to SOp output ^{Note 5}	tkso1	C = 20 pF ^{Note 6}			10		10		10	ns

$(T_A = -40 \text{ to } +85^{\circ}C, 2.7 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, \text{ Vss} = EV_{SS0} = 0 \text{ V})$

Notes 1. HS is condition of HS (high-speed main) mode.

- **2.** LS is condition of LS (low-speed main) mode.
- **3.** LV is condition of LV (low-voltage main) mode.
- 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 6. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM numbers (g = 1)
 - fMCK: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))



(3) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

Parameter	Symbol	Condition	s	HS	Note 1	LS⁵	lote 2	LV ^{Note 3}		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkCY2	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	$t_{\text{KCY1}} \ge 4/f_{\text{CLK}}$	125		500		1000		ns
		$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$	tксү1 ≥ 4/fcLk	250		500		1000		ns
		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	$t_{\text{KCY1}} \ge 4/f_{\text{CLK}}$	500		500		1000		ns
		$1.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	$t_{\text{KCY1}} \ge 4/f_{\text{CLK}}$	1000		1000		1000		ns
		$1.6~V \leq EV_{\text{DD0}} \leq 3.6~V$	tkcy1 ≥ 4/fcLk	_		1000		1000		ns
SCKp high-/low-level width	tкн2, tкL2	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$		tксү₂/2 −18		tксү₂/2 <i>–</i> 50		tксү₂/2 <i>–</i> 50		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$		tксү2/2 -38		tксү2/2 –50		tксү2/2 –50		ns
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		tксү2/2 –50		tксү2/2 –50		tксү2/2 –50		ns
		$1.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		tксү2/2 –100		tксү2/2 –100		tксү2/2 –100		ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$		_		tксү2/2 –100		tксү2/2 –100		ns
SIp setup time	tsik2	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$		44		110		110		ns
(to SCKp↑) ^{Note 4}		$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$		75		110		110		ns
		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$		110		110		110		ns
		$1.7~V \leq EV_{\text{DD0}} \leq 3.6~V$		220		220		220		ns
		$1.6~V \leq EV_{\text{DD0}} \leq 3.6~V$		_		220		220		ns
SIp hold time	tĸsı2	$1.7~V \leq EV_{\text{DD}} \leq 3.6~V$		19		19		19		ns
(from SCKp↑) ^{Note 4}		$1.6~V \leq EV_{\text{DD}} \leq 3.6~V$		-		19		19		ns
Delay time from SCKp \downarrow	tĸso2	$1.7~V \leq EV_{\text{DD}} \leq 3.6~V$	$C = 30 pF^{Note 6}$		25		25		25	ns
to SOp output ^{Note 5}		$1.6~V \le EV_{\text{DD}} \le 3.6~V$	$C = 30 \text{ pF}^{Note 6}$		-		25		25	ns

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **6.** C is the load capacitance of the SCKp and SOp output lines.
- Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).
- **Remark** p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM numbers (g = 0, 1)

(4) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

(TA = -40 to +85°C, 1.6 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V)

Parameter	Symbol	C	condition	าร	HS	Note 1	LS⁵	lote 2	LV ^N	lote 3	Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time ^{Note 4}	t ксү2	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq$	3.6 V	16 MHz < fмск	8/fмск		_		-		ns
				fмск ≤ 16 MHz	6/fмск		6/fмск		6/fмск		ns
		$2.4 \text{ V} \leq EV_{\text{DD0}} \leq$	3.6 V		6/fмск		6/fмск		6/fмск		ns
					and 500ns		and 500ns		and 500ns		
		1.8 V ≤ EV _{DD0} ≤	36V		500ПЗ		6/fмск		6/fмск		ns
			0.0 1		and		and		and		110
					750ns		750ns		750ns		
		$1.7 \text{ V} \leq EV_{DD0} \leq$	3.6 V		6/fмск		6/fмск		6/fмск		ns
					and 1500ns		and 1500ns		and 1500ns		
		1.6 V ≤ EV _{DD0} ≤	3.6 V		_		6/fмск		6/fмск		ns
							and		and		
							1500ns		1500ns		
SCKp high-/low-level	tкн2,	$2.7~V \leq EV_{\text{DD}} \leq$	3.6 V		tксү2/2		tксү2/2		tксү2/2		ns
width	tKL2				-8		-8		-8		
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq$	3.0 V		tксү2/2 –18		tксү2/2 –18		tксү2/2 –18		ns
		1.7 V ≤ EVpp0 ≤	3.6 V		tксү2/2		tксү2/2		tkcy2/2		ns
					-66		-66		-66		
		$1.6 V \le EV_{DD0} \le$	3.6 V		-		tксү2/2		tксү2/2		ns
	-						-66		-66		
SIp setup time (to SCKp↑) ^{Note 5}	tsik2	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq$	3.6 V		1/fмск +20		1/fмск +30		1/fмск +30		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V			+20 1/fмск		+30 1/fмск		+30 1/fмск		nc
			3.0 V		+30		+30		+30		ns
		1.7 V ≤ EV _{DD0} ≤	3.6 V		1/fмск		1/fмск		1/fмск		ns
					+40		+40		+40		
		$1.6 V \le EV_{DD0} \le$	3.6 V		-		1/fмск		1/fмск		ns
							+40		+40		
SIp hold time (from SCKp↑) ^{Note 5}	tksi2	1.8 V ≤ EV _{DD0} ≤	3.6 V		1/fмск +31		1/fмск +31		1/fмск +31		ns
		1.7 V ≤ EV _{DD0} ≤	36V		1/fмск+		1/fмск+		1/fмск+		ns
					250		250		250		
		1.6 V ≤ EV _{DD0} ≤	3.6 V		-		1/fмск+		1/fмск+		ns
			1				250		250		
Delay time from SCKp↓	tkso2	C = 30 pF ^{Note 7}	2.7 V	$\leq EV_{DD0} \leq 3.6 V$		2/fмск		2/fмск		2/fмск	ns
to SOp output ^{Note 6}			2 4 14			+44		+110		+110	
			2.4 V	$\leq EV_{DD0} \leq 3.6 V$		2/fмск +75		2/fмск +110		2/fмск +110	ns
			1.8 V	≤ EV _{DD0} ≤ 3.6 V		2/fмск		2/fмск		2/fмск	ns
						+110		+110		+110	
			1.7 V	$\leq EV_{DD0} \leq 3.6 V$		2/fмск		2/fмск		2/fмск	ns
						+220		+220		+220	
			1.6 V	$\leq EV_{DD0} \leq 3.6 V$		-		2/fмск +220		2/fмск +220	ns
								+220		+220	

(Note, Caution and Remark are listed on the next page.)

- Notes 1. HS is condition of HS (high-speed main) mode.
 - **2.** LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
 - When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **6.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 7. C is the load capacitance of the SOp output lines.

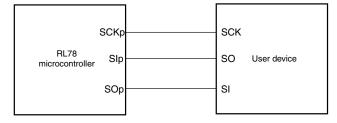
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

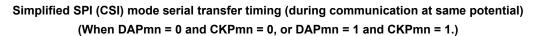
- **Remarks 1.** p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3),
 - g: PIM number (g = 0, 1)
 - 2. fMCK: Serial array unit operation clock frequency
 - (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

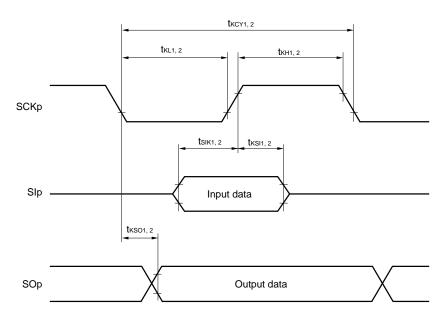
n: Channel number (mn = 00 to 03, 10, 11))



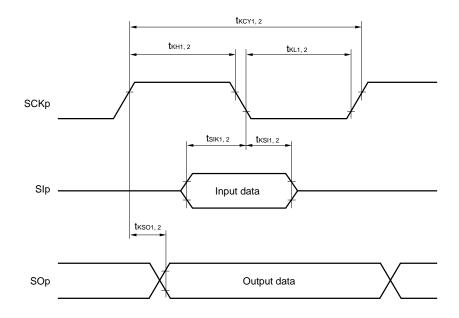
Simplified SPI (CSI) mode connection diagram (during communication at same potential)

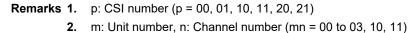






Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)





(5) During communication at same potential (simplified l²C mode) (1/2) (T₄ = -40 to +85°C, 1.6 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions	HS	Note 1	LS	Note 2	LV	Unit	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$\label{eq:constraint} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_b = 50 \mbox{ pF}, \mbox{ R}_b = 2.7 \mbox{ k}\Omega \end{array}$		1000 ^{Note} 4		400 ^{Note} 4		400 ^{Note} 4	kHz
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$		400 ^{Note 4}		400 ^{Note} 4		400 ^{Note} 4	kHz
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD0}} < 2.7 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 k\Omega \end{array}$		300 ^{Note 4}		300 ^{Note} 4		300 ^{Note} 4	kHz
		$\label{eq:linear} \begin{array}{l} 1.7 \mbox{ V} \leq \mbox{EV}_{\mbox{DD0}} < 1.8 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 k\Omega \end{array}$		250 ^{Note 4}		250 ^{Note} 4		250 ^{Note} 4	kHz
		$\label{eq:linear} \begin{array}{l} 1.6 \mbox{ V} \leq EV_{\mbox{DD0}} < 1.8 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 k\Omega \end{array}$		-		250 ^{Note} 4		250 ^{Note} 4	kHz
Hold time when SCLr = "L"	t LOW	$\label{eq:linear} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 50 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 2.7 k\Omega \end{array}$	475		1150		1150		ns
		$\label{eq:loss} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$	1150		1150		1150		ns
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{\tiny DD0}} < 2.7 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 \mbox{ k}\Omega \end{array}$	1550		1550		1550		ns
		$\label{eq:2.1} \begin{array}{l} 1.7 \ V \leq E V_{\text{DD0}} < 1.8 \ V, \\ C_{\text{b}} = 100 \ \text{pF}, \ R_{\text{b}} = 5 \ \text{k}\Omega \end{array}$	1850		1850		1850		ns
		$\label{eq:linear} \begin{split} 1.6 \mbox{ V} &\leq E V_{\mbox{DD0}} < 1.8 \mbox{ V}, \\ C_{\mbox{b}} &= 100 \mbox{ pF}, \mbox{ R}_{\mbox{b}} = 5 \kappa \Omega \end{split}$	-		1850		1850		ns
Hold time when SCLr = "H"	tніgн	$\label{eq:linear} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 50 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 2.7 \mbox{ k}\Omega \end{array}$	475		1150		1150		ns
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$	1150		1150		1150		ns
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{\tiny DD0}} < 2.7 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 \mbox{ k}\Omega \end{array}$	1550		1550		1550		ns
		$\begin{array}{l} 1.7 \; V \leq E V_{\text{DD0}} < 1.8 \; V, \\ C_{\text{b}} = 100 \; \text{pF}, \; R_{\text{b}} = 5 \; \text{k}\Omega \end{array}$	1850		1850		1850		ns
		$\label{eq:linear} \begin{array}{l} 1.6 \mbox{ V} \leq EV_{\mbox{\tiny DD0}} < 1.8 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 \mbox{ k}\Omega \end{array}$	-		1850		1850		ns
Data setup time (reception)	tsu:dat	$\label{eq:constraint} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{b}} = 50 \mbox{ pF}, \mbox{ R}_{\mbox{b}} = 2.7 \mbox{ k}\Omega \end{array}$	1/f _{МСК} + 85 ^{Note 5}		1/f _{мск} + 145 ^{Note 5}		1/f _{мск} + 145 ^{Note 5}		ns
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$	1/f _{МСК} + 145 ^{Note 5}		1/f _{мск} + 145 ^{Note 5}		1/f _{мск} + 145 ^{Note 5}		ns
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD0}} < 2.7 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 k\Omega \end{array}$	1/fмск+ 230 ^{Note 5}		1/fмск+ 230 ^{Note 5}		1/f _{МСК} + 230 ^{Note 5}		ns
		$\label{eq:linear} \begin{array}{l} 1.7 \mbox{ V} \leq \mbox{EV}_{\mbox{DD}} < 1.8 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 5 \mbox{k} \Omega \end{array}$	1/f _{MCK} + 290 ^{Note 5}		1/f _{MCK} + 290 ^{Note 5}		1/f _{MCK} + 290 ^{Note 5}		ns
		$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ $C_{\text{b}} = 100 \text{ pF}, \text{ R}_{\text{b}} = 5 \text{ k}\Omega$	-		1/f _{мск} + 290 ^{Note 5}		1/f _{мск} + 290 ^{Note 5}		ns

(Notes, Caution and Remarks are listed on the next page.)



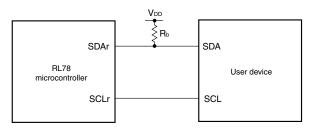
Parameter	Symbol	Conditions	HS	HS ^{Note 1}		lote 2	LV ^{Note 3}		Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data hold time (transmission)	thd:dat	$\begin{array}{l} 2.7 \ \text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	0	305	0	305	0	305	ns
		$\label{eq:linear} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$	0	355	0	355	0	355	ns
		1.8 V ≤ EV _{DD0} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	0	405	ns
		$\begin{array}{l} 1.7 \ V \leq EV_{DD0} \leq 1.8 \ V, \\ C_{b} = 100 \ pF, \ R_{b} = 5 \ k\Omega \end{array}$	0	405	0	405	0	405	ns
		$1.6 \text{ V} \le \text{EV}_{\text{DD0}} < 1.8 \text{ V},$ C _b = 100 pF, R _b = 5 kΩ	-	-	0	405	0	405	ns

(5) During communication at same potential (simplified I²C mode) (2/2) (T_A = -40 to +85°C. 1.6 V \leq EV_{DD} \leq V_{DD} \leq 3.6 V. V_{SS} = EV_{SS0} = 0 V)

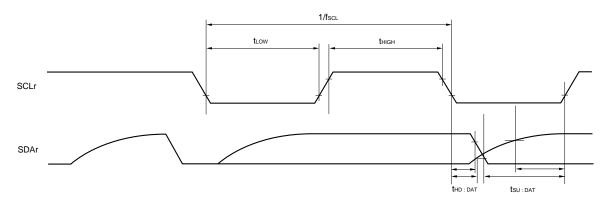
Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. The value must also be fcLk/4 or lower.
- 5. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".
- Caution Select the normal input buffer and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).

Simplified I²C mode mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



Remarks 1. R_b[Ω]: Communication line (SDAr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance

- **2.** r: IIC number (r = 00, 01, 10, 11, 20, 21), g: PIM number (g = 0, 1), h: POM number (h = 0, 1)
- fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number, mn = 00 to 03, 10, 11)

(6) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (1/2)

Parameter	Symbol		Conditions		HS ^{Note 1}		LS ^{Note 2}		LV ^{Note 3}		Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer		Reception	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V,$			fмск/6		fмск/6		fмск/6	bps
rate ^{Note 4}				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 7}$		5.3		1.3		0.6	Mbps
			$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$			fмск/6		fмск/6		fмск/6	bps
			$1.6~V \leq V_b \leq 2.0~V^{\text{Note 5}}$	Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 7}$		5.3 Note 6		1.3		0.6	Mbps

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - **4.** Transfer rate in the SNOOZE mode is 4800 bps.
 - 5. Use it with $EV_{DD0} \ge V_b$.
 - 6. The following conditions are required for low-voltage interface when EVDD0 < VDD.
 - $2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 2.7 \text{ V}$: MAX. 2.6 Mbps
 - $1.8~V \leq EV_{\text{DD0}}$ < 2.4 V : MAX. 1.3 Mbps
 - 7. fclk in each operating mode is as below.
 - HS (high-speed main) mode: fclk = 32 MHz
 - LS (low-speed main) mode: fclk = 8 MHz
 - LV (low-voltage main) mode: fcLK = 4 MHz
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** $V_{b}[V]$: Communication line voltage
 - **2.** q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10, 11)



[bps]

(6) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (2/2)

$(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V},$	Vss = EVsso = 0 V)
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Parameter	Symbol		Conditions		HS	Note 1	LS	Note 2	LV ^{Note 3}		Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer		Transmission	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V,$			Note 4		Note 4		Note 4	bps
rate			$2.3 V \le V_b \le 2.7 V$	Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 2.7 k Ω , V_b = 2.3 V		1.2 Note 5		1.2 Note 5		1.2 Note 5	Mbps
			$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$			Note 7		Note 7		Note 7	bps
			$1.6~V \leq V_b \leq 2.0~V^{\text{Note 6}}$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$		0.43 Note 8		0.43 Note 8		0.43 Note 8	Mbps

Notes 1. HS is condition of HS (high-speed main) mode.

- **2.** LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- **4.** The smaller maximum transfer rate derived by using f_{MCK}/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD0} \leq 3.6 V and 2.3 V \leq V_b \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

$$Baud rate error (theoretical value) = \frac{1}{\frac{1}{Transfer rate \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\}}{(\frac{1}{(Transfer rate}) \times Number of transferred bits} \times 100 [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- 5. This value as an example is calculated when the conditions described in the "Conditions" column are met. See **Note 4** above to calculate the maximum transfer rate under conditions of the customer.
- 6. Use it with $EV_{DD0} \ge V_b$.
- **7.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

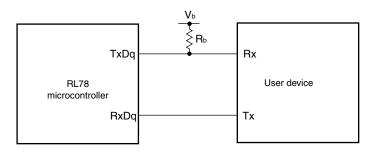
Expression for calculating the transfer rate when 1.8 V \leq EV_{DD0} < 3.3 V and 1.6 V \leq V_b \leq 2.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$

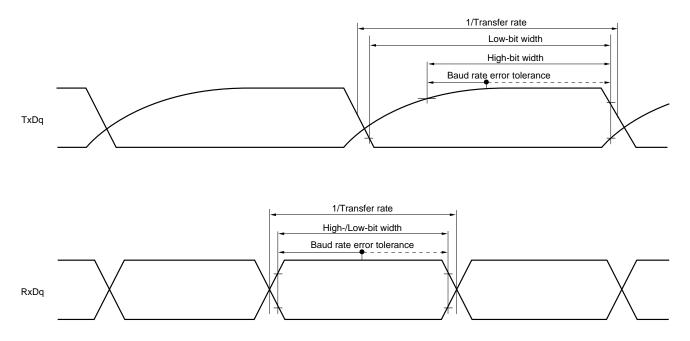
Baud rate error (theoretical value) = $\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$

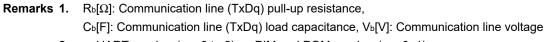
- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **8.** This value as an example is calculated when the conditions described in the "Conditions" column are met. See **Note 7** above to calculate the maximum transfer rate under conditions of the customer.
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)





2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

3. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))



(7) Communication at different potential (2.5 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

Parameter	Symbol	Conditions		HS ^N	lote 1	LSN	ote 2	LV ^{No}	ote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t ксү1	$\label{eq:2.7} \begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 20 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	tĸcy1 ≥ 2/fc∟ĸ	300		1150		1150		ns
SCKp high-level width	tкнı	$\label{eq:constraint} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{DD0} \leq 3.6 \mbox{ V}, 2.3 \mbox{ V} \\ C_b = 20 \mbox{ pF}, \mbox{ R}_b = 2.7 \mbox{ k}\Omega \end{array}$	$V \le V_b \le 2.7 V$,	tксү1/2 – 120		tксү1/2 – 120		tксү1/2 – 120		ns
SCKp low-level width	t KL1	$\begin{array}{l} 2.7 \ \text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \ \text{V}, 2.3 \ \text{V} \\ \text{C}_{\text{b}} = 20 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	$V \le V_b \le 2.7 V$,	tксү1/2 – 10		tксү1/2 – 50		tксү1/2 – 50		ns
SIp setup time (to SCKp↑) ^{Note 4}	tsik1	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V}$ $C_b = 20 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$V \le V_b \le 2.7 V$,	121		479		479		ns
SIp hold time (from SCKp↑) ^{Note 4}	t _{KSI1}	$\begin{array}{l} 2.7 \ V \leq E V_{DD0} \leq 3.6 \ V, \ 2.3 \ V \\ C_b = 20 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	$V \le V_b \le 2.7 V$,	10		10		10		ns
Delay time from SCKp↓ to SOp output ^{Note 4}	tkso1	$\label{eq:constraint} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{DD0} \leq 3.6 \mbox{ V}, 2.3 \mbox{ V} \\ C_b = 20 \mbox{ pF}, \mbox{ R}_b = 2.7 \mbox{ k}\Omega \end{array}$	$V \le V_b \le 2.7 V$,		130		130		130	ns
SIp setup time (to SCKp↓) ^{Note 5}	tsik1	$\label{eq:constraint} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{DD0} \leq 3.6 \mbox{ V}, 2.3 \mbox{ V} \\ C_b = 20 \mbox{ pF}, \mbox{ R}_b = 2.7 \mbox{ k}\Omega \end{array}$	$V \le V_b \le 2.7 V$,	33		110		110		ns
SIp hold time (from SCKp↓) ^{Note 5}	tksi1	$\label{eq:constraint} \begin{array}{l} 2.7 \mbox{ V} \leq EV_{DD0} \leq 3.6 \mbox{ V}, 2.3 \mbox{ V} \\ C_b = 20 \mbox{ pF}, \mbox{ R}_b = 2.7 \mbox{ k}\Omega \end{array}$	$V \leq V_b \leq 2.7 V$,	10		10		10		ns
Delay time from SCKp↑ to SOp output ^{Note 5}	tkso1	$\begin{array}{l} 2.7 \ V \leq E V_{DD0} \leq 3.6 \ V, \ 2.3 \ V \\ C_b = 20 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	$V \leq V_b \leq 2.7 V$,		10		10		10	ns

 $(T_A = -40 \text{ to } +85^{\circ}C, 2.7 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, \text{ V}_{SS} = EV_{SS0} = 0 \text{ V})$

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
- 5. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 1)



(8) Communication at different potential (1.8V, 2.5 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (1/2)

Parameter	Symbol	Conditions		HS [№]	ote 1	LSN	ote 2	LVN	ote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t ксү1			500		1150		1150		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 4}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	tксү1 ≥ 4/fc∟к	1150		1150		1150		ns
SCKp high-level width	tкнı	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \ 2.3 \ V \leq \\ C_{b} = 30 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	≤ V _b ≤ 2.7 V,	tксү1/2 – 170		tксү1/2 – 170		tксү1/2 – 170		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq \\ ^{4}, \\ C_{b} = 30 \ pF, \ R_{b} = 5.5 \ k\Omega \end{array}$	$\leq V_b \leq 2.0 \ V^{\text{Note}}$	tксү1/2 – 458		tксү1/2 – 458		tксү1/2 – 458		ns
SCKp low-level width	tĸ∟1	$\label{eq:linear} \begin{split} 2.7 \ V &\leq EV_{\text{DD0}} \leq 3.6 \ \text{V}, \ 2.3 \ \text{V} \leq V_b \leq 2.7 \ \text{V}, \\ C_b &= 30 \ \text{pF}, \ R_b = 2.7 \ \text{k}\Omega \end{split}$		tксү1/2 – 18		tксү1/2 — 50		tксү1/2 — 50		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq \\ ^{4}, \\ C_{b} = 30 \ pF, \ R_{b} = 5.5 \ k\Omega \end{array}$	$\leq V_b \leq 2.0 V^{Note}$	tксү1/2 – 50		tксү1/2 – 50		tксү1/2 – 50		ns

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- **3.** LV is condition of LV (low-voltage main) mode.
- **4.** Use it with $EV_{DD0} \ge V_b$.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 20), m: Unit number , n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.



(8) Communication at different potential (1.8 V, 2.5 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/2)

Parameter	Symbol	Conditions	HS	Note 1	LS	Note 2	L۷	Note 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) ^{Note 4}	tsik1	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 30 \ pF, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$	177		479		479		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \\ {}^{6}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	479		479		479		ns
SIp hold time (from SCKp↑) ^{Note 4}	tksi1	$\begin{array}{l} \hline c_b = 30 \ \text{pr}, \ \text{Nb} = 3.3 \ \text{K} 2 \\ \hline 2.7 \ \text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \ \text{V}, \ 2.3 \ \text{V} \leq \text{V}_b \leq 2.7 \ \text{V}, \\ \hline c_b = 30 \ \text{pF}, \ \text{R}_b = 2.7 \ \text{k} \Omega \end{array}$	19		19		19		ns
		$ \begin{array}{l} 1.8 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V^{\text{Note}} \\ {}^{\text{6}}, \\ C_{\text{b}} = 30 \ \text{pF}, \ R_{\text{b}} = 5.5 \ \text{k}\Omega \end{array} $	19		19		19		ns
Delay time from SCKp↓ to SOp output ^{Note 4}	tkso1	$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ C_{b} = 30 \; pF, \; R_{b} = 2.7 \; k\Omega \end{array}$		195		195		195	ns
		$\label{eq:VDD} \begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \\ {}^{6}, \\ C_b = 30 \ p\text{F}, \ R_b = 5.5 \ k\Omega \end{array}$		483		483		483	ns
SIp setup time (to SCKp↓) ^{Note 5}	tsik1	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 30 \ pF, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$	44		110		110		ns
			110		110		110		ns
SIp hold time (from SCKp↓) ^{Note 5}	tksi1	$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ C_{b} = 30 \; pF, \; R_{b} = 2.7 \; k\Omega \end{array}$	19		19		19		ns
		$\label{eq:Vote} \begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \\ {}^{6}, \\ C_b = 30 \ p\text{F}, \ R_b = 5.5 \ k\Omega \end{array}$	19		19		19		ns
Delay time from SCKp↑ to SOp output ^{Note 5}	tĸso1	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		25		25		25	ns
		$\label{eq:VDD} \begin{array}{l} 1.8 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}} \\ \ensuremath{\mathfrak{6}}, \\ C_b = 30 \ p\text{F}, \ R_b = 5.5 \ k\Omega \end{array}$		25		25		25	ns

1	$T_{A} = -40$ to +85°C	$1.8 V < EV_{DD0} < V$	Vnn < 3 6 V	Vss = EVsso = 0 V)
	TA40 10 +05 C	, I.O V \leq EVDDU \leq '	vuu ≤ 3.0 v,	$v_{55} - Ev_{550} - Uv)$

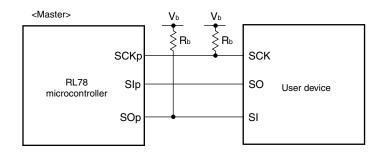
Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- **3.** LV is condition of LV (low-voltage main) mode.
- 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
- 5. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **6.** Use it with $EV_{DD0} \ge V_b$.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

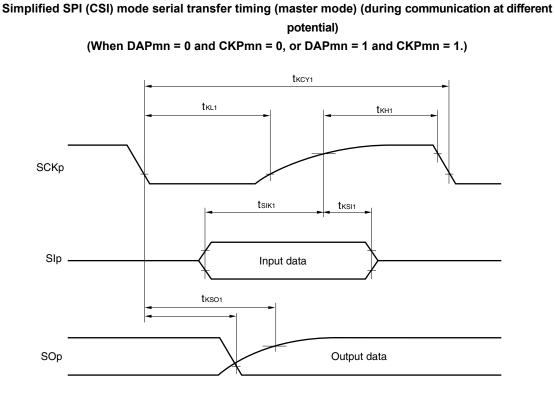


Simplified SPI (CSI) mode connection diagram (during communication at different potential)

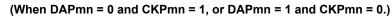


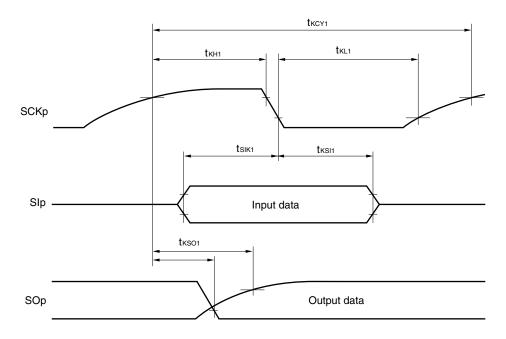
- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 20), m: Unit number , n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.





Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential)





- **Remarks 1.** p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (m = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **2.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

RENESAS

(9) Communication at different potential (1.8 V, 2.5 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Cond	ditions	HS'	Note 1	LS	lote 2	L۷	Note 3	Uni
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time ^{Note 4}	t ксү2	$2.7~V \leq EV_{DD0} \leq 3.6~V,$	24 MHz < fмск	20/fмск		-		-		ns
		$2.3V{\leq}V_b{\leq}2.7V$	20 MHz < fмск≤24 MHz	16/ f мск		-		_		ns
			16 MHz < fмск≤20 MHz	14/ f мск		-		_		ns
			8 MHz < fмск≤ 16 MHz	12/fмск		_		_		ns
			4 MHz < fмск≤8 MHz	8/fмск		16/fмск		-		ns
			fмск≤4 MHz	6/ f мск		10/f мск		10/fмск		ns
		$1.8 V \le EV_{DD0} < 3.3 V$,	24 MHz < fмск	48/fмск		_		_		ns
		$1.6V\!\le\!V_{b}\!\le\!2.0V^{Note5}$	20 MHz < fмск≤24 MHz	36/f мск		_		_		ns
			16 MHz < fмск≤ 20 MHz	32/fмск		_		_		ns
			8 MHz < fмск≤ 16 MHz	26/fмск		_		-		ns
			4 MHz < fмcк≤8 MHz	16/fмск		16/fмск		_		ns
			fмск ≤ 4 MHz	10/ f мск		10/f мск		10/fмск		ns
SCKp high-/low-level width	tкн2, tкL2	$2.7~V \leq EV_{DD0} \leq 3.6~V$, 2.3 V \le Vb \le 2.7 V	tксү2/2 – 18		tксү2/2 - 50		tксү2/2 - 50		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V^{\text{Note}} \\ _{\text{5}} \end{array}$		tксү2/2 - 50		tксү2/2 - 50		tксү2/2 - 50		ns
Slp setup time (to SCKp↑) ^{Note 6}	tsıĸ2	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$, 2.3 V \leq V _b \leq 2.7 V	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		1.8 V ≤ EV _{DD0} < 3.3 V ₅	, 1.6 V \leq V _b \leq 2.0 V ^{Note}	1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
SIp hold time (from SCKp↑) ^{Note 6}	tksi2			1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
Delay time from SCKp↓ to SOp output ^{Note 7}	tĸso2	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}$			2/fмск + 214		2/fмск + 573		2/fмск + 573	ns
		1.8 V \leq EV _{DD0} < 3.3 V 5, C _b = 30 pF, R _b = 5.5 k	$V_{\rm b} \le 1.6 \ V \le V_{\rm b} \le 2.0 \ V^{\rm Note}$		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns

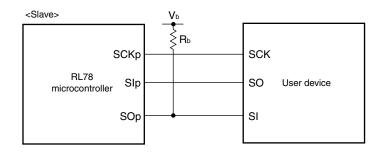
A \ /

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. Transfer rate in the SNOOZE mode : MAX. 1 Mbps
- **5.** Use it with $EV_{DD0} \ge V_b$.
- 6. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 7. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp⁺ when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VL, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

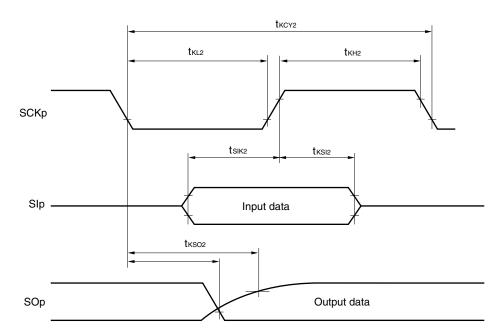
Simplified SPI (CSI) mode connection diagram (during communication at different potential)



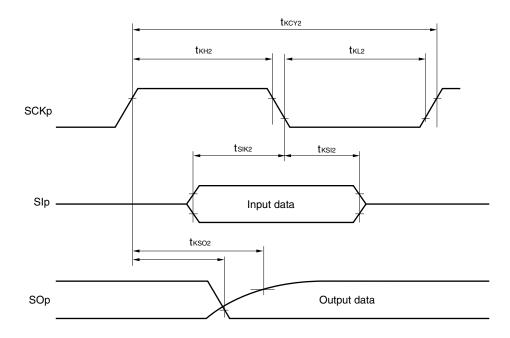
- **Remarks 1.** R_b[Ω]: Communication line (SOp) pull-up resistance, C_b[F]: Communication line (SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 20), m: Unit number (m = 0, 1), n: Channel number (n = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - fMCK: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00, 02, 10))
 - **4.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



- **Remarks 1.** p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **2.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(10) Communication at different potential (1.8 V, 2.5 V) (simplified l²C mode) (1/2) (T_A = -40 to +85°C, 1.8 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, Vss = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions	HS	Note 1	LS	Note 2	LV	Note 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fsc∟	$\label{eq:2.7} \begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		1000 ^{Note 4}		300 ^{Note} 4		300 ^{Note} 4	kHz
		$\label{eq:2.7} \begin{split} & 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ & 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ & C_{b} = 100 \; pF, \; R_{b} = 2.7 \; k\Omega \end{split}$		400 ^{Note} 4		300 ^{Note} 4		300 ^{Note} 4	kHz
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note 5}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k\Omega \end{split}$		300 ^{Note} 4		300 ^{Note} 4		300 ^{Note} 4	kHz
Hold time when SCLr = "L"	t∟ow	$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	475		1550		1550		ns
		$\label{eq:2.7} \begin{split} & 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ & 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ & C_{b} = 100 \; pF, \; R_{b} = 2.7 \; k\Omega \end{split}$	1150		1550		1550		ns
		$\begin{split} & 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \\ & 1.6 \ V \leq V_{b} \leq 2.0 \ V^{Note 5}, \\ & C_{b} = 100 \ pF, \ R_{b} = 5.5 \ k\Omega \end{split}$	1550		1550		1550		ns
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	200		610		610		ns
		$\label{eq:2.7} \begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 100 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	600		610		610		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_{b} \leq 2.0 \ V^{Note 5}, \\ C_{b} &= 100 \ pF, \ R_{b} = 5.5 \ k\Omega \end{split}$	610		610		610		ns

(Notes, Caution and Remarks are listed on the next page.)



Parameter	Symbol	Conditions	HS	Note 1	LS [№]	lote 2	LVN	lote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data setup time (reception)	tsu:dat	$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	1/f _{MCK} + 135 ^{Note} 6		1/f _{MCK} + 190 ^{Note 6}		1/f _{MCK} + 190 ^{Note} 6		ns
		$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 100 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	1/fмск + 190 ^{Note} 6		1/f _{мск} + 190 ^{Note 6}		1/f _{мск} + 190 ^{Note} 6		ns
		$ \begin{split} & 1.8 \; V \leq EV_{DD0} < 3.3 \; V, \\ & 1.6 \; V \leq V_{b} \leq 2.0 \; V^{Note\; 5}, \\ & C_{b} = 100 \; pF, \; R_{b} = 5.5 \; k\Omega \end{split} $	1/f _{MCK} + 190 ^{Note} 6		1/f _{МСК} + 190 ^{Note 6}		1/f _{MCK} + 190 ^{Note} 6		ns
Data hold time (transmission)	thd:dat	$\label{eq:2.7} \begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	0	305	0	305	0	305	ns
		$\begin{array}{l} 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 100 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	0	355	0	355	0	355	ns
		$ \begin{split} & 1.8 \; V \leq EV_{DD0} < 3.3 \; V, \\ & 1.6 \; V \leq V_{b} \leq 2.0 \; V^{Note 5}, \\ & C_{b} = 100 \; pF, \; R_{b} = 5.5 \; k\Omega \end{split} $	0	405	0	405	0	405	ns

(10) Communication at different potential (1.8 V, 2.5 V) (simplified I²C mode) (2/2) (T_A = -40 to +85°C. 1.8 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V. V_{SS} = EV_{SS0} = 0 V)

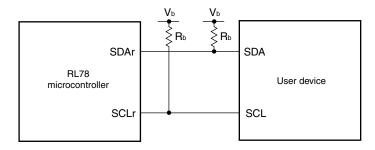
Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- 4. The value must also be fclk/4 or lower.
- **5.** Use it with $EV_{DD0} \ge V_b$.
- 6. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".
- Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SDAr pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

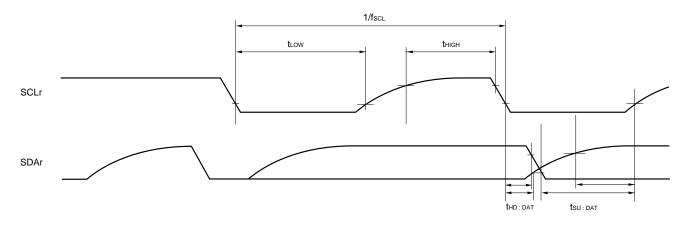
(Remarks are listed on the next page.)



Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** R_b[Ω]: Communication line (SDAr, SCLr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance, V_b[V]: Communication line voltage
 - **2.** r: IIC number (r = 00, 10, 20), g: PIM, POM number (g = 0, 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10)
 - **4.** IIC01, IIC11, and IIC21 cannot communicate at different potential. Use IIC00, IIC10, or IIC20 for communication at different potential.



2.5.2 Serial interface IICA

(1) I²C standard mode

(TA = -40 to +85°C, 1.6 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V)

Parameter	Symbol	Conditions		St	andard	Mode ^{No}	te 1		Unit
			HS	Note 2	LS	lote 3	L۷	Note 4	
			MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	0	100	0	100	0	100	kHz
		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	0	100	0	100	0	100	
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	0	100	0	100	0	100	
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	-		0	100	0	100	
Setup time of restart condition	tsu:sta	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		μs
		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		
		$1.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	4.7		4.7		4.7		
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	-		4.7		4.7		
Hold time ^{Note 5}	thd:sta	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		μs
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		
		$1.6~V \leq EV_{\text{DD0}} \leq 3.6~V$	-		4.0		4.0		
Hold time when SCLA0 = "L"	t LOW	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		μs
		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		
		$1.6~V \leq EV_{\text{DD0}} \leq 3.6~V$	-		4.7		4.7		
Hold time when SCLA0 = "H"	tніgн	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		μs
		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		
		$1.6~V \leq EV_{\text{DD0}} \leq 3.6~V$	-		4.0		4.0		
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{DD0} \leq 3.6~V$	250		250		250		ns
		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	250		250		250		
		$1.7~V \leq EV_{DD0} \leq 3.6~V$	250		250		250		
		$1.6~V \leq EV_{DD0} \leq 3.6~V$	-		250		250		
Data hold time (transmission) ^{Note 6}	thd:dat	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	0	3.45	0	3.45	0	3.45	μs
		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	0	3.45	0	3.45	0	3.45	
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	0	3.45	0	3.45	0	3.45	
		$1.6 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	-	-	0	3.45	0	3.45	
Setup time of stop condition	tsu:sto	$2.7~V \leq EV_{DD0} \leq 3.6~V$	4.0		4.0		4.0		μs
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.0		4.0		4.0		
		$1.6 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	-		4.0		4.0		
Bus-free time	t BUF	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		μs
		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		
		$1.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	4.7		4.7		4.7		
		$1.6 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V}$	_		4.7		4.7		

(Note and Remark are listed on the next page.)

Parameter	Symbol	Conditions			Fast Mo	ode ^{Note 7}				Mode Note 8	Unit
			HS	Note 2	LS	lote 3	LV	lote 4	HS	Note 2	
			MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	0	400	0	400	0	400	0	1000	kHz
		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	0	400	0	400	0	400	-		
Setup time of restart	tsu:sta	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		0.26		μs
condition		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		-		
Hold time ^{Note 5}	thd:sta	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		0.26		μs
		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		-		
Hold time when SCLA0	t∟ow	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	1.3		1.3		1.3		0.5		μs
= "L"		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	1.3		1.3		1.3		_		
Hold time when SCLA0	tніgн	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		0.26		μs
= "H"		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		_		
Data setup time	tsu:dat	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	100		100		100		50		ns
(reception)		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	100		100		100		_		
Data hold time	thd:dat	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	0	0.9	0	0.9	0	0.9	0	450	μs
(transmission) ^{Note 6}		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	0	0.9	0	0.9	0	0.9	_		
Setup time of stop	tsu:sto	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		0.26		μs
condition		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	0.6		0.6		0.6		-		
Bus-free time	t BUF	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	1.3		1.3		1.3		0.5		μs
		$1.8~V \leq EV_{\text{DD0}} \leq 3.6~V$	1.3		1.3		1.3		_		

(2) I²C fast mode, fast mode plus

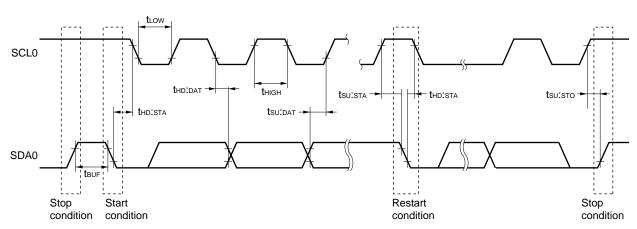
$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Notes 1. In normal mode, use it with fcLK \ge 1 MHz, 1.6 V \le EVDD \le 3.6 V.

- 2. HS is condition of HS (high-speed main) mode.
- **3.** LS is condition of LS (low-speed main) mode.
- 4. LV is condition of LV (low-voltage main) mode.
- 5. The first clock pulse is generated after this period when the start/restart condition is detected.
- 6. The maximum value (MAX.) of the during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.
- 7. In fast mode, use it with fcLK \ge 3.5 MHz, 1.8 V \le EVDD \le 3.6 V.
- 8. In fast mode plus, use it with fcLK \ge 10 MHz, 2.7 V \le EVDD \le 3.6 V.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

 $Standard mode: C_b = 400 \text{ pF}, R_b = 2.7 \text{ k}\Omega \\ Fast mode: C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega \\ Fast mode plus: C_b = 120 \text{ pF}, R_b = 1.1 \text{ k}\Omega \\$



IICA serial transfer timing



2.6 Analog Characteristics

2.6.1 A/D converter characteristics

Division of A/D Converter Characteristics

Reference voltag	Reference voltage (+) = AV _{REFP} Reference voltage (-) = AV _{REFM}	Reference voltage (+) = AV _{DD} Reference voltage (-) = AV _{SS}	Reference voltage (+) = Internal refrence voltage Reference voltage (-) = AVss
High-accuracy channel; ANI0 to ANI12 (input buffer power supply: AV _{DD})	See 2.6.1 (1) See 2.6.1 (2)	See 2.6.1 (3)	See 2.6.1 (6)
Standard channel; ANI16 to ANI30 (input buffer power supply: Vbb or EVbbo)	See 2.6.1 (4)	See 2.6.1 (5)	
Temperature sensor, internal reference voltage output	See 2.6.1 (4)	See 2.6.1 (5)	-

(1) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{REFP} \le \text{AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V}, \text{AV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V}, \text{HALT mode})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res				12	bit
Overall error ^{Notes 1, 2, 3}	AINL	12-bit resolution		±1.7	±3.3	LSB
Conversion time	tconv	ADTYP = 0, 12-bit resolution	3.375			μs
Zero-scale error ^{Notes 1, 2, 3}	Ezs	12-bit resolution		±1.3	±3.2	LSB
Full-scale error ^{Notes 1, 2, 3}	Efs	12-bit resolution		±0.7	±2.9	LSB
Integral linearity errorNotes 1, 2, 3	ILE	12-bit resolution		±1.0	±1.4	LSB
Differential linearity error ^{Notes 1, 2, 3}	DLE	12-bit resolution		±0.9	±1.2	LSB
Analog input voltage	VAIN		0		AVREFP	V

- **Notes 1.** TYP. Value is the average value at $AV_{DD} = AV_{REFP} = 3 V$ and $T_A = 25^{\circ}C$. MAX. value is the average value $\pm 3\sigma$ at normalized distribution.
 - 2. These values are the results of characteristic evaluation and are not checked for shipment.
 - **3.** Excludes quantization error ($\pm 1/2$ LSB).
- Cautions 1. Route the wiring so that noise will not be superimposed on each power line and ground line, and insert a capacitor to suppress noise. In addition, separate the reference voltage line of AV_{REFP} from the other power lines to keep it free from the influences of noise.
 - 2. During A/D conversion, keep a pulse, such as a digital signal, that abruptly changes its level from being input to or output from the pins adjacent to the converter pins and P20 to P27 and P150 to P154.

(2) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{ V}_{\text{SS}} = 0 \text{ V}, \text{ AV}_{\text{SS}} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{AV}_{\text{REFP}},$
Reference voltage (–) = AVREFM = 0 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	8		12	bit
			$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	8		10 ^{Note 1}	
			$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$		8 ^{Note 2}		
Overall errorNote 3	AINL	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±6.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.5	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	3.375			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	6.75			
		ADTYP = 0, 8-bit resolution ^{Note 2}	$1.6 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	13.5			
		ADTYP = 1,	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	2.5625			
		8-bit resolution	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	5.125			
			$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	10.25			
Zero-scale errorNote 3	Ezs	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±4.5	LSB
		10-bit resolution	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			±4.5	
		8-bit resolution	$1.6 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			±2.0	
Full-scale errorNote 3	Efs	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±4.5	LSB
		10-bit resolution	$1.8~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±4.5	
		8-bit resolution	$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	
Integral linearity errorNote 3	ILE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			±1.5	
		8-bit resolution	$1.6 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			±1.0	
Differential linearity errorNote 3	DLE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±1.5	LSB
		10-bit resolution	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			±1.5	
		8-bit resolution	$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±1.0	
Analog input voltage	VAIN			0		AVREFP	V

- 2. Cannot be used for lower 4 bit of ADCR register
- **3.** Excludes quantization error ($\pm 1/2$ LSB).



(3) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI0 to ANI12

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{ V}_{\text{SS}} = 0 \text{ V}, \text{ AV}_{\text{SS}} = 0 \text{ V}, \text{ Reference voltage (+) = AV}_{\text{DD}}, \text{ Reference voltage (+) = AV}_{\text{DD}}, \text{ Reference voltage (+) = AV}_{\text{DD}}$

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$	8		12	bit
			$1.8 \text{ V} \le AV_{\text{DD}} \le 3.6 \text{ V}$	8		10 ^{Note 1}	
			$1.6 \text{ V} \leq AV_{DD} \leq 3.6 \text{ V}$		8 ^{Note 2}		
Overall errorNote 3	AINL	12-bit resolution	$2.4 \text{ V} \le AV_{\text{DD}} \le 3.6 \text{ V}$			±7.5	LSB
		10-bit resolution	$1.8 \text{ V} \le AV_{\text{DD}} \le 3.6 \text{ V}$			±5.5	
		8-bit resolution	$1.6 \text{ V} \le AV_{\text{DD}} \le 3.6 \text{ V}$			±3.0	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4~V \leq AV_{DD} \leq 3.6~V$	3.375			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	$1.8 \text{ V} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	6.75			
		ADTYP = 0, 8-bit resolution ^{Note 2}	$1.6 \text{ V} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	13.5			
		ADTYP = 1,	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$	2.5625			
		8-bit resolution	$1.8 \text{ V} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	5.125			
			$1.6~V \leq AV_{\text{DD}} \leq 3.6~V$	10.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±6.0	LSB
		10-bit resolution	$1.8~V \leq AV_{\text{DD}} \leq 3.6~V$			±5.0	
		8-bit resolution	$1.6~V \leq AV_{\text{DD}} \leq 3.6~V$			±2.5	
Full-scale error ^{Note 3}	EFS	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±6.0	LSB
		10-bit resolution	$1.8~V \leq AV_{\text{DD}} \leq 3.6~V$			±5.0	
		8-bit resolution	$1.6~V \leq AV_{\text{DD}} \leq 3.6~V$			±2.5	
Integral linearity error ^{Note 3}	ILE	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±3.0	LSB
		10-bit resolution	$1.8~V \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	
		8-bit resolution	$1.6~V \leq AV_{\text{DD}} \leq 3.6~V$			±1.5	
Differential linearity error ^{Note 3}	DLE	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	LSB
		10-bit resolution	$1.8~V \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	
		8-bit resolution	$1.6~V \leq AV_{\text{DD}} \leq 3.6~V$			±1.5	
Analog input voltage	VAIN			0		AVDD	V

- 2. Cannot be used for lower 4 bit of ADCR register
- **3.** Excludes quantization error ($\pm 1/2$ LSB).



(4) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

$(T_{A} = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, 1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 $
V, Reference voltage (+) = AVREFP, Reference voltage (–) = AVREFM = 0 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	8		12	bit
			$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	8		10 ^{Note 1}	
			$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$		8 ^{Note 2}	•	
Overall error ^{Note 3}	AINL	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±7.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±5.5	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±3.0	
Conversion time	tсолу	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	4.125			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	9.5			
		ADTYP = 0, 8-bit resolution ^{Note 2}	$1.6 \text{ V} \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$	57.5			
		ADTYP = 1,	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$	3.3125			
		8-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$	7.875			
			$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	54.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±5.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.5	
Full-scale error ^{Note 3}	Ers	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±5.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.5	
Integral linearity error ^{Note 3}	ILE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±3.0	LSB
		10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.0	
		8-bit resolution	$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±1.5	
Differential linearity error ^{Note 3}	DLE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	LSB
		10-bit resolution	$1.8~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	
		8-bit resolution	$1.6~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±1.5	
Analog input voltage	VAIN			0		AVREFP and EVDD0	V
		Interanal reference voltage $(2.4 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{HS} (high-speed main) mode})$		V _{BGR} Note 4			V
		Temperature sensor (2.4 V \leq V _{DD} \leq 3.6 V,	output voltage HS (high-speed main) mode)	,	VTMPS25 ^{Note}	4	V

- 2. Cannot be used for lower 4 bit of ADCR register
- **3.** Excludes quantization error ($\pm 1/2$ LSB).
- 4. See 2.6.2 Temperature sensor, internal reference voltage output characteristics.

(5) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD0}} \le 3.6 \text{ V}, 1.6 \text{ V} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+) = AV}_{\text{DD}}, \text{Reference voltage (-) = AV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \le AV_{\text{DD}} \le 3.6~V$	8		12	bit
			$1.8~V \le AV_{\text{DD}} \le 3.6~V$	8		10 ^{Note 1}	
			$1.6~V \le AV_{\text{DD}} \le 3.6~V$		8 ^{Note 2}		
Overall error ^{Note 3}	AINL	12-bit resolution	$2.4~V \le AV_{\text{DD}} \le 3.6~V$			±8.5	LSB
		10-bit resolution	$1.8~V \le AV_{\text{DD}} \le 3.6~V$			±6.0	
		8-bit resolution	$1.6~V \le AV_{\text{DD}} \le 3.6~V$			±3.5	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$	4.125			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	$1.8~V \le AV_{\text{DD}} \le 3.6~V$	9.5			
		ADTYP = 0, 8-bit resolution ^{Note 2}	$1.6~V \le AV_{\text{DD}} \le 3.6~V$	57.5			
		ADTYP = 1,	$2.4~V \le AV_{\text{DD}} \le 3.6~V$	3.3125			μs
		8-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	7.875			
			$1.6~V \le AV_{DD} \le 3.6~V$	54.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4~V \le AV_{\text{DD}} \le 3.6~V$			±8.0	LSB
		10-bit resolution	$1.8~V \le AV_{\text{DD}} \le 3.6~V$			±5.5	
		8-bit resolution	$1.6~V \le AV_{\text{DD}} \le 3.6~V$			±3.0	
Full-scale error ^{Note 3}	Ers	12-bit resolution	$2.4~V \le AV_{DD} \le 3.6~V$			±8.0	LSB
		10-bit resolution	$1.8~V \le AV_{\text{DD}} \le 3.6~V$			±5.5	
		8-bit resolution	$1.6~V \leq AV_{\text{DD}} \leq 3.6~V$			±3.0	
Integral linearity errorNote 3	ILE	12-bit resolution	$2.4~V \le AV_{DD} \le 3.6~V$			±3.5	LSB
		10-bit resolution	$1.8~V \le AV_{DD} \le 3.6~V$			±2.5	
		8-bit resolution	$1.6~V \le AV_{DD} \le 3.6~V$			±1.5	
Differential linearity error ^{Note 3}	DLE	12-bit resolution	$2.4~V \le AV_{DD} \le 3.6~V$			±2.5	LSB
		10-bit resolution	$1.8~V \le AV_{DD} \le 3.6~V$			±2.5	
		8-bit resolution	$1.6~V \le AV_{\text{DD}} \le 3.6~V$			±2.0	
Analog input voltage	Vain			0		AV _{DD} and EV _{DD0}	V
		Interanal reference volt (2.4 V \leq V _{DD} \leq 3.6 V, H	age S (high-speed main) mode)	V _{BGR} Note 4			V
		Temperature sensor of (2.4 V \leq V _{DD} \leq 3.6 V, H	utput voltage S (high-speed main) mode)	,	VTMPS25 ^{Note}	4	V

- 2. Cannot be used for lower 4 bit of ADCR register
- **3.** Excludes quantization error (±1/2 LSB).
- 4. See 2.6.2 Temperature sensor, internal reference voltage output characteristics.



(6) When reference voltage (+) = Internal reference voltage (1.45 V) (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVss (ADREFM = 0), target ANI pin: ANI0 to ANI12, ANI16 to ANI30

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, 1.6 \text{ V} \le \text{EV}_{DD} \le \text{V}_{DD}, 1.6 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V}, \text{AV}_{SS} = 0 \text{ V}, \text{Reference voltage (+) = Internal reference voltage, Reference voltage (-) = AV}_{SS} = 0 \text{ V}, \text{HS (high-speed main) mode)}$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		8			bit
Conversion time	t CONV	8-bit resolution	16			μs
Zero-scale error ^{Note}	Ezs	8-bit resolution			±4.0	LSB
Integral linearity error ^{Note}	ILE	8-bit resolution			±2.0	LSB
Differential linearity error ^{Note}	DLE	8-bit resolution			±2.5	LSB
Reference voltage (+)	AV _{REF(+)}	= Internal reference voltage (V _{BGR})	1.38	1.45	1.5	V
Analog input voltage	VAIN		0		VBGR	V

Note Excludes quantization error ($\pm 1/2$ LSB).

2.6.2 Temperature sensor, internal reference voltage output characteristics

· · ·			,			
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, T_A = +25°C		1.05		V
Internal reference voltage	VBGR	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	Fvtmps	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tамр		10			μs

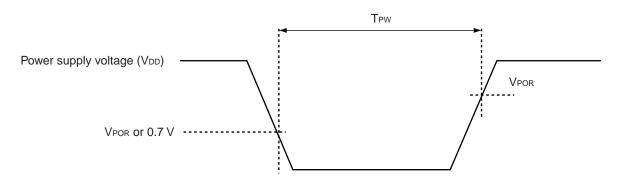
$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V}, \text{HS (high-speed main) mode)}$

2.6.3 POR circuit characteristics

 $(T_A = -40 \text{ to } +85^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	Power supply rise time 1		1.51	1.55	V
	VPDR	Power supply fall time	1.46	1.50	1.54	V
Minimum pulse width ^{Note}	Tpw		300			μs

Note This is the time required for the POR circuit to execute a reset when V_{DD} falls below V_{PDR}. When the microcontroller enters STOP mode or if the main system clock (f_{MAIN}) has been stopped by setting bit 0 (HIOSTOP) and bit 7 (MSTOP) of the clock operation status control register (CSC), this is the time required for the POR circuit to execute a reset before V_{DD} rises to V_{POR} after having fallen below 0.7 V.





2.6.4 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection Supply voltage level	VLVD2	Power supply rise time	3.07	3.13	3.19	V	
voltage	voltage		Power supply fall time	3.00	3.06	3.12	V
		VLVD3	Power supply rise time	2.96	3.02	3.08	V
			Power supply fall time	2.90	2.96	3.02	V
		VLVD4	Power supply rise time	2.86	2.92	2.97	V
			Power supply fall time	2.80	2.86	2.91	V
		VLVD5	Power supply rise time	2.76	2.81	2.87	V
			Power supply fall time	2.70	2.75	2.81	V
		VLVD6	Power supply rise time	2.66	2.71	2.76	V
			Power supply fall time	2.60	2.65	2.70	V
		VLVD7	Power supply rise time	2.56	2.61	2.66	V
		Power supply fall time	2.50	2.55	2.60	V	
		VLVD8	Power supply rise time	2.45	2.50	2.55	V
			Power supply fall time	2.40	2.45	2.50	V
		VLVD9	Power supply rise time	2.05	2.09	2.13	V
			Power supply fall time	2.00	2.04	2.08	V
		VLVD10	Power supply rise time	1.94	1.98	2.02	V
			Power supply fall time	1.90	1.94	1.98	V
		VLVD11	Power supply rise time	1.84	1.88	1.91	V
			Power supply fall time	1.80	1.84	1.87	V
		VLVD12	Power supply rise time	1.74	1.77	1.81	V
			Power supply fall time	1.70	1.73	1.77	V
		VLVD13	Power supply rise time	1.64	1.67	1.70	V
			Power supply fall time	1.60	1.63	1.66	V
Minimum pu	Ilse width	t∟w		300			μs
Detection de	elay time					300	μs

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: V_{DD} = 2.7 to 3.6 V@1 MHz to 32 MHz V_{DD} = 2.4 to 3.6 V@1 MHz to 16 MHz LS (low-speed main) mode: V_{DD} = 1.8 to 3.6 V@1 MHz to 8 MHz

LV (low-voltage main) mode: VDD = 1.6 to 3.6 V@1 MHz to 4 MHz

LVD Detection Voltage of Interrupt & Reset Mode

(T _A = -40 to +	85°C, Vpdr ≤	\leq VDD \leq 3.6 V, Vss = 0 V)					
Parameter	Symbol	Con	ditions	MIN.	TYP.	MAX.	Unit
Interrupt & reset	VLVD13	VPOC2, VPOC1, VPOC0 =	0, 0, 0, falling reset voltage	1.60	1.63	1.66	V
mode	VLVD12	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.74	1.77	1.81	V
			Falling interrupt voltage	1.70	1.73	1.77	V
	VLVD11	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.84	1.88	1.91	V
			Falling interrupt voltage	1.80	1.84	1.87	V
	VLVD4	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.86	2.92	2.97	V
			Falling interrupt voltage	2.80	2.86	2.91	V
`	VLVD11	VPOC2, VPOC1, VPOC0 =	0, 0, 1, falling reset voltage	1.80	1.84	1.87	V
	VLVD10	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.02	V
			Falling interrupt voltage	1.90	1.94	1.98	V
	VLVD9	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V
			Falling interrupt voltage	2.00	2.04	2.08	V
	VLVD2	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	V
			Falling interrupt voltage	3.00	3.06	3.12	V
	VLVD8	VPOC2, VPOC1, VPOC0 =	0, 1, 0, falling reset voltage	2.40	2.45	2.50	V
	VLVD7	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.66	V
			Falling interrupt voltage	2.50	2.55	2.60	V
	VLVD6	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.76	V
			Falling interrupt voltage	2.60	2.65	2.70	V
	VLVD5	VPOC2, VPOC1, VPOC0 =	0, 1, 1, falling reset voltage	2.70	2.75	2.81	V
	VLVD4	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
			Falling interrupt voltage	2.80	2.86	2.91	V
	VLVD3	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.08	V
			Falling interrupt voltage	2.90	2.96	3.02	V

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: VDD = 2.7 to 3.6 V@1 MHz to 32 MHz

- VDD = 2.4 to 3.6 V@1 MHz to 16 MHz
- LS (low-speed main) mode: VDD = 1.8 to 3.6 V@1 MHz to 8 MHz

LV (low-voltage main) mode: VDD = 1.6 to 3.6 V@1 MHz to 4 MHz

2.6.5 Supply voltage rise slope characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SVDD				54	V/ms

Caution Be sure to maintain the internal reset state until V_{DD} reaches the operating voltage range specified

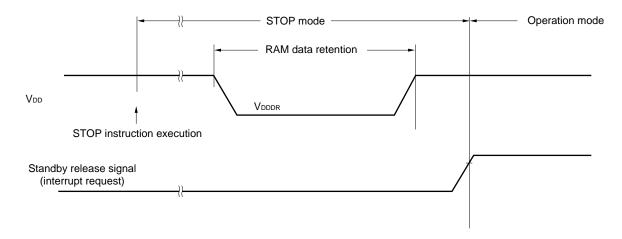
in 2.4 AC Characteristics, by using the LVD circuit or external reset pin.

2.7 RAM Data Retention Characteristics

(T _A = -40 to	o +85°C.	Vss =	0 V)
117 70 6	,,		••,

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 ^{Note}		3.6	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



2.8 Flash Memory Programming Characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	fclк	$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	1		32	MHz
Number of code flash rewrites ^{Notes 1, 2}	Cerwr	Retained for 20 years $T_A = 85^{\circ}C^{Note 3}$	1,000			Times
Number of data flash rewrites ^{Notes 1, 2}		Retained for 1 years T _A = $25^{\circ}C^{Note 3}$		1,000,000		
		Retained for 5 years T _A = $85^{\circ}C^{Note 3}$	100,000			
		Retained for 20 years $T_A = 85^{\circ}C^{Note 3}$	10,000			

1	TA = -4	40 to	+85°C,	181	/ <	Vnn	< 3.6	v	Vss =	0 V)
	IA	10 10	.05 0,	1.0		V DD	20.0	۰,	¥ 33 -	••,

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

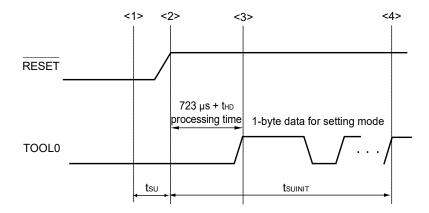
2.9 Dedicated Flash Memory Programmer Communication (UART)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115.2 k		1 M	bps

(TA = -40 to +85°C, 1.8 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVss0 = 0 V)

2.10 Timing Specs for Switching Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	tsuinit	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until a external reset ends	ts∪	POR and LVD reset must end before the external reset ends.	10			μs
How long the TOOL0 pin must be kept at the low level after an external reset ends (except flash firmware processing time)	tнo	POR and LVD reset must end before the external reset ends.	1			ms



- <1> The low level is input to the TOOL0 pin.
- <2> The pins reset ends (POR and LVD reset must end before the external reset ends.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.
 - $t_{\text{SU:}}$ How long from when the TOOL0 pin is placed at the low level until a external reset ends
 - thd: How long to keep the TOOL0 pin at the low level from when the external resets end (except flash firmware processing time)



3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS $T_A = -40$ to +105°C)

This chapter describes the following electrical specifications.

Target productsG:Industrial applicationsTA = -40 to +105°CR5F10EBAGNA, R5F10EBCGNA, R5F10EBDGNA, R5F10EBEGNAR5F10EGAGFB, R5F10EGCGFB, R5F10EGDGFB, R5F10EGEGFBR5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNAR5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB

- Cautions 1. The RL78/G1A has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EV_{DD0} or EV_{SS0} pin, replace EV_{DD0} with V_{DD}, or replace EV_{SS0} with V_{SS}.
 - Please contact Renesas Electronics sales office for derating of operation under T_A = +85°C to +105°C. Derating is the systematic reduction of load for the sake of improved reliability.
- **Remark** When RL78/G1A is used in the range of $T_A = -40$ to +85°C, see 2. **ELECTRICAL SPECIFICATIONS** ($T_A = -40$ to +85°C).



3.1 Absolute Maximum Ratings

Absolute Maximum Ratings (T_A = 25°C) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	Vdd		-0.5 to +6.5	V
	EVDD0		-0.5 to +6.5	V
	AVDD		-0.5 to +4.6	V
	AVREFP		-0.3 to AV _{DD} +0.3 ^{Note 3}	V
	EVsso		-0.5 to +0.3	V
	AVss		-0.5 to +0.3	V
	AVREFM		–0.3 to AV _{DD} +0.3 ^{Note 3} and AV _{REFM} ≤ AV _{REFP}	V
REGC pin input voltage	Viregc	REGC	-0.3 to +2.8 and -0.3 to V_{DD} +0.3 $^{\text{Note 1}}$	V
Input voltage	VI1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	-0.3 to EV_{DD0} +0.3 and -0.3 to V_{DD} +0.3 $^{\text{Note 2}}$	V
	Vı2	P60 to P63 (N-ch open-drain)	-0.3 to +6.5	V
	V _{I3}	P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} +0.3 ^{Note 2}	V
	V _{I4}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Output voltage	Vo1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	-0.3 to EV _{DD0} +0.3 ^{Note 2}	V
	V ₀₂	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Analog input voltage	Vaii	ANI16 to ANI30	-0.3 to EV_DD0 +0.3 and -0.3 to AV_{REF(+)} +0.3^{Notes 2, 4}	V
	Vai2	ANI0 to ANI12	-0.3 to AV _{DD} +0.3 and -0.3 to AV _{REF(+)} +0.3 ^{Notes 2, 4}	

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

- **2.** Must be 6.5 V or lower.
- 3. Must be 4.6 V or lower.
- 4. Do not exceed AV_{REF(+)} + 0.3 V in case of A/D conversion target pin.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - **2.** AV_{REF(+)}: + side reference voltage of the A/D converter.
 - 3. Vss: Reference voltage



Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	-40	mA
		Total of all pins –170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	-70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P70 to P77,	-100	mA
	Іон2	Per pin	P20 to P27, P150 to P154	-0.1	mA
		Total of all pins		-1.3	mA
Output current, low	lol1	Per pin	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	40	mA
		Total of all pins 170 mA	P00 to P04, P40 to P43, P120, P130, P140, P141	70	mA
			P05, P06, P10 to P16, P30, P31, P50, P51, P60 to P63, P70 to P77	100	mA
	IOL2	Per pin	P20 to P27, P150 to P154	0.4	mA
		Total of all pins		6.4	mA
Operating ambient	TA	In normal operation	on mode	-40 to +105	°C
temperature		In flash memory p	programming mode		
Storage temperature	Tstg			-65 to +150	°C

Absolute Maximum Ratings (T_A = 25°C) (2/2)

- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



3.2 Oscillator Characteristics

3.2.1 X1, XT1 oscillator characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/crystal resonator	$2.7~V \leq V_{\text{DD}} \leq 3.6~V$	1.0		20.0	MHz
frequency (fx) ^{Note}		$2.4~V \leq V_{\text{DD}} < 2.7~V$	1.0		16.0	
XT1 clock oscillation frequency (fx) ^{Note}	Crystal resonator		32	32.768	35	kHz

- **Note** Indicates only permissible oscillator frequency ranges. See AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.
- Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

3.2.2 On-chip oscillator characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator oscillation frequency ^{Notes 1, 2}	fін			1		32	MHz
High-speed on-chip oscillator oscillation frequency accuracy		+85 to +105 °C	$2.4~V \leq V_{\text{DD}} \leq 3.6~V$	-2		+2	%
		–20 to +85 °C	$2.4~V \leq V_{\text{DD}} \leq 3.6~V$	-1		+1	%
		–40 to –20 °C	$2.4~V \leq V_{\text{DD}} \leq 3.6~V$	-1.5		+1.5	%
Low-speed on-chip oscillator oscillation	fı∟				15		kHz
Low-speed on-chip oscillator oscillation frequency accuracy				-15		+15	%

- **Notes 1.** High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H/010C2H) and bits 0 to 2 of HOCODIV register.
 - 2. This indicates the oscillator characteristics only. See AC Characteristics for instruction execution time.



3.3 DC Characteristics

3.3.1 Pin characteristics

(T _A = -40 to +105	°C, 2.4 V ≤	$AV_{DD} \leq V_{DD} \leq 3.6 V, 2.4 V \leq EV_{DD0} \leq 3.6 V$	V DD \leq 3.6 V, Vss = EV	/sso = 0 '	V)		(1/5)
Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high ^{Note 1}	Іон1	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141	$2.4~V \leq EV_{DD0} \leq 3.6~V$			-3.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			-10.0	mA
		P130, P140, P141 (When duty ≤ 70% ^{Note 3})	$2.4~V \leq EV_{DD0} < 2.7~V$			-5.0	mA
		Total of P05, P06, P10 to P16, P30,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			-19.0	mA
		P31, P50, P51, P70 to P77, (When duty ≤ 70% ^{Note 3})	$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			-10.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$			-29.0	mA
	Іон2	Per pin for P20 to P27, P150 to P154	$2.4~\text{V} \leq AV_{\text{DD}} \leq 3.6~\text{V}$			-0.1 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$2.4 \text{ V} \leq AV_{\text{DD}} \leq 3.6 \text{ V}$			-1.3	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the EV_{DD0}, V_{DD} pins to an output pin.
 - 2. However, do not exceed the total current value.

 Specification under conditions where the duty factor ≤ 70%. The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

Total output current of pins = (Iон × 0.7)/(n × 0.01)
 <Example> Where n = 80% and Iон = -10.0 mA
 Total output current of pins = (-10.0 × 0.7)/(80 × 0.01) ≅ -8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

- Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



T _A = -40 to +10	<u>)5°C, 2.4 V</u>	\leq AVDD \leq VDD \leq 3.6 V, 2.4 V \leq EVDD	\leq VDD \leq 3.6 V, Vss =	EVsso =	0 V)	<u>г г</u>	(2/
Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low ^{Note 1}	Iol1	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141				8.5 ^{Note 2}	mA
		Per pin for P60 to P63				15.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			15.0	mA
		P130, P140, P141 (When duty ≤ 70% ^{Note 3})	$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			9.0	mA
		Total of P05, P06, P10 to P16, P30,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			35.0	mA
		P31, P50, P51, P60 to P63, P70 to P77 (When duty ≤ 70% ^{Note 3})	$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			20.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				50.0	mA
	IOL2	Per pin for P20 to P27, P150 to P154				0.4 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$2.4 \text{ V} \le AV_{\text{DD}} \le 3.6 \text{ V}$			5.2	mA

~ `^

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVsso and Vss pin.

- 2. However, do not exceed the total current value.
- **3.** Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the dury factor > 70% the duty ratio can can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = $(I_{OL} \times 0.7)/(n \times 0.01)$
- <Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins = $(10.0 \times 0.7)/(80 \times 0.01) \approx 8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(T _A = –40 to +10	5°C, 2.4 V	\leq AV DD \leq VDD \leq 3.6 V, 2.4 V \leq EV D	$DO \leq VDD \leq 3.6 V, VSS =$	= EVsso = ((3/5		
Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	Normal input buffer	0.8EVddo		EVDD0 EVDD0 EVDD0 AVDD AVDD 0.2EVDD0 0.3AVDD	V
	Symbol Conditions MIN. TYP. I v. P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141 Normal input buffer 0.8EVbdo E ViH2 P01, P03, P04, P10, P11, P13 to P16, P43 TTL input buffer 2.4 V ≤ EVbdo < 3.6 V	EVDD0	V				
				1.5		TYP. MAX. EVDD0 EVDD0 EVDD0 EVDD0 EVDD0 AVDD AVDD 6.0 VDD 0.2EVDD0 0.3EVDD0 0.32	V
Items Symbol Input voltage, high VIH1 P00 to P06, P10 to P P40 to P43, P50, P5 P120, P140, P141 VIH2 P01, P03, P04, P10, P13 to P16, P43 VIH2 P01, P03, P04, P10, P13 to P16, P43 VIH3 P20 to P27, P150 to VIH4 P60 to P63 VIH5 P121 to P124, P137, P120, P140, P141 Input voltage, low VIL1 P00 to P06, P10 to F P40 to P43, P50, P5 P120, P140, P141 VIL2 P01, P03, P04, P10, P13 to P16, P43 P13 to P16, P43 VIL3 P20 to P27, P150 to VIL4 VIL4 P60 to P63 P13 to P16, P43	VIH3	P20 to P27, P150 to P154	0.7AVDD		AVDD	V	
	P60 to P63		0.7EVDD0		6.0	V	
	VIH5	P121 to P124, P137, EXCLK, EXCLK	(S, RESET	0.8VDD		EVDD0 AVDD 6.0 VDD 0.2EVDD0 0.5	V
Input voltage, low	VIL1	P40 to P43, P50, P51, P70 to P77,	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	0.2EVDD0	V		
	VIL2			V			
				0		0.32	V
	VIL3	P20 to P27, P150 to P154		0		0.3AVDD	V
	VIL4	P60 to P63		0		0.3EVDD0	V
	$ \begin{array}{ c c c c c c } \hline V_{IH1} & P00 \ \text{to } P06, P10 \ \text{to } P16, P30, P31, \\ P40 \ \text{to } P43, P50, P51, P70 \ \text{to } P77, \\ P120, P140, P141 \\ \hline V_{IH2} & P01, P03, P04, P10, P11, \\ P13 \ \text{to } P16, P43 \\ \hline & & & & & & & & & & & & & & & & & &$	0.2VDD	V				

$(T_{1} = -40 \text{ to } \pm 40 \text{ EV})^{-2} = 2.4 \text{ V} = 2.4 \text{ V} = 2.4 \text{ V} = 5 \text{ V} = 2.6 \text{ V} = 5 \text{ V} = 2.6 \text{ V}$

Caution The maximum value of V_{IH} of pins P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 is EV_{DD0}, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



() (E)

Items	Symbol	Conditions	MIN.	TYP.	MAX.	Unit		
Output voltage, high	Vон1	Voh1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$ I _{OH1} = -2.0 mA	EV _{DD0} – 0.6			V
		P120, P130, P140, P141	$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OH1}} = -1.5 \text{ mA}$	EV _{DD0} - 0.5			V	
	V _{OH2}	P20 to P27, P150 to P154	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V},$ I_{OH2} = -100 μ A	AV _{DD} – 0.5			V	
Output voltage, V low	V _{OL1}	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77,	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL1}} = 3.0 \text{ mA}$			0.6	V	
	P120, P130, P140, P141	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL1}} = 1.5 \text{ mA}$			0.4	V		
Vol2 Vol3			$2.4 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL1}} = 0.6 \text{ mA}$			0.4	V	
	Vol2	P20 to P27, P150 to P154	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V},$ $I_{\text{OL2}} = 400 \ \mu\text{A}$			0.4	V	
	Vol3	P60 to P63	$2.7 \text{ V} \leq EV_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL3}} = 3.0 \text{ mA}$			0.4	V	
			$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $I_{\text{OL3}} = 2.0 \text{ mA}$			0.4	V	

+40EOC 24V < AV 40 4 < 2 6 V V <u>م ۱</u>۸ ·--

- Caution P00, P02 to P04, P10 to P15, P43, P50, P71, and P74 do not output high level in N-ch open-drain mode.
- Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(T _A = –40 to +10	<u>)5°C, 2.4 V</u>	\leq AVDD \leq VDD \leq 3.6 V, 2.4 V \leq I	$EV_{DD0} \leq V_{DD0}$	o ≤ 3.6 V, Vss =	EVsso =	0 V)	1	(5/
Items	Symbol	Conditio	ons		MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ilih1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P140, P141	VI = EVDDO				1	μA
	ILIH2	P137, RESET	$V_I = V_{DD}$				1	μA
	Іцнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = VDD	In input port or external clock input			1	μA
				In resonator connection			10	μA
	Ілн4	P20 to P27, P150 to P154	$V_{I} = AV_{DD}$				1	μA
Input leakage current, low	ILIL1	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P67, P70 to P77, P120, P140, P141	VI = EVsso				-1	μA
		P137, RESET	VI = Vss				-1	μA
	Ililis	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = Vss	In input port or external clock input			-1	μA
				In resonator connection			-10	μA
	ILIL4	P20 to P27, P150 to P154	VI = AVss				-1	μA
On-chip pull-up resistance	Ru	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	VI = EVsso	, In input port	10	20	100	kΩ

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



3.3.2 Supply current characteristics

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply current	DD1 ^{Note 1}	Operating mode	HS (high-speed main) mode ^{Note 5}	f _{IH} = 32 MHz ^{Note 3}	Basic operation	V _{DD} = 3.0 V		2.1		mA
					Normal operation	V _{DD} = 3.0 V		4.6	7.5	mA
				f _{IH} = 24 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		3.7	5.8	mA
				f⊪ = 16 MHz ^{Note 3}	Normal operation	V _{DD} = 3.0 V		2.7	4.2	mA
			HS (high-speed main) mode ^{Note 5}	$f_{MX} = 20 \text{ MHz}^{\text{Note 2}},$ $V_{\text{DD}} = 3.0 \text{ V}$	Normal operation	Square wave input		3.0	4.9	mA
						Resonator connection		3.2	5.0	
				$f_{MX} = 10 \text{ MHz}^{\text{Note 2}},$ $V_{\text{DD}} = 3.0 \text{ V}$	Normal operation	Square wave input		1.9	2.9	mA
						Resonator connection		1.9	2.9	
			Subsystem clock mode	fsub = 32.768 kHz ^{Note 4} T _A = -40°C	Normal operation	Square wave input		4.1	4.9	μA
						Resonator connection		4.2	5.0	
				fsub = 32.768 kHz ^{Note 4} T _A = +25°C	Normal operation	Square wave input		4.2	4.9	μΑ
						Resonator connection		4.3	5.0	
				fsub = 32.768 kHz ^{Note 4} T _A = +50°C	Normal operation	Square wave input		4.3	5.5	μA
						Resonator connection		4.4	5.6	
				fsub = 32.768 kHz ^{Note 4} T _A = +70°C	Normal operation	Square wave input		4.5	6.3	μA
						Resonator connection		4.6	6.4	
				fsub = 32.768 kHz ^{Note 4} T _A = +85°C	Normal operation	Square wave input		4.8	7.7	μA
						Resonator connection		4.9	7.8	
				fsuв = 32.768 kHz ^{Note 4} T _A = +105°С	Normal operation	Square wave input		6.9	19.7	μΑ
						Resonator connection		7.0	19.8	

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The following points apply in the HS (high-speed main) mode.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-downresistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

- 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- 3. When high-speed system clock and subsystem clock are stopped.
- **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When setting ultra-low power consumption oscillation (AMPHS1 = 1).
- **5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 V \le V_{DD} \le 3.6 V @1 MHz$ to 32 MHz $2.4 V \le V_{DD} \le 3.6 V @1 MHz$ to 16 MHz

- **Remarks 1.** fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. file: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is $T_A = 25^{\circ}C$



Parameter	Symbol			V, Vss = EVsso = 0 V Conditions		MIN.	TYP.	MAX.	Unit
Supply	DD2Note 2	HALT	HS (high-speed	f⊪ = 32 MHz ^{Note 4}	V _{DD} = 3.0 V		0.54	2.90	mA
current ^{Note 1}		mode	main) mode ^{Note 7}	fıн = 24 MHz ^{Note 4}	V _{DD} = 3.0 V		0.44	2.30	mA
				fıн = 16 MHz ^{Note 4}	V _{DD} = 3.0 V		0.40	1.70	mA
			HS (high-speed	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.90	mA
			main) mode ^{Note 7}	V _{DD} = 3.0 V	Resonator connection		0.45	2.00	
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	1.02	mA
				V _{DD} = 3.0 V	Resonator connection		0.26	1.10	
			Subsystem clock	fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.25	0.57	μA
			mode	$T_A = -40^{\circ}C$	Resonator connection		0.44	0.76	
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.30	0.57	μA
				T _A = +25°C	Resonator connection		0.49	0.76	
				T ₄ = +50°C	Square wave input		0.38	1.17	μA
					Resonator connection		0.57	1.36	
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.52	1.97	μA
				T _A = +70°C	Resonator connection		0.71	2.16	
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.97	3.37	μA
				T _A = +85°C	Resonator connection		1.16	3.56	
				fsub = 32.768 kHz ^{Note 5}	Square wave input		3.01	15.37	μA
				T _A = +105°C	Resonator connection		3.20	15.56	
	DD3 ^{Note 6}	STOP	T _A = −40°C				0.16	0.50	μA
mode ^{Note 8} $T_A = +25^{\circ}$	T _A = +25°C				0.23	0.50			
	T _A = +50°C	T _A = +50°C				0.34	1.10		
T _A = +7	T _A = +70°C				0.46	1.90			
			T _A = +85°C				0.75	3.30	
			T _A = +105°C				2.94	15.30]

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The following points apply in the HS (high-speed main) mode.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- 4. When high-speed system clock and subsystem clock are stopped.
- **5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1).
- 6. When subsystem clock is stopped.
- **7.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.7 \text{ V} \le V_{\text{DD}} \le 3.6 \text{ V}@1 \text{ MHz}$ to 32 MHz

$$2.4~\text{V} \leq \text{V}_\text{DD} \leq 3.6~\text{V}@1~\text{MHz}$$
 to 16 MHz

- Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- **Remarks 1.** f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. file: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is $T_A = 25^{\circ}C$



Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	_{FIL} Note 1				0.20		μA
RTC operating current	_{RTC} Notes 1, 2, 3				0.02		μA
12-bit interval timer operating current	IT ^{Notes 1, 2, 4}				0.02		μA
Watchdog timer operating current	WDT ^{Notes 1, 2, 5}	f⊩ = 15 kHz			0.22		μA
A/D converter operating current	ADC ^{Notes 6, 7}	AV _{DD} = 3.0 V, W	hen conversion at maximum speed		420	720	μA
AV _{REF(+)} current	AVREFNote 8	AV _{DD} = 3.0 V, AD	DREFP1 = 0, ADREFP0 = $0^{\text{Note 7}}$		14.0	25.0	μA
		AV _{REFP} = 3.0 V, A	ADREFP1 = 0, ADREFP0 = $1^{Note \ 10}$		14.0	25.0	μA
		ADREFP1 = 1, A	$\Delta DREFP0 = 0^{Note 1}$		14.0	25.0	μA
A/D converter reference voltage current	ADREF ^{Notes 1, 9}	V _{DD} = 3.0 V			75.0		μA
Temperature sensor operating current	ITMPS ^{Note 1}	V _{DD} = 3.0 V			75.0		μA
LVD operating current	ILVD ^{Notes 1, 11}				0.08		μA
BGO operating current	BGO ^{Notes 1, 12}				2.5	12.2	mA
Self-programming operating current	FSP ^{Notes 1, 13}				2.5	12.2	mA
SNOOZE operating	Isnoz	A/D converter	The mode is performed ^{Notes 1, 14}		0.50	1.10	mA
current		operation	During A/D conversion ^{Note 1}		0.60	1.34	mA
		(AV _{DD} = 3.0 V)	During A/D conversion ^{Note 7}		420	720	μA
		Simplified SPI (C	CSI)/UART operation ^{Note 1}		0.70	1.54	mA

40 to ±105°C 2 4 V < EV-*(*т < V-0.10

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Current flowing to VDD.
 - 2. When high-speed on-chip oscillator and high-speed system clock are stopped.
 - 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
 - 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip ocsillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
 - **5.** Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2, or IDD3 and IWDT when the watchdog timer is in operation.
 - **6.** Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC, IAVREF, IADREF when the A/D converter operates in an operation mode or the HALT mode.
 - 7. Current flowing to the AVDD.
 - 8. Current flowing from the reference voltage source of A/D converter.
 - 9. Operation current flowing to the internal reference voltage.
 - **10.** Current flowing to the AVREFP.
 - **11.** Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
 - 12. Current flowing only during data flash rewrite.
 - **13.** Current flowing only during self programming.

Remarks 1. fil: Low-speed on-chip oscillator clock frequency

- 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- 3. fclk: CPU/peripheral hardware clock frequency
- 4. Temperature condition of the TYP. value is $T_A = 25^{\circ}C$



3.4 AC Characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{ AV}_{DD} \le \text{V}_{DD} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V})$

Items	Symbol		Conditio	ons		MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсү	Main system	HS (high-spe	ed	$2.7~V \leq V_{\text{DD}} \leq 3.6~V$	0.03125		1	μs
instruction execution time)		clock (fmain) operation	main) mode		$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}$	0.0625		1	μs
		$\begin{array}{llllllllllllllllllllllllllllllllllll$		$2.4 \text{ V} \leq V_{\text{DD}} \leq 3.6 \text{ V}$	28.5	30.5	31.3	μs	
			HS (high-spe	ed	$2.7~V \leq V_{\text{DD}} \leq 3.6~V$	0.03125		1	μs
			main) mode		$2.4 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V}$	0.0625		1	μs
External system clock	fex	$2.7~V \leq V_{\text{DD}} \leq$	3.6 V			1.0		20.0	MHz
frequency		$2.4~V \leq V_{\text{DD}} <$	2.7 V			1.0		16.0	MHz
	fexs					32		35	kHz
External system clock input	texh, texl	$2.7~V \leq V_{\text{DD}} \leq$	3.6 V			24			ns
high-level width, low-level		$2.4~V \leq V_{\text{DD}} <$	2.7 V			30			ns
width	texns, texus					13.7			μs
TI00, TI01, TI03 to TI07 input high-level width, low-level width	t⊤ıн, t⊤ı∟					1/fмск+10			ns ^{Note}
TO00, TO01, TO03 to	fтo	HS (high-spee	ed main) 2.	.7 V	$\leq EV_{DD0} \leq 3.6 V$			8	MHz
TO07 output frequency		mode	2.	.4 V	$\leq EV_{DD0} < 2.7 V$			4	MHz
PCLBUZ0, PCLBUZ1	fpcl	HS (high-spee	ed main) 2.	7 V	$\leq EV_{DD0} \leq 3.6 V$			8	MHz
output frequency		mode	2.	.4 V	$\leq EV_{DD0} < 2.7 V$			4	MHz
Interrupt input high-level	tinth, tintl	INTP0	2.	.4 V	$\leq V_{DD} \leq 3.6 \text{ V}$	1			μs
width, low-level width		INTP1 to INTE	P11 2.	.4 V	$\leq EV_{DD0} \leq 3.6 V$	1			μs
Key interrupt input high-level width, low-level width	tкr	KR0 to KR9			$\leq EV_{DD0} \leq 3.6 \text{ V},$ $\leq AV_{DD0} \leq 3.6 \text{ V}$	250			ns
RESET low-level width	trsl					10			μs

Note The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$. 2.4 V $\leq EV_{DD0} < 2.7$ V : MIN. 125 ns

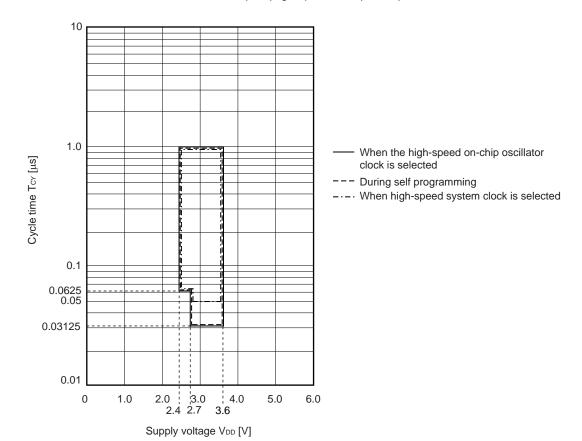
Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer clock select register 0 (TPS0) and timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))



Minimum Instruction Execution Time during Main System Clock Operation

TCY vs VDD (HS (high-speed main) mode)

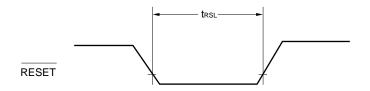




AC Timing Test Points Ин/Vон **Ин/**Vон Test points VIL/VOL VIL/VOL **External System Clock Timing** 1/f_{EX} $\mathbf{t}_{\mathsf{EXL}}$ tехн 0.7 VDD MIN. EXCLK 0.3 VDD MAX. **TI/TO Timing** t⊤ı∟ tтін TI00, TI01, TI03 to TI07 1/**f**то -TO00, TO01, TO03 to TO07 Interrupt Request Input Timing **t**INTL **t**INTH INTP0 to INTP11 **Key Interrupt Input Timing t**KR KR0 to KR9



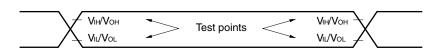
RESET Input Timing





3.5 Peripheral Functions Characteristics

AC Timing Test Points



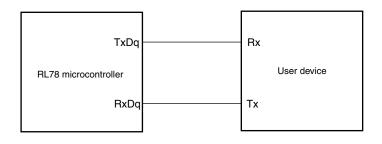
3.5.1 Serial array unit

(1) During communication at same potential (UART mode) (dedicated baud rate generator output) ($T_A = -40$ to +105°C, 2.4 V $\leq EV_{DD0} \leq V_{DD} \leq 3.6$ V, Vss = EVsso = 0 V)

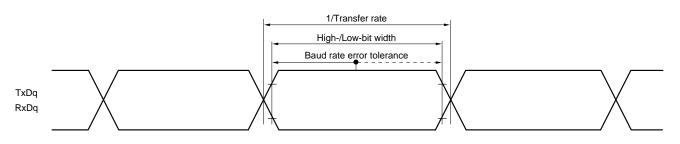
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate ^{Note 1}					fмск/12	bps
		Theoretical value of the maximum transfer rate fcLk = 32 MHz, fMck = fcLk			2.6 ^{Note 2}	Mbps

- Notes 1. Transfer rate in the SNOOZE mode is 4800 bps.
 - The following conditions are required for low-voltage interface when EV_{DD0} < V_{DD}.
 2.4 V ≤ EV_{DD0} < 2.7 V : MAX. 1.3 Mbps
- Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Remarks 1. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

2. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10, 11))

(2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

Parameter	Symbol	Condition	S	MIN.	TYP.	MAX.	Unit
SCKp cycle time	tkcy1	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	tkcy1 ≥ 4/fcLk	250			ns
		$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$	tkcy1 ≥ 4/fcLk	500			ns
SCKp high-/low-level width	tкнı,	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$		tксү1/2 – 36			ns
	tĸ∟1	$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$		tксү1/2 – 76			ns
SIp setup time (to SCKp↑) ^{Note 1}	tsik1	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$		66			ns
		$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$		113			ns
SIp hold time (from SCKp↑) ^{Note 1}	tksi1			38			ns
Delay time from SCKp↓ to SOp output ^{Note 2}	tkso1	C = 30 p ^{Note 3}				50	ns

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **3.** C is the load capacitance of the SCKp and SOp output lines.
- Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).
- **Remark** p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM numbers (g = 0, 1)



(3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Cond	ditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time ^{Note 1}	t ксү2	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	16 MHz < fмск	16/ f мск			ns
			fмск ≤ 16 MHz	12/fмск			ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$ 1		12/fмск and 1000			ns
SCKp high-/low-level width	t кн2,	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$	$.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$				ns
	t_{KL2} 2.4 V $\leq EV_{DD0} \leq 3.6$ V		,	tксү2/2-16			ns
SIp setup time	tsik2	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V}$	1	1/fмск + 40			ns
(to SCKp↑) ^{Note 2}		$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$	1	1/fмск + 60			ns
SIp hold time	t KSI2	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$	/	1/fмск+62			ns
(from SCKp↑) ^{Note 2}	from SCKp [↑]) ^{Note 2} $2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$		1	1/fмск+62			ns
Delay time from SCKp↓ to	tkso2	C = 30 pF ^{Note 4}	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V$			2/fмск+66	ns
SOp output ^{Note 3}			$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$			2/fмск+113	ns

 $(T_{\text{A}} = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Notes 1. Transfer rate in the SNOOZE mode : MAX. 1 Mbps

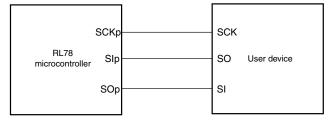
- When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 4. C is the load capacitance of the SOp output lines.
- Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).
- **Remarks 1.** p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1),
 - n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1)
 - 2. fmck: Serial array unit operation clock frequency

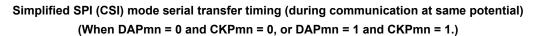
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

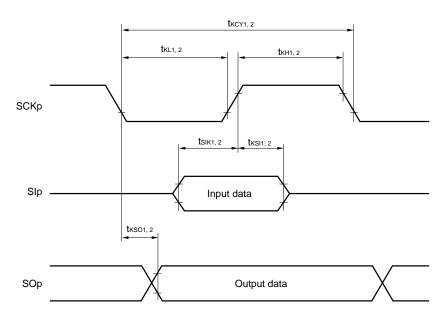
n: Channel number (mn = 00 to 03, 10, 11))



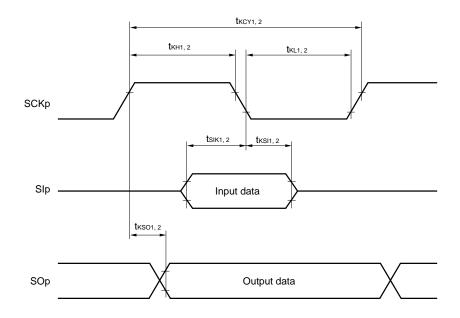
Simplified SPI (CSI) mode connection diagram (during communication at same potential)

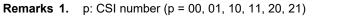






Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)





2. m: Unit number, n: Channel number (mn = 00 to 03, 10, 11)



Parameter	Symbol	Conditions	MIN.	MAX.	Unit
SCLr clock frequency	fsc∟	$\begin{array}{l} 2.7 \ \text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \ \text{V}, \\ C_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$		400 ^{Note 1}	kHz
		$\label{eq:linear} \begin{array}{l} 2.4 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$		100 ^{Note 1}	kHz
Hold time when SCLr = "L"	tLow	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ C_{b} = 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	1200		ns
		$\label{eq:linear} \begin{array}{l} 2.4 \mbox{ V} \leq EV_{\mbox{DD0}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$	4600		ns
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ \\ C_{b} = 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	1200		ns
		$\label{eq:linear} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \\ C_{\text{b}} = 100 \ \text{pF}, \ R_{\text{b}} = 3 \ \text{k}\Omega \end{array}$	4600		ns
Data setup time (reception)	tsu:dat	$\begin{array}{l} 2.7 \ \text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \ \text{V}, \\ C_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$	1/f _{мск} + 220 ^{Note 2}		ns
		$\label{eq:linear} \begin{array}{l} 2.4 \mbox{ V} \leq EV_{\mbox{DD}} \leq 3.6 \mbox{ V}, \\ C_{\mbox{\tiny b}} = 100 \mbox{ pF}, \mbox{ R}_{\mbox{\tiny b}} = 3 k\Omega \end{array}$	1/f _{мск} + 580 ^{Note 2}		ns
Data hold time (transmission)	thd:dat	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ \\ C_{b} = 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	0	770	ns
		$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \\ C_{\text{b}} = 100 \ \text{pF}, \ R_{\text{b}} = 3 \ \text{k}\Omega \end{array}$	0	1420	ns

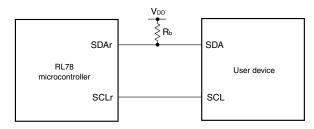
(4) During communication at same potential (simplified l²C mode) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Notes 1. The value must also be fcLK/4 or lower.

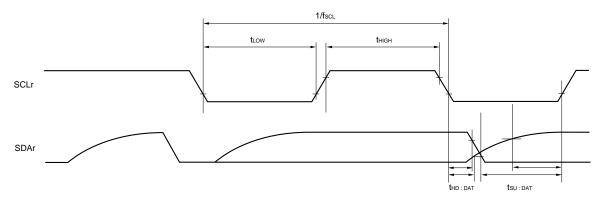
- 2. Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".
- Caution Select the normal input buffer and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).



Simplified I²C mode mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



- **Remarks 1.** R_b[Ω]: Communication line (SDAr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance
 - **2.** r: IIC number (r = 00, 01, 10, 11, 20, 21), g: PIM number (g = 0, 1), h: POM number (h = 0, 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number, mn = 00 to 03, 10, 11)



(5) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (1/2) ($T_A = -40$ to +105°C, 2.4 V $\leq EV_{DD0} \leq V_{DD} \leq 3.6$ V, Vss = EVsso = 0 V)

Parameter	Symbol		Conditions				MAX.	Unit
Transfer rate ^{Note 1}		Reception	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V,$				fмск/12	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate fcLk = 32 MHz, fMck = fcLk			2.6	Mbps
			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$				fмск/12	bps
			$1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate fclk = 32 MHz, fмck = fclk			2.6 ^{Note 2}	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps.

- 2. The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$. 2.4 V $\leq EV_{DD0} < 2.7$ V : MAX. 1.3 Mbps
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** V_b[V]: Communication line voltage
 - **2.** q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
 - fMCK: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
 n: Channel number (mn = 00 to 03, 10, 11)

R01DS0151EJ0230 Rev.2.30 Apr 26, 2024



(5) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (2/2) ($T_A = -40$ to +105°C, 2.4 V $\leq EV_{DD0} \leq V_{DD} \leq 3.6$ V, Vss = EVsso = 0 V)

Parameter	Symbol		Cond	itions	MIN.	TYP.	MAX.	Unit
Transfer	r Transmission $2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$					Note 1	bps	
rate			$2.3 \text{ V} \leq V_b \leq 2.7 \text{ V}$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega, V_b = 2.3 \text{ V}$			1.2 ^{Note 2}	Mbps
			$2.4 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V},$				Note 3	bps
			$1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$			0.43 ^{Note 4}	Mbps

Notes 1. The smaller maximum transfer rate derived by using f_{MCK}/12 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD0} \leq 3.6 V and 2.3 V \leq V_b \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =

$$\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln \\ \text{Index} = \frac{(1 - \frac{2.0}{V_b})\}}{(\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

- 2. This value as an example is calculated when the conditions described in the "Conditions" column are met. See **Note 1** above to calculate the maximum transfer rate under conditions of the customer.
- **3.** The smaller maximum transfer rate derived by using fMCK/12 or the following expression is the valid maximum transfer rate.

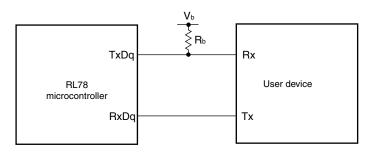
Expression for calculating the transfer rate when 2.4 V \leq EV_{DD0} < 3.3 V and 1.6 V \leq V_b \leq 2.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

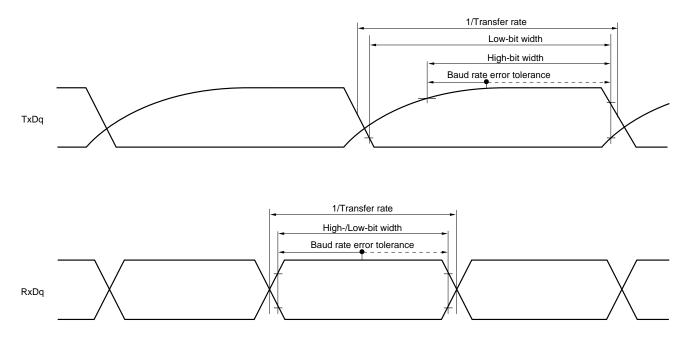
Baud rate error (theoretical value) = $\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
 4. This value as an example is calculated when the conditions described in the "Conditions" column are met. See Note 3 above to calculate the maximum transfer rate under conditions of the customer.
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (Vbb tolerance (When 25- to 48-pin products)/EVbb tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)



Remarks 1. Rb[Ω]: Communication line (TxDq) pull-up resistance, Cb[F]: Communication line (TxDq) load capacitance, Vb[V]: Communication line voltage Image: Cbl and Cbl and

2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10, 11))



(6) Communication at different potential (1.8 V, 2.5 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (1/2)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
SCKp cycle time	tксүı	$ \begin{array}{ll} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, & t_{KCY1} \geq 4/f_{CLK} \\ 2.3 \ V \leq V_b \leq 2.7 \ V, & \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega & \end{array} $		1000			ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	tксү1 ≥ 4/fc∟к	2300			ns
SCKp high-level width	tкнı	$\begin{array}{l} 2.7 \; V \leq EV_{\text{DD0}} \leq 3.6 \; V, \; 2.3 \; V \leq \\ C_{\text{b}} = 30 \; pF, \; R_{\text{b}} = 2.7 \; k\Omega \end{array}$	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 2.7 \text{ k}\Omega$				ns
		$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq \\ C_{\text{b}} = 30 \ \text{pF}, \ R_{\text{b}} = 5.5 \ \text{k}\Omega \end{array}$	$V_{b} \leq 2.0 \ V,$	tксү1/2 – 916			ns
SCKp low-level width	tĸ∟1	$\label{eq:2.7} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ \text{V}, \ 2.3 \ \text{V} \leq V_{\text{b}} \leq 2.7 \ \text{V}, \\ C_{\text{b}} = 30 \ \text{pF}, \ R_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$		tксү1/2 – 36			ns
		$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq \\ C_{\text{b}} = 30 \ \text{pF}, \ R_{\text{b}} = 5.5 \ \text{k}\Omega \end{array}$	$V_b \leq 2.0 V$,	tксү1/2 – 100			ns

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 20), m: Unit number , n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.



(6) Communication at different potential (1.8 V, 2.5 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/2)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SIp setup time (to SCKp↑) ^{Note 1}	tsıkı	$\label{eq:V_b} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	354			ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD0} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	958			ns
SIp hold time (from SCKp↑) ^{Note 1}	tksı1	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	38			ns
		$\label{eq:V_b} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	38			ns
Delay time from SCKp↓ to SOp output ^{Note 1}	tkso1	$\label{eq:V_b} \begin{split} 2.7 \ V &\leq EV_{\text{DD0}} \leq 3.6 \ \text{V}, \ 2.3 \ \text{V} \leq V_b \leq 2.7 \ \text{V}, \\ C_b &= 30 \ \text{pF}, \ R_b = 2.7 \ \text{k}\Omega \end{split}$			390	ns
		$\label{eq:V_def} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$			966	ns
Slp setup time (to SCKp↓) ^{Note 2}	tsıĸı	$\label{eq:V_def} \begin{split} 2.7 \ V &\leq EV_{\text{DD0}} \leq 3.6 \ \text{V}, \ 2.3 \ \text{V} \leq V_b \leq 2.7 \ \text{V}, \\ C_b &= 30 \ \text{pF}, \ R_b = 2.7 \ \text{k}\Omega \end{split}$	88			ns
		$\label{eq:V_def} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	220			ns
SIp hold time (from SCKp↓) ^{Note 2}	tksi1	$\label{eq:V_def} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	38			ns
		$\label{eq:V_b} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	38			ns
Delay time from SCKp↑ to SOp output ^{Note 2}	tkso1	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$			50	ns
		$\label{eq:linear} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$			50	ns

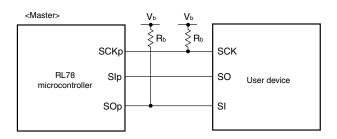
 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

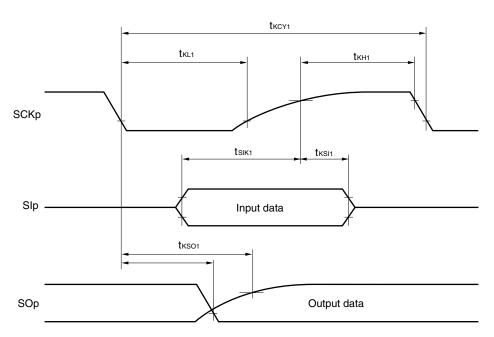


- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 20), m: Unit number , n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

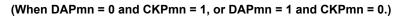
Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different

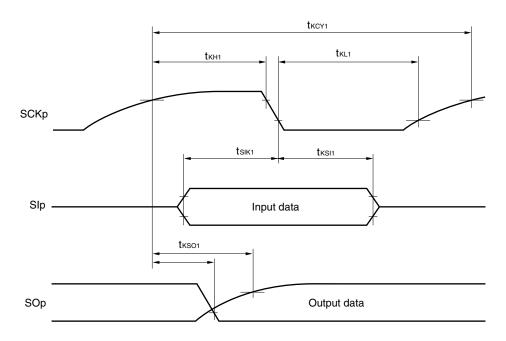


(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential)





- **Remarks 1.** p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (m = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **2.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

RENESAS

(7) Communication at different potential (1.8 V, 2.5 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
SCKp cycle time ^{Note 1}	tĸcv2	$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V \end{array}$	24 MHz < fмск	40/f мск			ns
			20 MHz < fмск ≤ 24 MHz	32/f мск			ns
			16 MHz < fмск ≤ 20 MHz	28/ f мск			ns
			8 MHz < fмск ≤ 16 MHz	24/ f мск			ns
			4 MHz < fмск ≤ 8 MHz	16/fмск			ns
			fмск ≤ 4 MHz	12/fмск			ns
		$2.4 V \le EV_{DD0} < 3.3 V,$ $1.6 V \le V_b \le 2.0 V$	24 MHz < fмск	96/ f мск			ns
			20 MHz < fмск ≤ 24 MHz	72/fмск			ns
			16 MHz < fмск ≤ 20 MHz	64/ f мск			ns
			8 MHz < fмск≤ 16 MHz	52/f мск			ns
			4 MHz < fмск≤ 8 MHz	32/f мск			ns
			fмск≤4 MHz	20/ f мск			ns
SCKp high-/low-level width	tкн2, tкL2	$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V,~2.3~V \leq V_b \leq 2.7~V$		tkcy2/2 – 36			ns
		$2.4 \ V \le EV_{DD0} < 3.3 \ V, \ 1.6 \ V \le V_b \le 2.0 \ V$		tксү2/2 – 100			ns
Slp setup time (to SCKp↑) ^{Note 2}		$2.7~V \leq EV_{\text{DD0}} \leq 3.6~V,~2.3~V \leq V_{\text{b}} \leq 2.7~V$		1/fмск + 40			ns
		$2.4~V \leq EV_{\text{DD0}} < 3.3~V,~1.6~V \leq V_{\text{b}} \leq 2.0~V$		1/fмск + 60			
SIp hold time (from SCKp↑) ^{Note 2}	tksi2			1/fмск + 62			ns
Delay time from SCKp↓ to SOp output ^{Note 3}	tkso2	$\label{eq:2.7} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} \leq 3.6 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V, \\ C_{\text{b}} = 30 \ p\text{F}, \ R_{\text{b}} = 2.7 \ k\Omega \end{array}$				2/f _{мск} + 428	ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, T$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 5.5 \text{ kG}$				2/f _{мск} + 1146	ns

 $(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, \text{ V}_{SS} = EV_{SS0} = 0 \text{ V})$

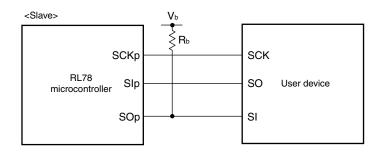
Notes 1. Transfer rate in the SNOOZE mode : MAX. 1 Mbps

- When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)



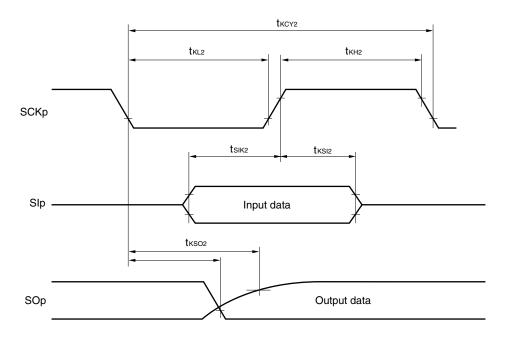
Simplified SPI (CSI) mode connection diagram (during communication at different potential)



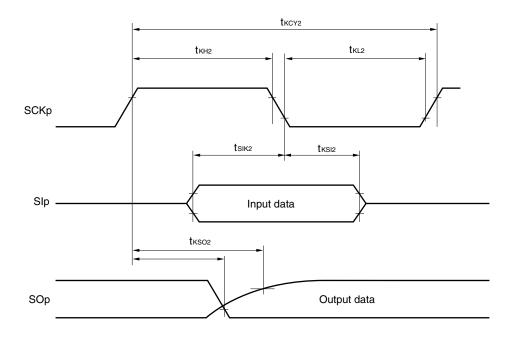
- **Remarks 1.** R_b[Ω]: Communication line (SOp) pull-up resistance, C_b[F]: Communication line (SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 20), m: Unit number (m = 0, 1), n: Channel number (n = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - fMCK: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00, 02, 10))
 - **4.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



- **Remarks 1.** p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **2.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

(8) Communication at different potential (1.8 V, 2.5 V) (simplified l^2C mode) (1/2)

 $(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le EV_{DD0} \le V_{DD} \le 3.6 \text{ V}, \text{ Vss} = EV_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
SCLr clock frequency	fsc∟	$\label{eq:2.7} \begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		400 ^{Note 1}	kHz
		$\label{eq:2.7} \begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$		100 ^{Note 1}	kHz
		$\label{eq:2.4} \begin{array}{l} 2.4 \; V \leq E V_{DD0} < 3.3 \; V, \\ 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 100 \; p F, \; R_b = 5.5 \; k \Omega \end{array}$		100 ^{Note 1}	kHz
Hold time when SCLr = "L"	tLow	$\label{eq:2.7} \begin{split} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	1200		ns
		$\label{eq:2.7} \begin{split} 2.7 \ V &\leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 100 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	4600		ns
		$\label{eq:2.4} \begin{array}{l} 2.4 \; V \leq E V_{DD0} < 3.3 \; V, \\ 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 100 \; pF, \; R_b = 5.5 \; k\Omega \end{array}$	4650		ns
Hold time when SCLr = "H"	tнісн	$\label{eq:2.7} \begin{split} 2.7 \ V &\leq E V_{DD0} \leq 3.6 \ V, \\ 2.3 \ V &\leq V_b \leq 2.7 \ V, \\ C_b &= 50 \ pF, \ R_b = 2.7 \ k\Omega \end{split}$	500		ns
		$\label{eq:2.7} \begin{split} & 2.7 \; V \leq EV_{DD0} \leq 3.6 \; V, \\ & 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ & C_{b} = 100 \; pF, \; R_{b} = 2.7 \; k\Omega \end{split}$	2400		ns
		$\label{eq:2.4} \begin{array}{l} 2.4 \; V \leq E V_{DD0} < 3.3 \; V, \\ 1.6 \; V \leq V_b \leq 2.0 \; V, \\ C_b = 100 \; pF, \; R_b = 5.5 \; k\Omega \end{array}$	1830		ns

(Notes, Caution and Remarks are listed on the next page.)



Parameter	Symbol	Conditions	MIN.	MAX.	Unit
Data setup time (reception)	tsu:dat	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/f _{МСК} + 340 ^{Note 2}		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/f _{МСК} + 760 ^{Note 2}		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1/f _{МСК} + 570 ^{Note 2}		ns
Data hold time (transmission)	thd:dat	$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	770	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} \leq 3.6 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	1420	ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	0	1215	ns

(8) Communication at different potential (1.8 V, 2.5 V) (simplified I²C mode) (2/2) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD0} \leq V_{DD} \leq 3.6 V, V_{SS} = EV_{SS0} = 0 V)

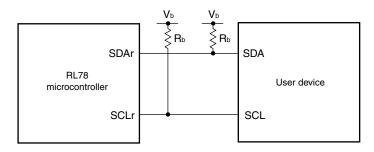
Notes 1. The value must also be $f_{CLK}/4$ or lower.

- **2.** Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H".
- Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SDAr pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VH and VL, see the DC characteristics with TTL input buffer selected.

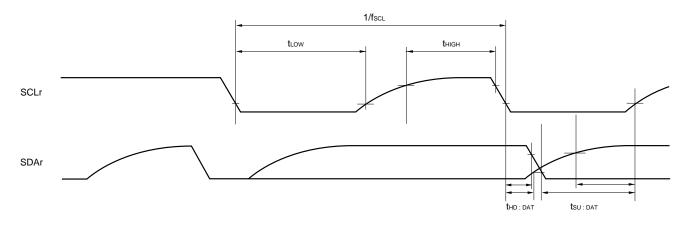
(**Remarks** are listed on the next page.)



Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** R_b[Ω]: Communication line (SDAr, SCLr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance, V_b[V]: Communication line voltage
 - **2.** r: IIC number (r = 00, 10, 20), g: PIM, POM number (g = 0, 1)
 - fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10)
 - **4.** IIC01, IIC11, and IIC21 cannot communicate at different potential. Use IIC00, IIC10, or IIC20 for communication at different potential.



3.5.2 Serial interface IICA

(1) I^2C standard mode, fast mode

(TA = -40 to +105°C, 2.4 V \leq EVDD0 \leq VDD \leq 3.6 V, Vss = EVsso = 0 V)

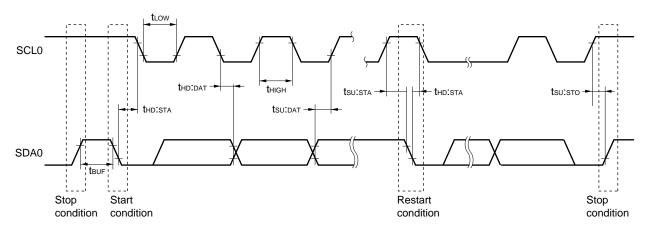
Parameter	Symbol	Conditions		Standard Mode		Fast Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fsc∟	Fast mode: fc∟ĸ ≥ 3.5 MHz	$2.4~V \leq EV_{DD0} \leq 3.6~V$			0	400	kHz
		Normal mode: fc∟ĸ ≥ 1 MHz	$2.4~V \leq EV_{\text{DD0}} \leq 3.6~V$	0	100			kHz
Setup time of restart condition	tsu:sta			4.7		0.6		μs
Hold time ^{Note 1}	thd:sta			4.0		0.6		μs
Hold time when SCLA0 = "L"	tLOW			4.7		1.3		μs
Hold time when SCLA0 = "H"	tніgн			4.0		0.6		μs
Data setup time (reception)	tsu:dat			250		100		ns
Data hold time (transmission)Note 2	thd:dat			0	3.45	0	0.9	μs
Setup time of stop condition	tsu:sto			4.0		0.6		μs
Bus-free time	t BUF			4.7		1.3		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

- 2. The maximum value (MAX.) of the during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.
- **Remark** The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

 $\begin{array}{ll} \mbox{Standard mode:} & C_b = 400 \mbox{ pF}, \mbox{ } R_b = 2.7 \mbox{ } k\Omega \\ \mbox{Fast mode:} & C_b = 320 \mbox{ } pF, \mbox{ } R_b = 1.1 \mbox{ } k\Omega \\ \end{array}$

IICA serial transfer timing



3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Division of A/D Converter Characteristics

Reference voltag	Reference voltage (+) = AV _{REFP} Reference voltage (-) = AV _{REFM}	Reference voltage (+) = AV _{DD} Reference voltage (-) = AV _{SS}	Reference voltage (+) = Internal refrence voltage Reference voltage (-) = AVss
High-accuracy channel; ANI0 to ANI12 (input buffer power supply: AV _{DD})	See 3.6.1 (1)	See 3.6.1 (2)	See 3.6.1 (5)
Standard channel; ANI16 to ANI30 (input buffer power supply: Vbb or EVbbb)	See 3.6.1 (3)	See 3.6.1 (4)	
Temperature sensor, internal reference voltage output	See 3.6.1 (3)	See 3.6.1 (4)	-

(1) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12

 $(T_{A} = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{\text{REFP}}, \text{Reference voltage (-)} = \text{AV}_{\text{REFM}} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	8.		12.	bit
Overall error ^{Note}	AINL	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±6.0	LSB
Conversion time	tсомv	ADTYP = 0, 12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	3.375			μs
Zero-scale error ^{Note}	Ezs	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±4.5	LSB
Full-scale error ^{Note}	Ers	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±4.5	LSB
Integral linearity error ^{Note}	ILE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	LSB
Differential linearity error ^{Note}	DLE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±1.5	LSB
Analog input voltage	VAIN			0		AVREFP	V

Note Excludes quantization error ($\pm 1/2$ LSB).



(2) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI0 to ANI12

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{ V}_{\text{SS}} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{AV}_{\text{DD}}, \text{ Reference voltage (-)} = \text{AV}_{\text{SS}} = 0 \text{ V}$

Parameter	Symbol	(MIN.	TYP.	MAX.	Unit	
Resolution	Res		$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$	8		12	bit
Overall error ^{Note}	AINL	12-bit resolution	$2.4~V \le AV_{\text{DD}} \le 3.6~V$			±7.5	LSB
Conversion time	tсомv	ADTYP = 0, 12-bit resolution	$2.4~\text{V} \leq A\text{V}_\text{DD} \leq 3.6~\text{V}$	3.375			μs
Zero-scale error ^{Note}	Ezs	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±6.0	LSB
Full-scale error ^{Note}	Ers	12-bit resolution	$2.4~V \le AV_{\text{DD}} \le 3.6~V$			±6.0	LSB
Integral linearity error ^{Note}	ILE	12-bit resolution	$2.4~V \le AV_{\text{DD}} \le 3.6~V$			±3.0	LSB
Differential linearity error Note	DLE	12-bit resolution	$2.4~V \le AV_{\text{DD}} \le 3.6~V$			±2.0	LSB
Analog input voltage	VAIN			0		AVDD	V

Note Excludes quantization error ($\pm 1/2$ LSB).



(3) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{\text{REFP}}, \text{Reference voltage (-)} = \text{AV}_{\text{REFM}} = 0 \text{ V})$

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit		
Resolution	Res		$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$	8		12	bit		
Overall error ^{Note 1}	AINL	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±7.0	LSB		
Conversion time	t CONV	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$	4.125			μs		
Zero-scale error ^{Note 1}	Ezs	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±5.0	LSB		
Full-scale error ^{Note 1}	Ers	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±5.0	LSB		
Integral linearity error ^{Note 1}	ILE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±3.0	LSB		
Differential linearity error ^{Note 1}	DLE	12-bit resolution	$2.4~V \leq AV_{\text{REFP}} \leq AV_{\text{DD}} \leq 3.6~V$			±2.0	LSB		
Analog input voltage	Vain			0.		AVREFP and EVDD0	V		
		Interanal reference $(2.4 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V})$	V _{BGR} Note 2			V			
		•	Temperature sensor output voltage (2.4 V \leq V_{DD} \leq 3.6 V, HS (high-speed main) mode)			V _{TMPS25} Note 2			

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

2. See 3.6.2 Temperature sensor, internal reference voltage output characteristics.



(4) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD0}} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{AV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}, \text{AV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+) = AV}_{\text{DD}}, \text{Reference voltage (-) = AV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	C	onditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$	8		12	bit
Overall error ^{Note 1}	AINL	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±8.5	LSB
Conversion time	t CONV	ADTYP = 0, 12-bit resolution	$2.4~V \leq AV_{DD} \leq 3.6~V$	4.125			μs
Zero-scale error ^{Note 1}	Ezs	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±8.0	LSB
Full-scale error ^{Note 1}	Ers	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±8.0	LSB
Integral linearity error ^{Note 1}	ILE	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±3.5	LSB
Differential linearity error ^{Note 1}	DLE	12-bit resolution	$2.4~V \leq AV_{\text{DD}} \leq 3.6~V$			±2.5	LSB
Analog input voltage	Vain			0		AV _{DD} and EV _{DD0}	V
		Interanal reference vol (2.4 V \leq V _{DD} \leq 3.6 V, H	V _{BGR} Note 2			V	
		Temperature sensor of (2.4 V \leq V _{DD} \leq 3.6 V, H	output voltage IS (high-speed main) mode)	,	VTMPS25 ^{Note}	2	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

2. See 3.6.2 Temperature sensor, internal reference voltage output characteristics.



(5) When reference voltage (+) = Internal reference voltage (1.45 V) (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVss (ADREFM = 0), target for conversion: ANI0 to ANI12, ANI16 to ANI30

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}, 2.4 \text{ V} \le \text{EV}_{DD} \le \text{V}_{DD}, 2.4 \text{ V} \le \text{AV}_{DD} \le \text{V}_{DD}, \text{V}_{SS} = \text{EV}_{SS0} = 0 \text{ V}, \text{AV}_{SS} = 0 \text{ V}, \text{Reference voltage (+) = Internal reference voltage, Reference voltage (-) = AV}_{SS} = 0 \text{ V}, \text{HS (high-speed main) mode)}$

Parameter	Symbol	Conditions		TYP.	MAX.	Unit
Resolution	Res		8			bit
Conversion time	t CONV	8-bit resolution	16.0			μs
Zero-scale error ^{Note}	Ezs	8-bit resolution			±4.0	LSB
Integral linearity error ^{Note}	ILE	8-bit resolution			±2.0	LSB
Differential linearity error ^{Note}	DLE	8-bit resolution			±2.5	LSB
Reference voltage (+)	AV _{REF(+)}	= Internal reference voltage (V _{BGR})	1.38	1.45	1.50	V
Analog input voltage	VAIN		0		VBGR	V

Note Excludes quantization error ($\pm 1/2$ LSB).

3.6.2 Temperature sensor, internal reference voltage output characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, T_A = +25°C		1.05		V
Internal reference voltage	VBGR	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		10			μs

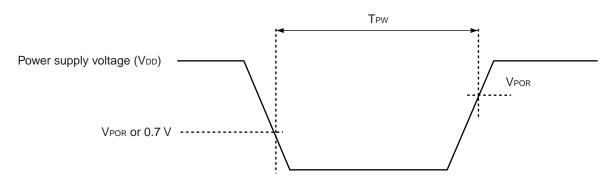
(TA = -40 to +105°C, 2.4 V \leq VDD \leq 3.6 V, Vss = 0 V, HS (high-speed main) mode)

3.6.3 POR circuit characteristics

(T_A = -40 to +105°C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	Power supply rise time		1.51	1.57	V
	VPDR	Power supply fall time	1.44	1.50	1.56	V
Minimum pulse width ^{Note}	Tpw		300			μs

Note This is the time required for the POR circuit to execute a reset when V_{DD} falls below V_{PDR}. When the microcontroller enters STOP mode or if the main system clock (f_{MAIN}) has been stopped by setting bit 0 (HIOSTOP) and bit 7 (MSTOP) of the clock operation status control register (CSC), this is the time required for the POR circuit to execute a reset before V_{DD} rises to V_{POR} after having fallen below 0.7 V.





3.6.4 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

(TA = -40 to +105°C, VPDR \leq VDD \leq 3.6 V, Vss = 0 V)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	VLVD2	Power supply rise time	3.01	3.13	3.25	V
voltage			Power supply fall time	2.94	3.06	3.18	V
		VLVD3	Power supply rise time	2.90	3.02	3.14	V
			Power supply fall time	2.85	2.96	3.07	V
		VLVD4	Power supply rise time	2.81	2.92	3.03	V
		Power supply fall time	2.75	2.86	2.97	V	
		VLVD5	Power supply rise time	2.70	2.81	2.92	V
			Power supply fall time	2.64	2.75	2.86	V
		VLVD6	Power supply rise time	2.61	2.71	2.81	V
			Power supply fall time	2.55	2.65	2.75	V
		VLVD7	Power supply rise time	2.51	2.61	2.71	V
			Power supply fall time	2.45	2.55	2.65	V
Minimum pu	lse width	tLw		300			μs
Detection de	elay time					300	μs

Remark $V_{LVD(n-1)} > V_{LVDn}$: n = 3 to 7

LVD Detection Voltage of Interrupt & Reset Mode

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{ VPDR} \le \text{VDD} \le 3.6 \text{ V}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol		Cond	ditions	MIN.	TYP.	MAX.	Unit
Interrupt & reset	VLVD5	VPOC	2, VPOC1, VPOC0 = 0), 1, 1, falling reset voltage	2.64	2.75	2.86	V
mode	VLVD4		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.81	2.92	3.03	V
				Falling interrupt voltage	2.75	2.86	2.97	V
	VLVD3		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.90	3.02	3.14	V
				Falling interrupt voltage	2.85	2.96	3.07	V

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: VDD = 2.7 to 3.6 V@1 MHz to 32 MHz

VDD = 2.4 to 3.6 V@1 MHz to 16 MHz

3.6.5 Supply voltage rise slope characteristics

(T_A = -40 to +105°C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SVDD				54	V/ms

Caution Be sure to maintain the internal reset state until VDD reaches the operating voltage range specified in 3.4 AC Characteristics, by using the LVD circuit or external reset pin.

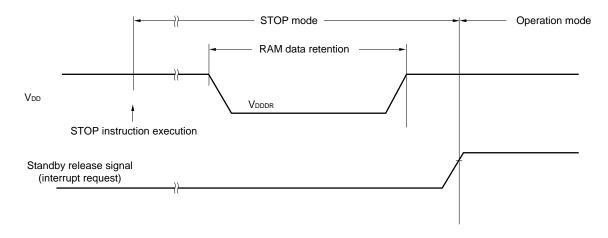


3.7 RAM Data Retention Characteristics

(T _A = -40 to +105°C, Vss = 0 V
--

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 ^{Note}		3.6	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



3.8 Flash Memory Programming Characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	fclк	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	1		32	MHz
Number of code flash rewrites ^{Notes 1, 2, 3}	Cerwr	Retained for 20 years $T_A = 85^{\circ}C$	1,000			Times
Number of data flash rewrites ^{Notes 1, 2, 3}		Retained for 1 years T _A = 25°C		1,000,000		
		Retained for 5 years T _A = 85°C	100,000			
		Retained for 20 years $T_A = 85^{\circ}C$	10,000			

(T_A = -40 to +105°C, 2.4 V \leq V_DD \leq 3.6 V, Vss = 0 V)

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
- **4.** This temperature is the average value at which data are retained.

3.9 Dedicated Flash Memory Programmer Communication (UART)

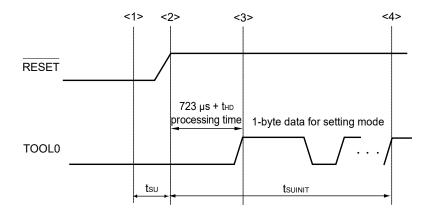
(T - 40.4+ 140500		
$(1A = -40 \text{ to } +105^{\circ}\text{C})$	$, 2.4 V \leq EVDD0 \leq VDD \leq$	3.6 V, Vss = EVsso = 0 V)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{FV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{FV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115.2 k		1 M	bps

3.10 Timing Specs for Switching Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	tsuinit	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until a external reset ends	tsu	POR and LVD reset must end before the external reset ends.	10			μs
How long the TOOL0 pin must be kept at the low level after an external reset ends (except flash firmware processing time)	tно	POR and LVD reset must end before the external reset ends.	1			ms



- <1> The low level is input to the TOOL0 pin.
- <2> The pins reset ends (POR and LVD reset must end before the external reset ends.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.
 - $t_{\text{SU:}}$ How long from when the TOOL0 pin is placed at the low level until a external reset ends
 - thd: How long to keep the TOOL0 pin at the low level from when the external resets end (except flash firmware processing time)

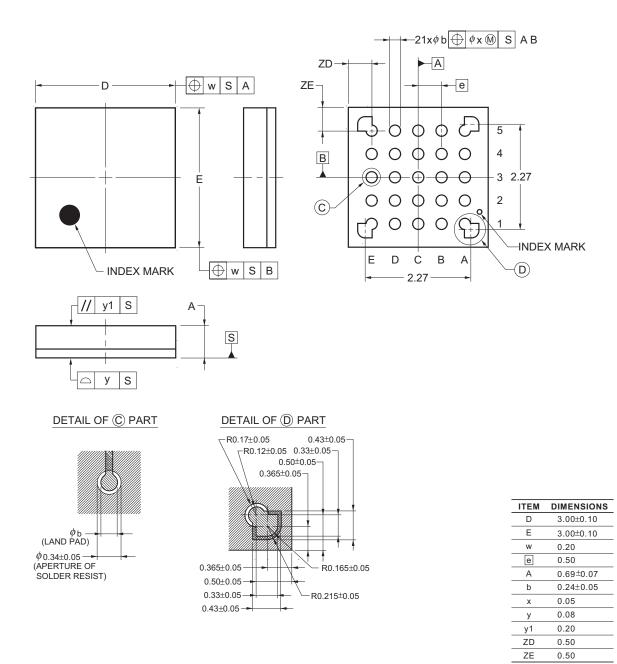


4. PACKAGE DRAWINGS

4.1 25-pin products

JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-WFLGA25-3x3-0.50	PWLG0025KA-A	P25FC-50-2N2-3	0.01

Unit: mm



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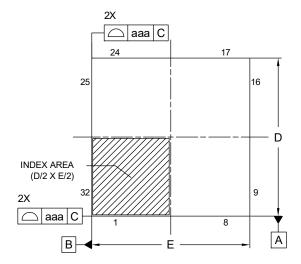
4.2 32-pin products

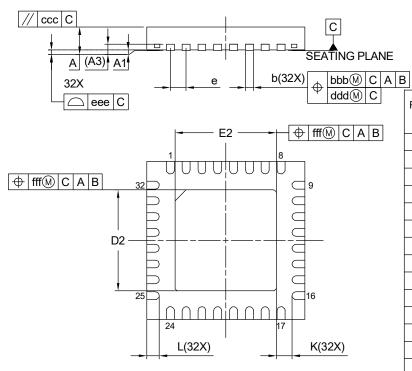
JEITA Package code	RENESAS code	Previo	us code	N	MASS(T)	(P.)[g]
P-HWQFN32-5x5-0.50	PWQN0032KB-A	P32K8-	-50-3B4-5		0.06	6
				OF (À) PART	
\angle INDEX AREA						
	<u> </u>					
			Referance	Dimen	sion in Mil	limeters
			Referance Symbol	Dimen	sion in Mil	limeters
					-	Max
			Symbol	Min	Nom	Max 5.05
		D	Symbol D	Min 4.95	Nom 5.00	Max 5.05 5.05
		D	Symbol D E	Min 4.95 4.95	Nom 5.00	Max 5.05 5.05
		D	Symbol D E A A ₁ b	Min 4.95 4.95 ——	Nom 5.00	Max 5.05 5.05 0.80
	EXPOSED DIE PAI	D	Symbol D E A A ₁	Min 4.95 4.95 — 0.00	Nom 5.00 5.00	Max 5.05 5.05 0.80
	EXPOSED DIE PAI	D	Symbol D E A A ₁ b	Min 4.95 4.95 — 0.00	Nom 5.00 5.00 — 0.25	Max 5.05 5.05 0.80 0.30
	EXPOSED DIE PAI	D	Symbol D E A A1 b e	Min 4.95 4.95 0.00 0.18 	Nom 5.00 5.00 0.25 0.50	Max 5.05 5.05 0.80 0.30 0.30
	EXPOSED DIE PAI	D	Symbol D E A A1 b e Lp	Min 4.95 4.95 0.00 0.18 0.30	Nom 5.00 5.00 0.25 0.50	Max 5.05 5.05 0.80
	EXPOSED DIE PAI	D	Symbol D E A A 1 b e Lp X	Min 4.95 4.95 0.00 0.18 0.30 	Nom 5.00 5.00 0.25 0.50	Max 5.05 5.05 0.80
	EXPOSED DIE PAI	D	Symbol D E A A b E E L p X y Z _D	Min 4.95 4.95 0.00 0.18 0.30 	Nom 5.00 5.00 0.25 0.50 0.40 	Max 5.05 5.05 0.80
	EXPOSED DIE PAI	D	Symbol D E A A 1 b e Lp X y	Min 4.95 4.95 0.00 0.18 0.30 	Nom 5.00 5.00 0.25 0.50 0.40 0.75 0.75	Max 5.05 5.05 0.80 0.30 0.30 0.50 0.05 0.05
	EXPOSED DIE PAI	D	Symbol D E A b e Lp x y Z _D Z _E	Min 4.95 4.95 0.00 0.18 0.30 	Nom 5.00 5.00 0.25 0.50 0.40 0.75	

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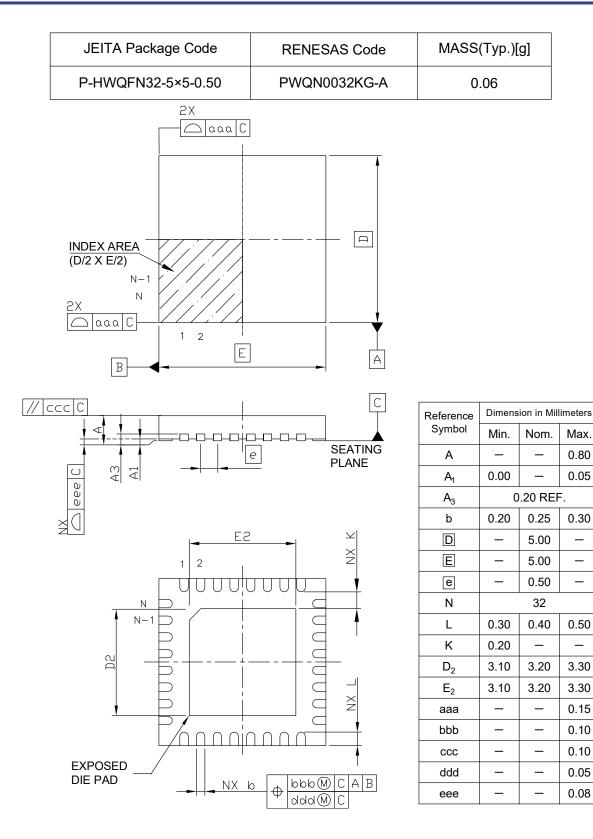
JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-HWQFN032-5x5-0.50	PWQN0032KE-A	0.06





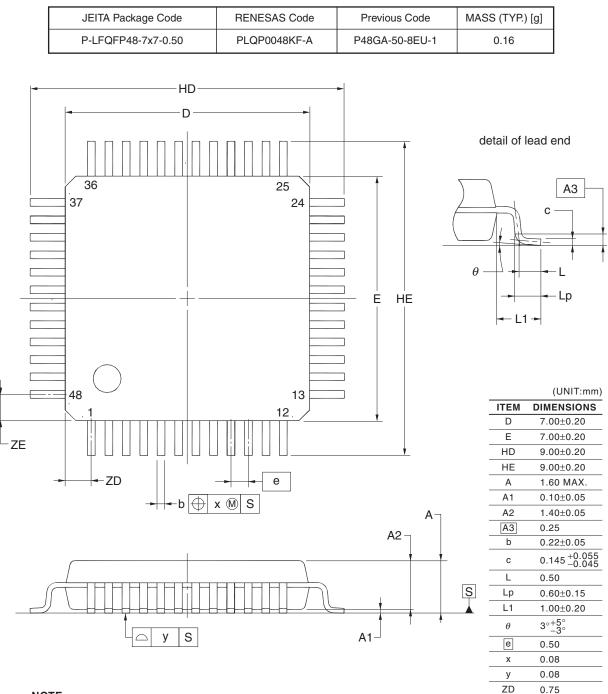
Dimension in Millimeters					
Min.	Nom.	Max.			
-	-	0.80			
0.00 0.02		0.05			
(0.203 REF.				
0.18	0.30				
5.00 BSC					
5.00 BSC					
0.50 BSC					
0.35 0.40 0.45					
0.20	-	-			
3.15	3.20	3.25			
3.15	3.20	3.25			
	0.15				
	0.10				
	0.10				
	0.05				
	0.08				
	0.10				
	Min. - 0.00 0.18 0.35 0.20 3.15	Min. Nom. - - 0.00 0.02 0.203 REF 0.203 REF 0.18 0.25 5.00 BSC 5.00 BSC 0.50 BSC 0.50 BSC 0.35 0.40 0.20 - 3.15 3.20 3.15 3.20 0.15 0.10 0.10 0.10 0.05 0.08			







4.3 48-pin products



NOTE

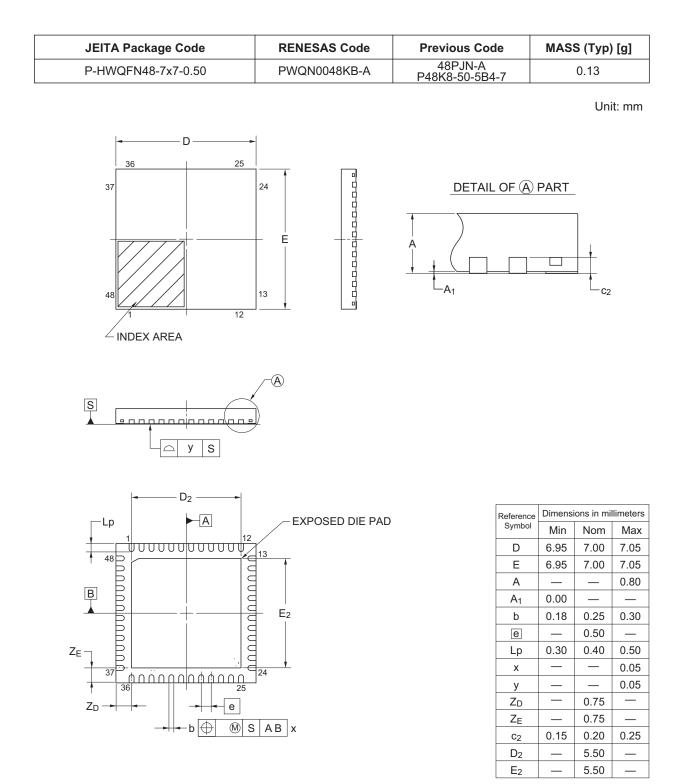
Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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ZE

0.75





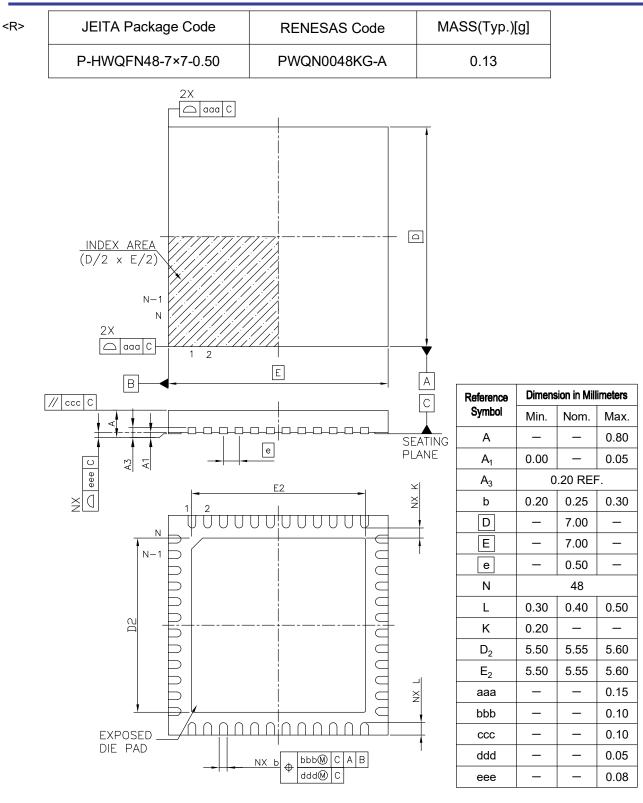
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	JEITA Pac	kage code	RENESAS	code	MASS(FYP.)[g]
	P-HWQFN04	48-7x7-0.50	PWQN0048	8KE-A	0.	13
	37	2X aaa C 36	25	24		
	INDEX AREA (D/2 X E/2) 2X 2X B 48 B		 			
/// c	A (A3) A1 48X C eee C	e	b(48X)			Referenc
		E	2		CAB	Symbol
	Г					A
⊕ fff(M C A B 48-				POSED E PAD	A1 A3
				q		A ₃ b
				J		D
				q		E
	D2			<u> </u>		е
				Б		L
				d		к
				Д		D ₂
	37			24		E2
			กกกกกฏ	Щ		aaa
		36	25	K(40)	N N	bbb
		L(48X)		K(48X	<u>)</u>	CCC
						ddd

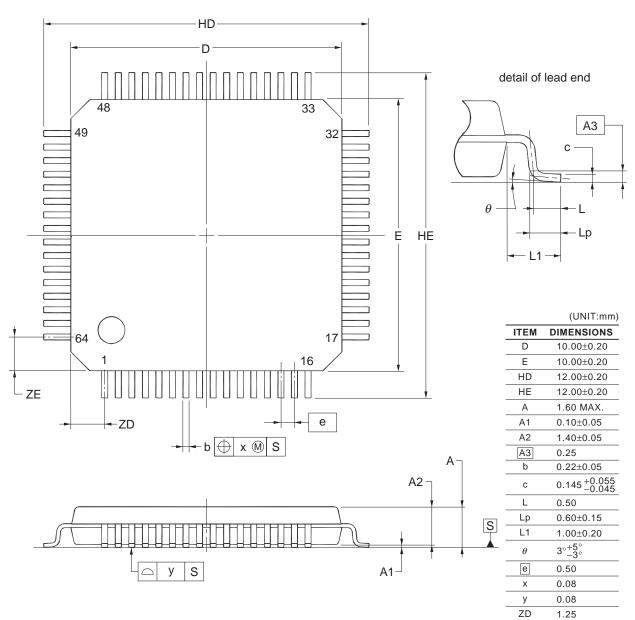
Reference	Dimension in Millimeters		
Symbol	Min.	Nom.	Max.
А	-	-	0.80
A ₁	0.00	0.02	0.05
A ₃	0.203 REF.		
b	0.20	0.25	0.30
D	7.00 BSC		
Е	7.00 BSC		
е	0.50 BSC		
L	0.30	0.40	0.50
К	0.20	-	-
D ₂	5.50	5.55	5.60
E2	5.50	5.55	5.60
aaa	0.15		
bbb	0.10		
CCC	0.10		
ddd	0.05		
eee	0.08		
fff	0.10		





4.4 64-pin products

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP64-10x10-0.50	PLQP0064KF-A	P64GB-50-UEU-2	0.35



NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

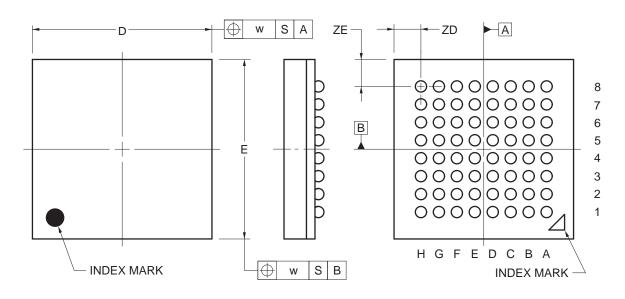
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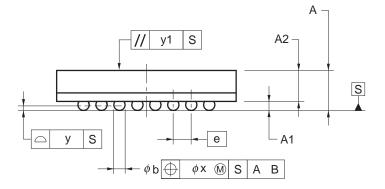
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1.25



JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-VFBGA64-4x4-0.40	PVBG0064LA-A	P64F1-40-AA2-2	0.03





	(UNIT:mm)
ITEM	DIMENSIONS
D	4.00±0.10
E	4.00±0.10
W	0.15
A	0.89±0.10
A1	0.20±0.05
A2	0.69
е	0.40
b	0.25 ± 0.05
х	0.05
У	0.08
y1	0.20
ZD	0.60
ZE	0.60

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Revision History

RL78/G1A Data Sheet

		Description	
Rev.	Date	Page	Summary
0.01	Dec 26, 2011	-	First Edition issued
1.00	Sep 25, 2013	p.1	Modification of 1.1 Features
		p.4	Modification of Table 1-1. List of Ordering Part Numbers
		p.6	Modification of Remark 3 to 1.3.2 32-pin products.
		p.13	Modification of 1.5.2 32-pin products.
		p.14	Modification of 1.5.3 48-pin products.
		p.16	Modification of 1.6 Outline of Functions
		p.21	Modification of 2.2.1 X1, XT1 oscillator characteristics
		p.31, 32	Modification of Note 1 in 2.3.2 Supply current characteristics
		p.34,35	Modification of Minimum Instruction Execution Time during Main System Clock Operation
		p.37	Modification of AC Timing Test Points in 2.5 Peripheral Functions Characteristics
		p.46 to p.58	Modification of Caution to 2.5.1 Serial array unit.
		p.63 to p.68	Modification of 2.6.1 A/D converter characteristics
		p.71	Modification of 2.7 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics
		p.71	Modification of 2.8 Flash Memory Programming Characteristics
		p.72	Modification of 2.10 Timing Specs for Switching Flash Memory Programming Modes
		p.73 to	Addition of 3 ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL
		p.117	APPLICATIONS TA = -40 to $+105^{\circ}$ C)
		p.118 to p.123	Modification of 4. PACKAGE DRAWINGS
2.10	Nov 30, 2016	p.4	Modification of Table 1-1. List of Ordering Part Numbers
		p.5 to 10	Modification of the position of the index mark in 1.3.1 25-pin products to 1.3.4 64-pin products
		p.6	Modification of Remark 3
		p.13	Modification of 1.5.2 32-pin products
		p.14	Modification of 1.5.3 48-pin products
		p.16	Modification of description in 1.6 Outline of Functions
		p.21	Modification of 2.2.1 X1, XT1 oscillator characteristics
		p.31, 32	Modification of Note 1 in 2.3.2 Supply current characteristics
		p.34, 35	Modification of Minimum Instruction Execution Time during Main System Clock Operation
		p.36	Modification of AC Timing Test Points and TI/TO Timing
		p.38	Modification of AC Timing Test Points in 2.5 Peripheral Functions Characteristics
		p.48, 50 to 52, 55, 59	Modification of Caution in 2.5.1 Serial array unit
		p.64 to 69	Modification of conditions of 2.6.1 A/D converter characteristics
		p.72	Renamed to 2.7 RAM Data Retention Characteristics, and modification of note and figure
		p.72	Modification of 2.8 Flash Memory Programming Characteristics

			Description
Rev.	Date	Page	Summary
2.10 Nov 30, 2016		p.73	Modification of 2.10 Timing Specs for Switching Flash Memory Programming Modes
		p.77	Modification of 3.2.1 X1, XT1 oscillator characteristics
		p.78, 79	Modification of 3.3.1 Pin characteristics
		p.88	Modification of 3.3.2 Supply current characteristics
		p.90	Modification of Minimum Instruction Execution Time during Main System Clock
		F	Operation
		p.91	Modification of AC Timing Test Points and TI/TO Timing
		p.93	Modification of AC Timing Test Points in 3.5 Peripheral Functions
			Characteristics
		p.95	Modification of 3.5.1 Serial array unit
		p.99,	Modification of Caution in 2.5.1 Serial array unit
		100,	
		102,	
		103,	
		105, 109	
		p.112 to 116	Modification of 3.6.1 (1) to (5)
		p.118	Renamed to 3.7 RAM Data Retention Characteristics, and modification of note and figure
		p.118	Addition of note 4 to 3.8 Flash Memory Programming Characteristics
		p.119	Modification of 3.10 Timing Specs for Switching Flash Memory Programming Modes
		p.120	Modification of 4.1 25-pin products
		р.123	Modification of 4.3 48-pin products
2.11	Dec 22, 2020	p.3	Modification of Figure 1-1 Part Number, Memory Size, and Package of RL78/G1A
		p.4	Addition of title and modification of description in Table 1-1 List of Ordering Part Numbers
		p.120 to 127	Addition and modification of all in CHAPTER 4 PACKAGE DRAWINGS
2.20	May 26, 2022	All	The medule name for CCL was abanged to Simplified CDL
2.20	May 26, 2023		The module name for CSI was changed to Simplified SPI
		All	"wait" for IIC was modified to "clock stretch"
		p.1	Addition of note in 1.1 Features
		p.4	Modification of Table 1-1 List of Ordering Part Numbers
		p.28	Modification of note1, note4 and note5 in 2.3.2 Supply current characteristics $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}) (1/3)$
		p.30	Modification of note1, note5 and note6 in 2.3.2 Supply current characteristics
			$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}) (2/3)$
		p.73	Modification of figure in 2.10 Timing Specs for Switching Flash Memory Programming Modes
		p.84	Modification of note1, note4 and note5 in 3.3.2 Supply current characteristics $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V}) (1/3)$
		p.86	Modification of note1, note5 and note6 in 3.3.2 Supply current characteristics $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = 0 \text{ V})$ (2/3)
		p.119	Modification of figure in 3.10 Timing Specs for Switching Flash Memory Programming Modes
		p.123	Addition of figure in 4.2 32-pin Products
2.30	Apr 26, 2024	p.120	Modification of Figure 1-1. Part Number, Memory Size, and Package of RL78/G1A
		- n 1	Modification of Table 1-1. List of Ordering Part Numbers
		p.4	

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General Precautions in the Handling of Microprocessing Unit and Microcontroller Unit Products

The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

1. Precaution against Electrostatic Discharge (ESD)

A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

2. Processing at power-on

The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power is supplied until the power is supplied until the power reaches the level at which resetting is specified.

3. Input of signal during power-off state

Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

4. Handling of unused pins

Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.

5. Clock signals

After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.

6. Voltage application waveform at input pin

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (Max.) and V_{IH} (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (Max.) and V_{IH} (Min.).

7. Prohibition of access to reserved addresses

Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.

8. Differences between products

Before changing from one product to another, for example to a product with a different part number, confirm that the change will not lead to problems. The characteristics of a microprocessing unit or microcontroller unit products in the same group but having a different part number might differ in terms of internal memory capacity, layout pattern, and other factors, which can affect the ranges of electrical characteristics, such as characteristic values, operating margins, immunity to noise, and amount of radiated noise. When changing to a product with a different part number, implement a systemevaluation test for the given product.

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